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# Multiport Vector Network Analyzers

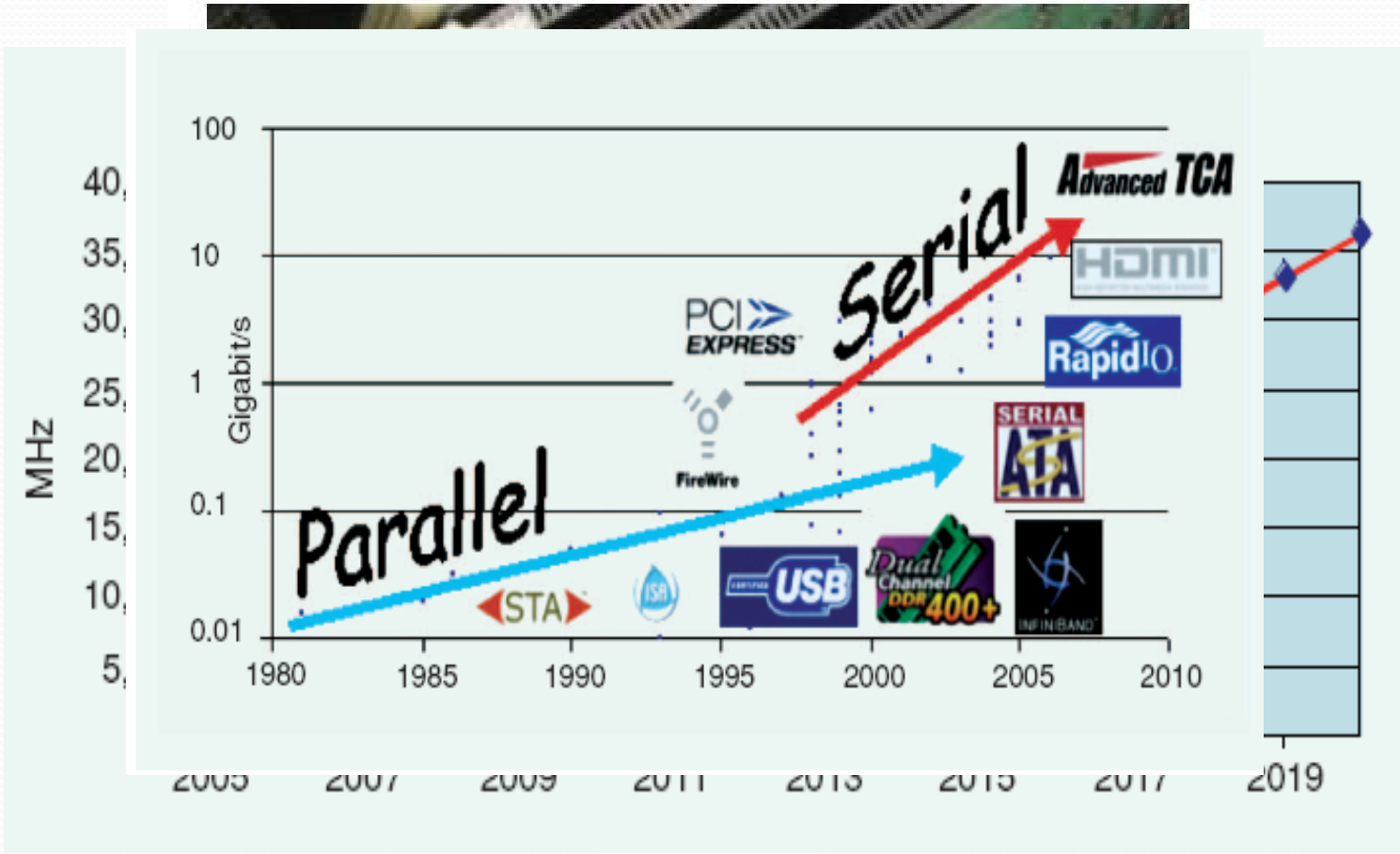
*From the beginning to modern signal integrity applications*  
*IEEE-MTT Distinguished Microwave Lectures*



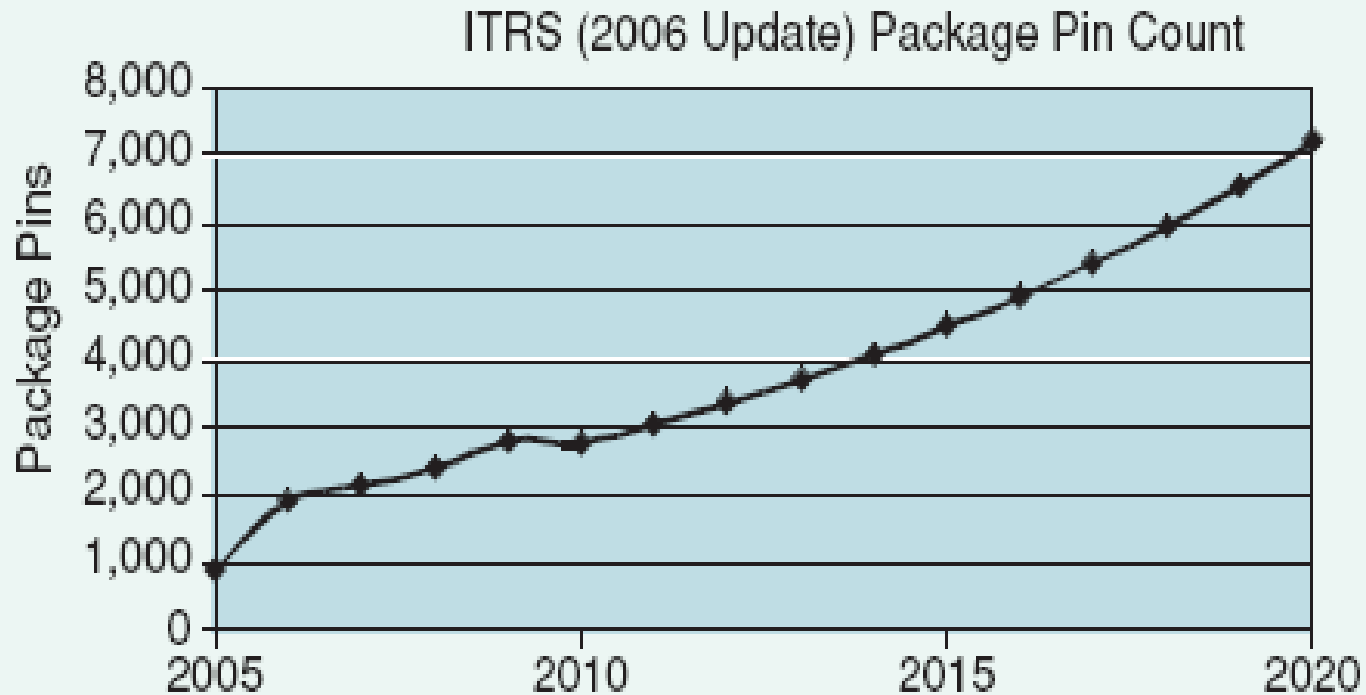
# Summary

- Signal Integrity and Microwave Measurement
- S parameters basics
- VNA Hardware Evolution
- Error Models and Calibration Techniques
- Interconnections for accurate Measurements
- A complete example
- Conclusions

# Signal Integrity and Microwave



# Do we need Multiport?



# The old questions Microwave Measurements

- How can I generate and sample microwave signals?
- Where's my reference plane ?
- What's my reference impedance?

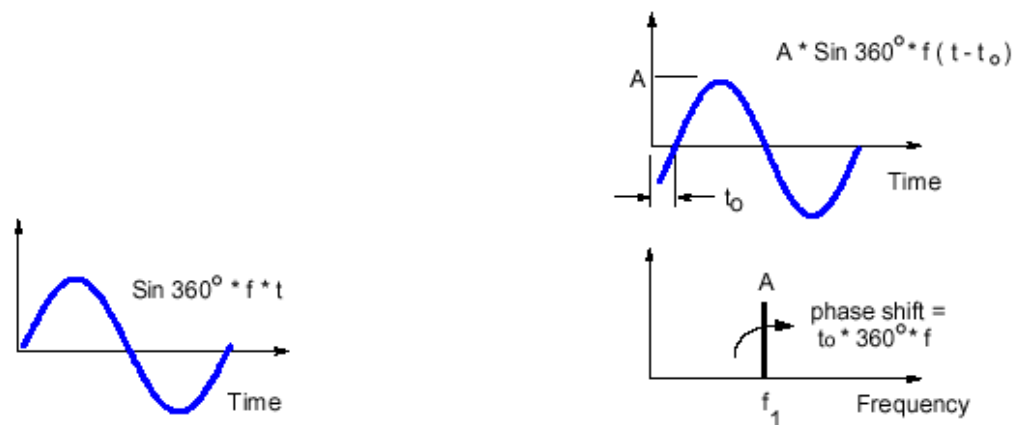
# Plus new problems...

- How do I keep reasonable microwave signals on non microwave substrate ?
- How can I make proper interconnections to measure these signals ?
- How much accuracy can I accept ?

# Let's start from scratch

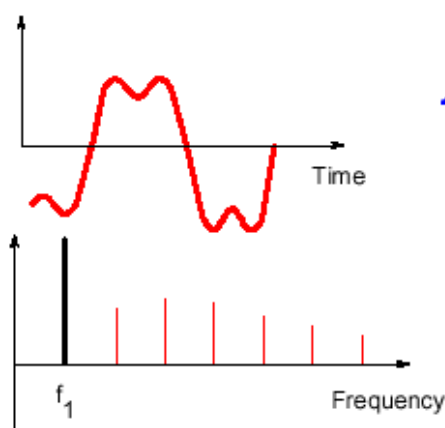
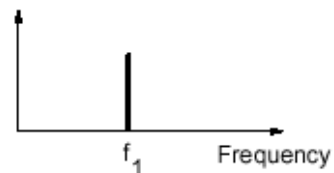
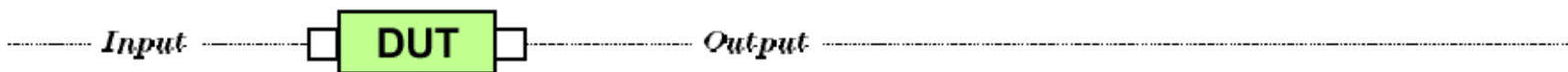
- S-parameter concept
- Mixed Mode S parameters
- S-parameter measurements

# Introduction



## *Linear behavior:*

- input and output frequencies are the same (no additional frequencies created)
- output frequency only undergoes magnitude and phase change



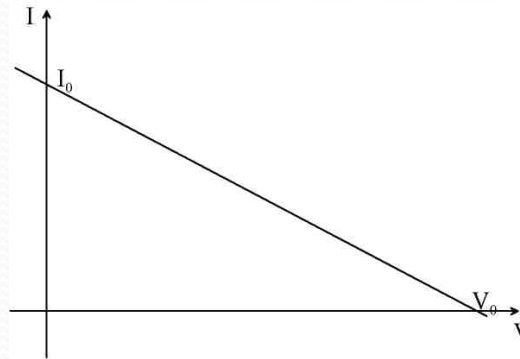
## *Nonlinear behavior:*

- output frequency may undergo frequency shift (e.g. with mixers)
- additional frequencies created (harmonics, intermodulation)



# Linear Circuit

- Every Linear circuit can be described in **frequency domain** with a set linear equations which define the interaction of the circuit with the external world
- Example: THE WELL KNOWN GENERATOR



eq. Thevenin Model  $V = -ZI + V_0$

eq. Norton Model  $I = -YV + I_0$



# N-port Linear Circuit

Variables are grouped in vectors and the relationship become matrix equations

- Example:  $\underline{V} = [Z] \underline{I} + \underline{V}_o$
- $\underline{I} = [Y] \underline{V} + \underline{I}_o$  where  $[Z]$ ,  $[Y]$  are the impedance/admittance matrices
- THERE ARE INFINITE POSSIBLE SET OF PARAMETERS THAT CAN BE USED TO SUCCESSFULLY DESCRIBE A LINEAR NETWORK
- Every parameter can be linked with any others by means of a **bi-linear matrix transform**.
- THE PARAMETER CHOICE DEPENDS ON THE USEFULNESS



# How do we measure them?

- If  $\underline{V}_o = \underline{I}_o = \underline{0}$
- Each parameter can be identify by the measurement:

$$Z_{ij} = \left. \frac{V_i}{I_j} \right|_{I_i=0}, \quad Y_{ij} = \left. \frac{I_i}{V_j} \right|_{V_i=0}$$

□ With specific load and source conditions, as example:

1. *Open Circuits (for Z par) Short Circuits (for Y par)*
2. Single tone sinusoidal source at one port
3. Measurement of V, I exactly at DUT ports
4. Change Frequency and repeat step 2-3

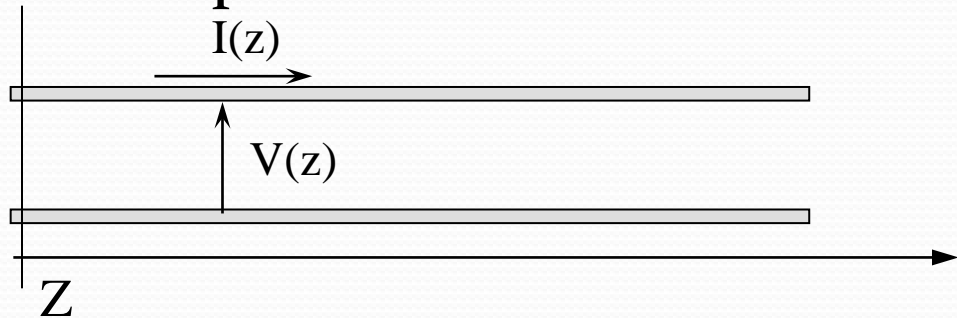
NB: VECTORIAL MEASUREMENT AT DIFFERENT FREQUENCY

DIFFERENT PARAMETERS MEAN DIFFERENT MEASUREMENT  
TECHNIQUES

# What's the best for the RF ?

- At RF frequencies everything become **POSITION**/FREQUENCY dependance

In general there are multiple modes and for every mode an equivalent transmission line can be used to describe the mode propagations



$$\begin{cases} V(z) = V^+(z) + V^-(z) \\ I(z) = I^+(z) + I^-(z) = \frac{V^+(z) - V^-(z)}{Z_\infty} \end{cases}$$

$$V^+(z) = V^+(0)e^{-jkz}$$

$$\begin{cases} V^+(z) = \frac{V(z) + Z_\infty I(z)}{2} \\ V^-(z) = \frac{V(z) - Z_\infty I(z)}{2} \end{cases}$$

# Scattering Parameter

Each forward and reflected voltages/currents on the line moves as:

$$V^+(z) = V^+(0)e^{-jkz}$$

$$V^-(z) = V^-(0)e^{+jkz}$$

Thus the natural choice when transmission lines are involved are some new parameters link to forward and backward voltages:

S-PARAMETERS

# Scattering Parameters

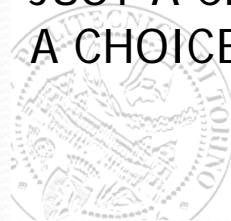
- $V(z)=0$  if at every section  $V/I$  is constant and  $=Z_\infty$
- At each port we define an **arbitrary** reference impedance and define new parameters such that:

$$a_i \equiv \frac{V_i + I_i Z_i}{2\sqrt{R_i}} \quad b_i \equiv \frac{V_i - I_i Z_i}{2\sqrt{R_i}} \quad a_i = \frac{V_i^+}{\sqrt{R_i^{ref}}}, \quad b_i = \frac{V_i^-}{\sqrt{R_i^{ref}}} \quad \longrightarrow \quad \begin{bmatrix} b_1 \\ b_2 \end{bmatrix} = \begin{bmatrix} S_{11} & S_{12} \\ S_{21} & S_{22} \end{bmatrix} \begin{bmatrix} a_1 \\ a_2 \end{bmatrix}$$

- If  $R=Z_\infty$  many interesting properties occurs for the S parameters of a line I.e.:

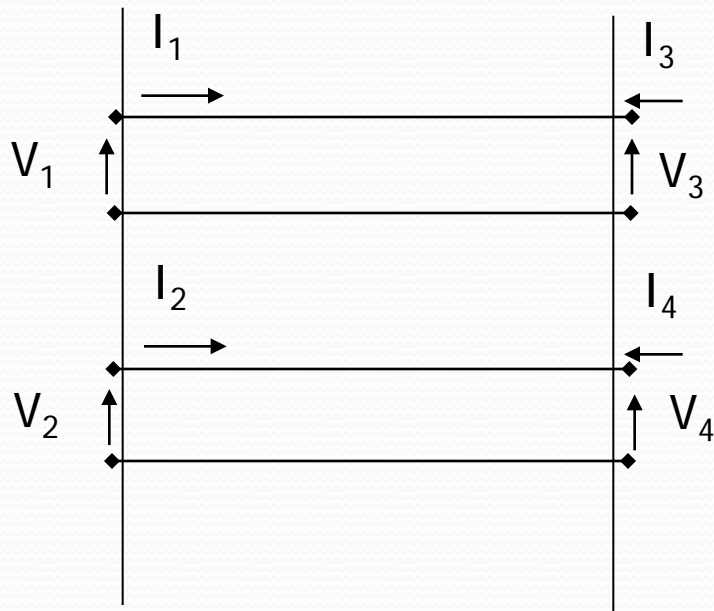
$$S(z) = \begin{bmatrix} 0 & e^{-jkz} \\ e^{-jkz} & 0 \end{bmatrix}$$

BUT REMEMBER THAT IT'S  
JUST A CHOICE, A GOOD CHOICE BUT  
A CHOICE!



# Differential S-parameters

- What if instead of single ended voltages and currents we wish to use differential ones ?



For Each Couple

$$V_{djk} \equiv V_j - V_k$$

$$V_{cjk} \equiv (V_j + V_k)/2$$

$$I_{djk} \equiv (I_j - I_k)/2$$

$$I_{cjk} \equiv (I_j + I_k)$$



# Differential S-parameters

- What are the propagation properties and is it useful to have an “S-parameter equivalent”?
- Use a linear combination of  $V$  and  $I$  it’s just another convention but to link it to propagation became more tricky:
  - Which Reference impedance we need to take?
  - What if we wish to have some port left single ended, i.e. an Operational Amplifier?
  - Which are the properties of the new parameters?



# Mixed Mode S-parameter

- Traditional definitions are:

$$a_{dj k} = \frac{1}{\sqrt{2}} (a_j - a_k)$$

$$b_{dj k} = \frac{1}{\sqrt{2}} (b_j - b_k)$$

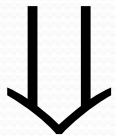
$$a_{cjk} = \frac{1}{\sqrt{2}} (a_j + a_k)$$

$$b_{cjk} = \frac{1}{\sqrt{2}} (b_j + b_k)$$

BUT THESE ARE VALID  
ONLY IF

$$Z_{cjk} = \frac{R}{2} \text{ Real Only}$$

$$Z_{dj k} = 2R \text{ Real Only}$$



$$\bullet \mathbf{\dot{S}} = \mathbf{MSM}^{-1} \mathbf{1}$$



# Generalized Mixed Mode

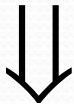
- In general we may have

$$a_{djk} \equiv \sqrt{R_{djk}} \frac{V_{djk} + I_{djk} Z_{djk}}{2|Z_{djk}|}$$

$$b_{djk} \equiv \sqrt{R_{djk}} \frac{V_{djk} - I_{djk} Z_{djk}}{2|Z_{djk}|}$$

$$a_{cjk} \equiv \sqrt{R_{cjk}} \frac{V_{cjk} + I_{cjk} Z_{cjk}}{2|Z_{cjk}|}$$

$$b_{cjk} \equiv \sqrt{R_{cjk}} \frac{V_{cjk} - I_{cjk} Z_{cjk}}{2|Z_{cjk}|}$$



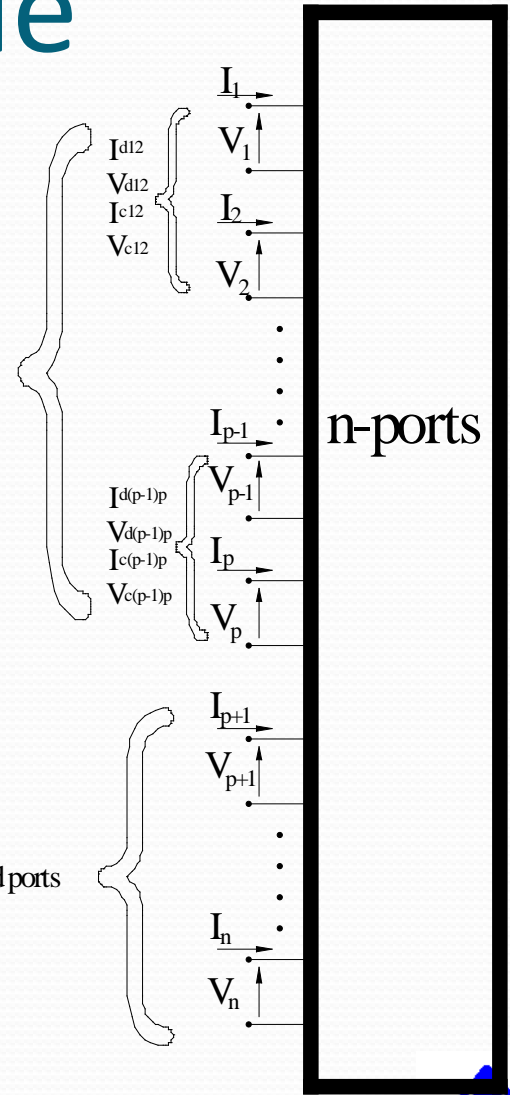
$$\dot{\mathbf{S}} = (\mathbf{\Xi}_{21} + \mathbf{\Xi}_{22}\mathbf{S})(\mathbf{\Xi}_{11} + \mathbf{\Xi}_{12}\mathbf{S})^{-1}$$

BILINEAR MATRIX TRANSFORM

$$\mathbf{a} \equiv \begin{pmatrix} a_{d12} \\ a_{d34} \\ \vdots \\ a_{d(p-1)p} \\ a_{c12} \\ a_{c34} \\ \vdots \\ a_{c(p-1)p} \\ a_{p+1} \\ \vdots \\ a_{n-1} \\ a_n \end{pmatrix} \quad \mathbf{b} \equiv \begin{pmatrix} b_{d12} \\ b_{d34} \\ \vdots \\ b_{d(p-1)p} \\ b_{c12} \\ b_{c34} \\ \vdots \\ b_{c(p-1)p} \\ b_{p+1} \\ \vdots \\ b_{n-1} \\ b_n \end{pmatrix}$$

p differential ports

n-p single ended ports



# S-parameter Measurement

- From the definition in a 2 port case:

$$\begin{bmatrix} b_1 \\ b_2 \end{bmatrix} = \begin{bmatrix} S_{11} & S_{12} \\ S_{21} & S_{22} \end{bmatrix} \begin{bmatrix} a_1 \\ a_2 \end{bmatrix}$$

$$b_1 = S_{11}a_1 + S_{12}a_2$$

$$b_2 = S_{21}a_1 + S_{22}a_2$$

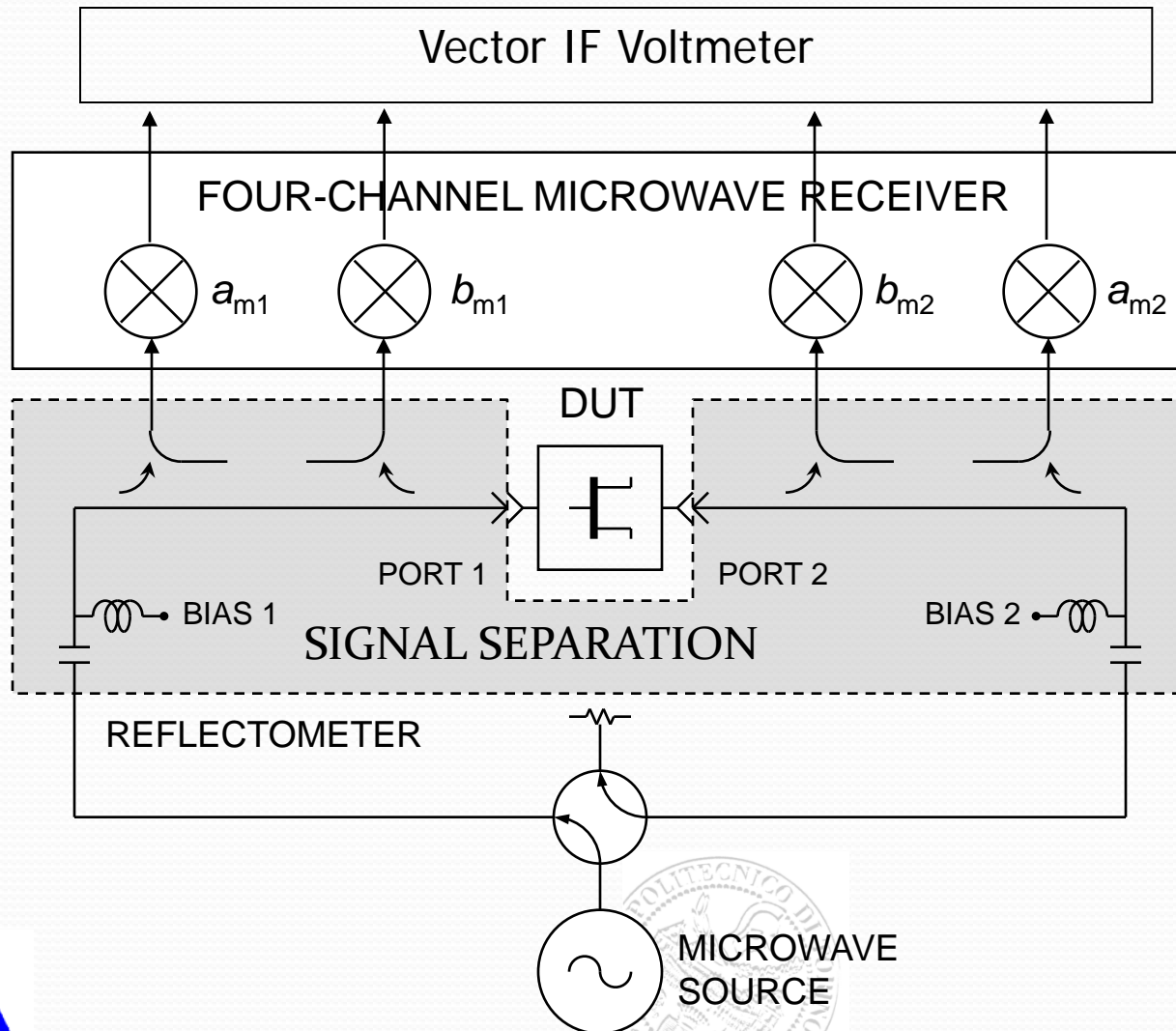
$$S_{ij} = \frac{b_i}{a_j} \Big|_{a_{i \neq j} = 0}$$

Which  
Means

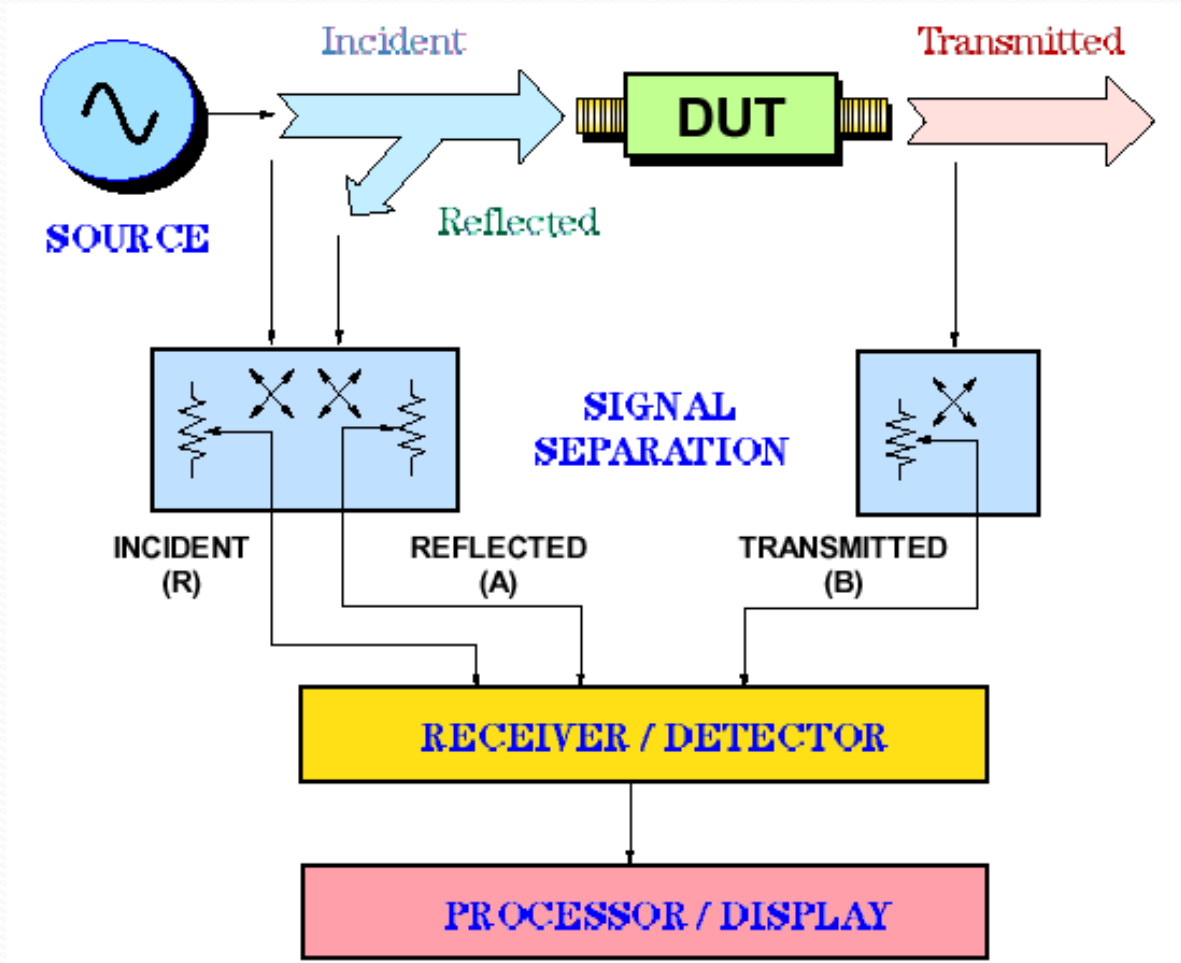
Measurements of incident and reflected signal while terminating the other port on their reference impedance



# VNA BASIC SCHEME

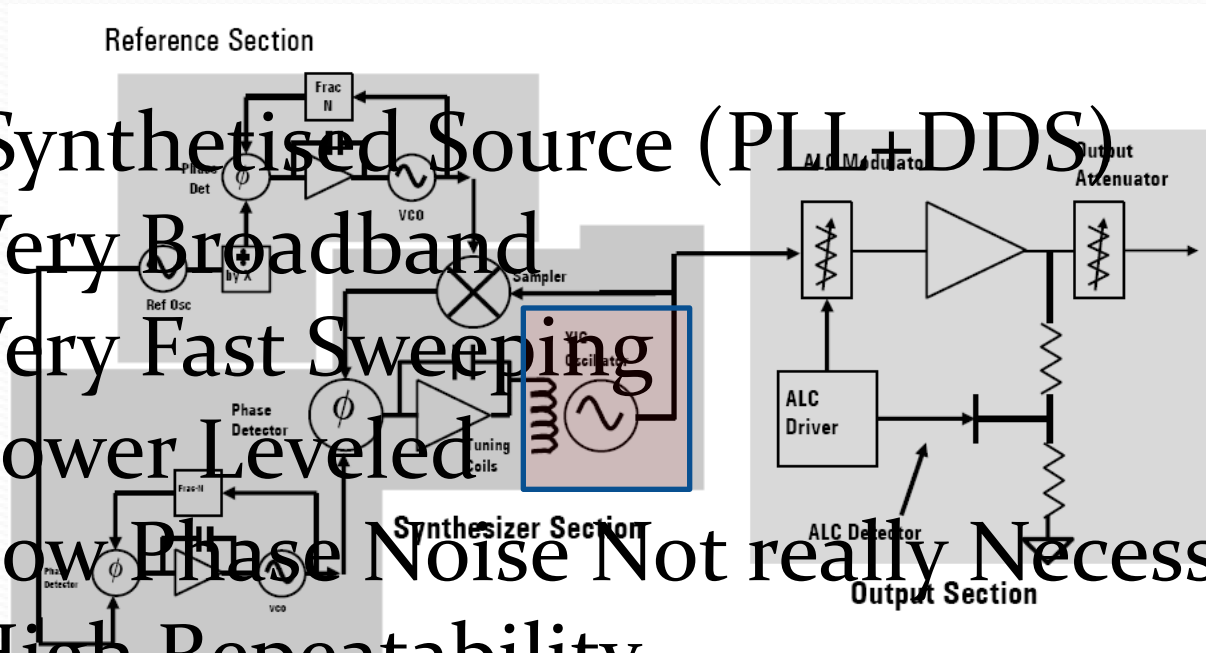


# 3-Sampler VNA



# VNA Source

- Synthesised Source (PLL+DDS)
- Very Broadband
- Very Fast Sweeping
- Power Levelled
- Low Phase Noise Not really Necessary
- High Repeatability



Agilent PNA Source block

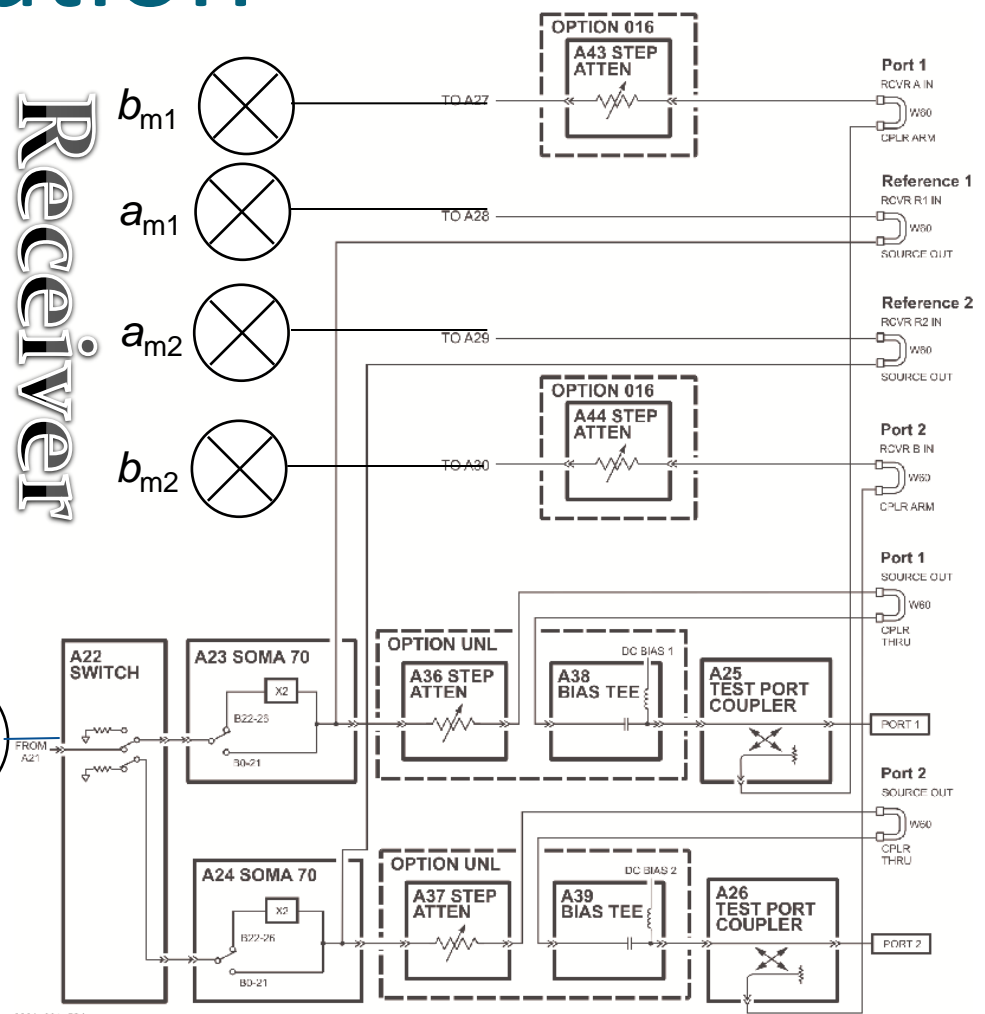
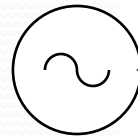


# Signal Separation

- Provides a and b waves separation
- Provides signal excitation at DUT ports
- It may have also bias tee and attenuators

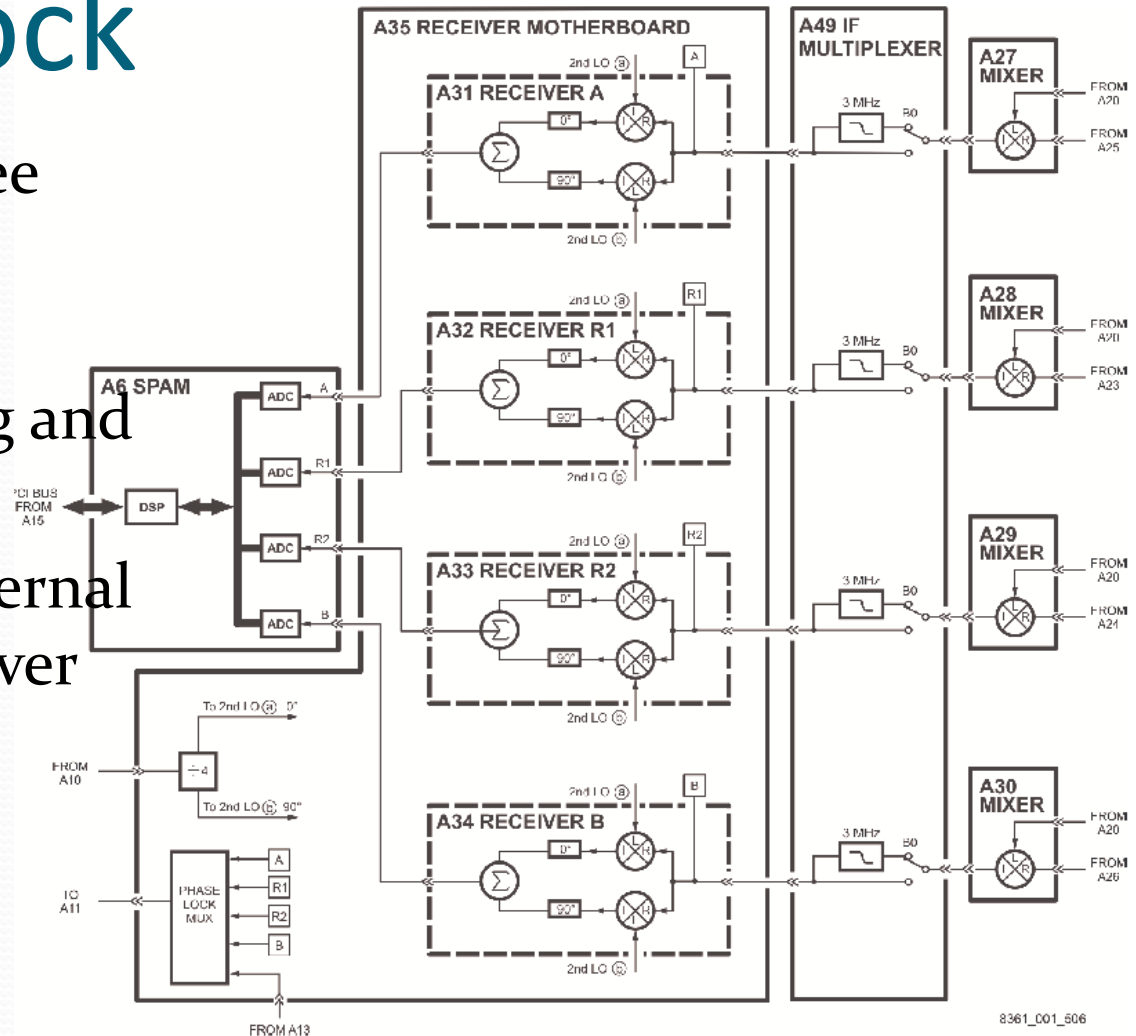
Receiver Block

MICROWAVE SOURCE



# Receiver Block

- Typically two or three downconversion
- Digital vectorial measurement of mag and phase
- Phase lock of the internal source through receiver signals



8361\_001\_506

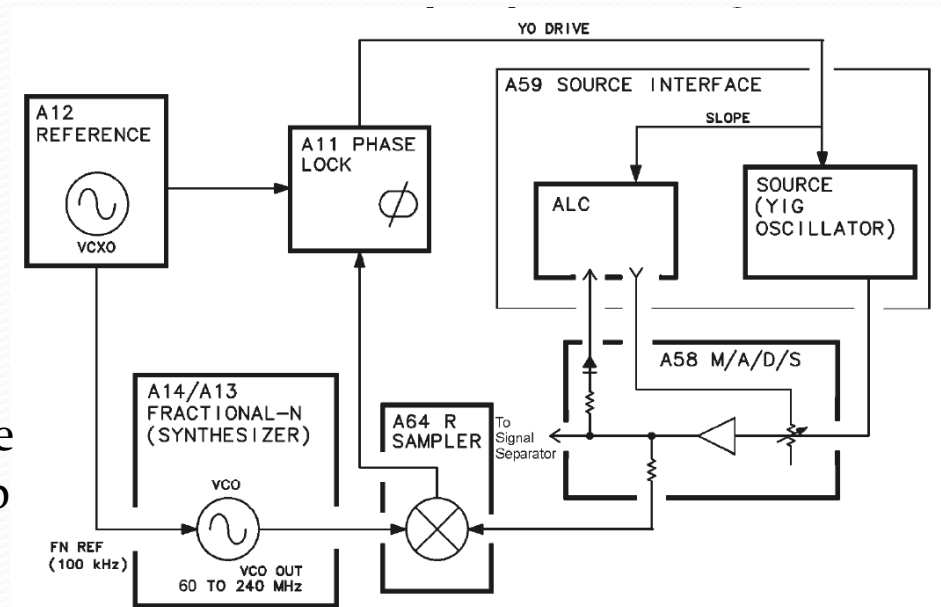


# Phase Lock through its receiver

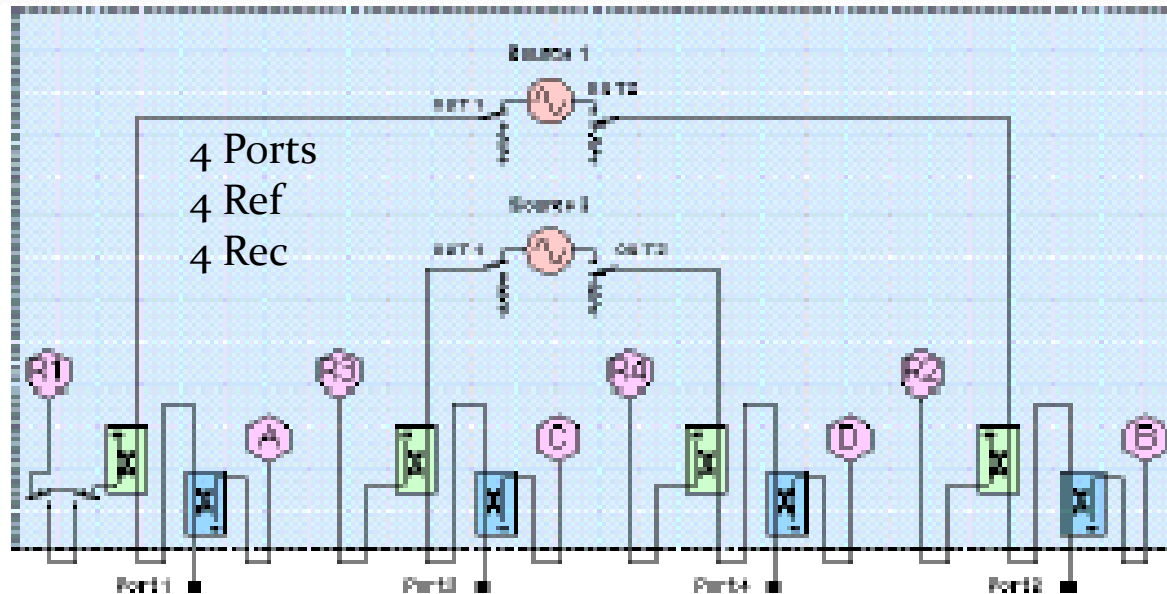
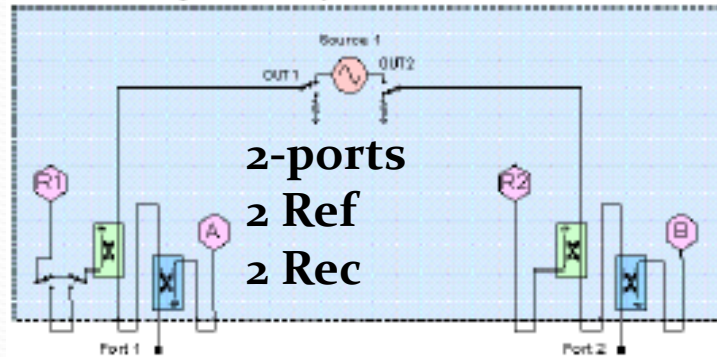
Unlike the old VNA where the source was autonomously locked and the receiver could lock to any microwave signal, modern VNAs cannot work unless their internal source is used.

As example:

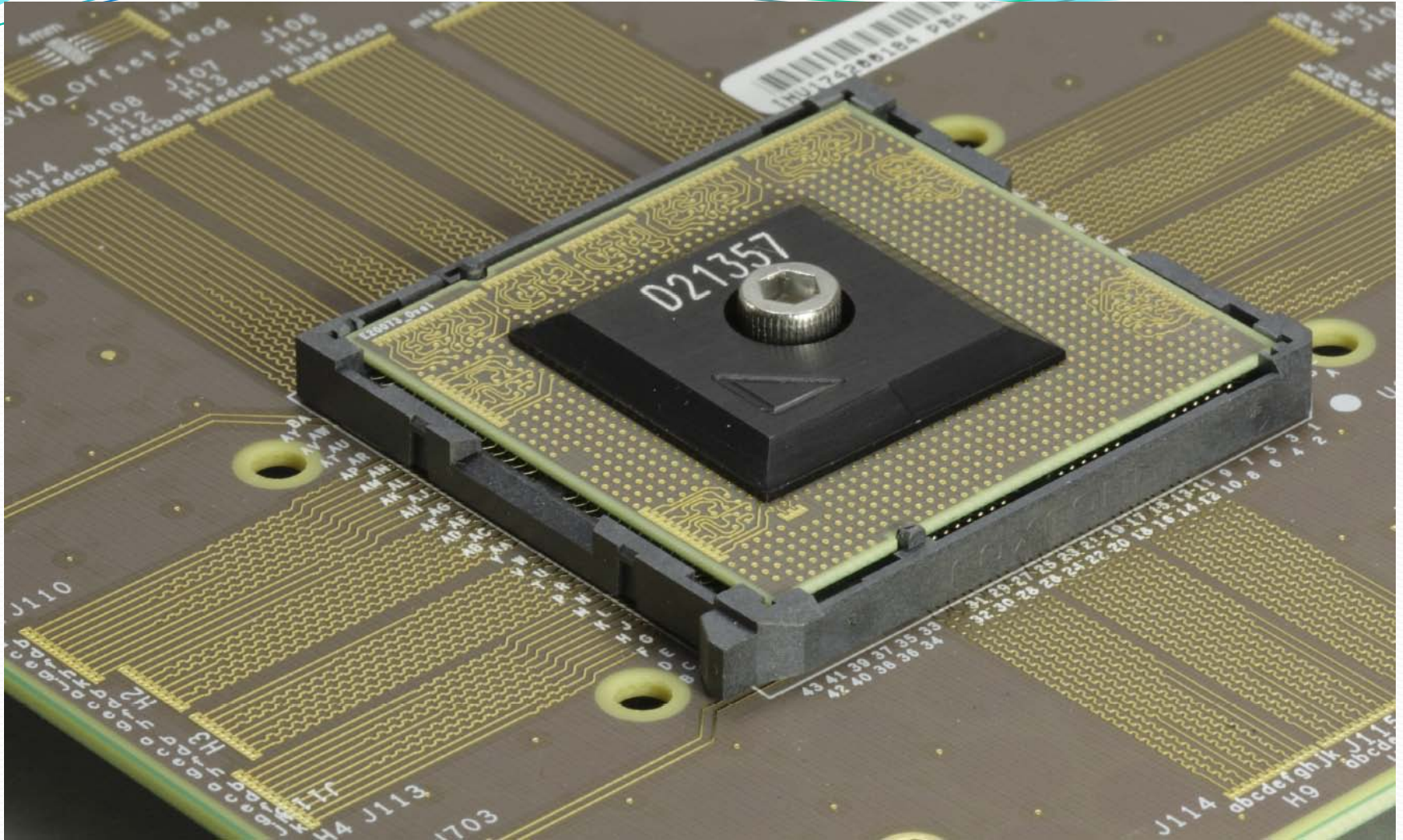
You cannot use a VNA to measure the signal coming out from a chip where its clock cannot be locked to an external reference



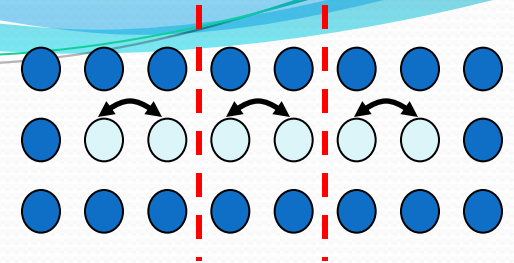
# Going More than 2ports



# Are 4 ports VNA enough?



# 4-port Measurements w/symmetry

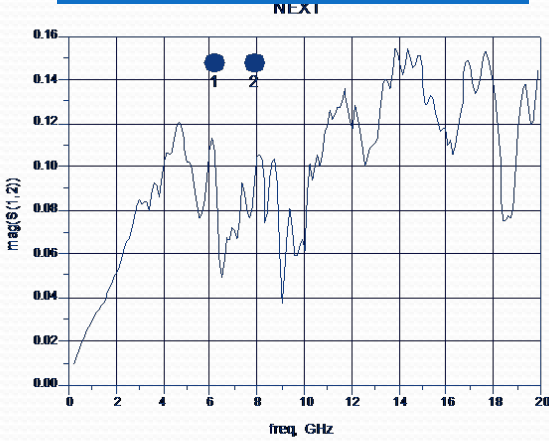


**Coupling within pairs:**  
Measured, as long as symmetry is assumed

**Coupling between pairs:**  
Unknown

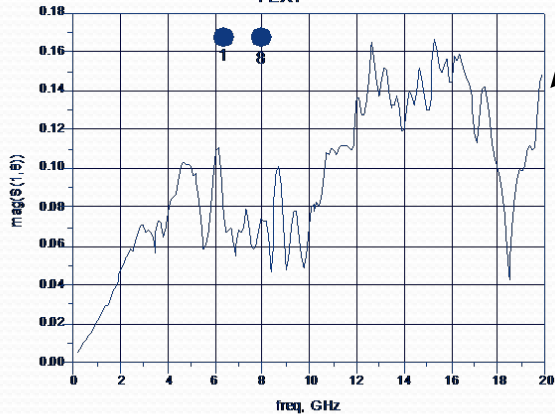
**Coupling within pairs**

## Crosstalk Measurements




## 4-port

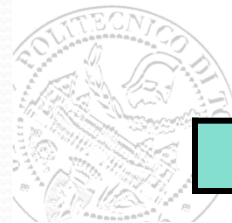
FEXT



## Measurement Matrix

|    | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 |
|----|---|---|---|---|---|---|---|---|---|----|----|----|
| 1  |   |   |   |   | 0 | 0 | 0 | 0 | 0 | 0  | 0  | 0  |
| 2  |   |   |   |   | 0 | 0 | 0 | 0 | 0 | 0  | 0  | 0  |
| 3  |   |   |   |   | 0 | 0 | 0 | 0 | 0 | 0  | 0  | 0  |
| 4  |   |   |   |   | 0 | 0 | 0 | 0 | 0 | 0  | 0  | 0  |
| 5  | 0 | 0 | 0 | 0 |   |   |   |   | 0 | 0  | 0  | 0  |
| 6  | 0 | 0 | 0 | 0 |   |   |   |   | 0 | 0  | 0  | 0  |
| 7  | 0 | 0 | 0 | 0 |   |   |   |   | 0 | 0  | 0  | 0  |
| 8  | 0 | 0 | 0 | 0 |   |   |   |   | 0 | 0  | 0  | 0  |
| 9  | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 |   |    |    |    |
| 10 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 |   |    |    |    |
| 11 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 |   |    |    |    |
| 12 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 |   |    |    |    |

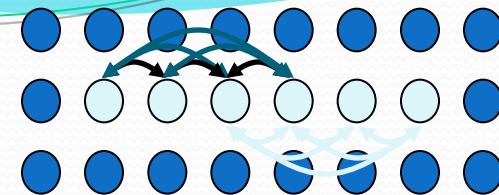
 = data collected via measurement





# 8-port Measurements w/symmetry

Package/Socket footprint



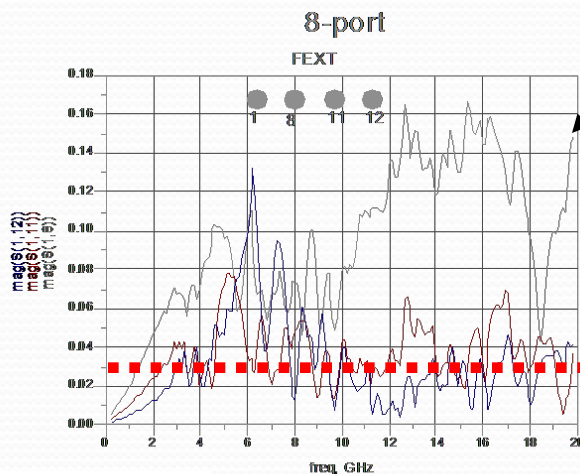
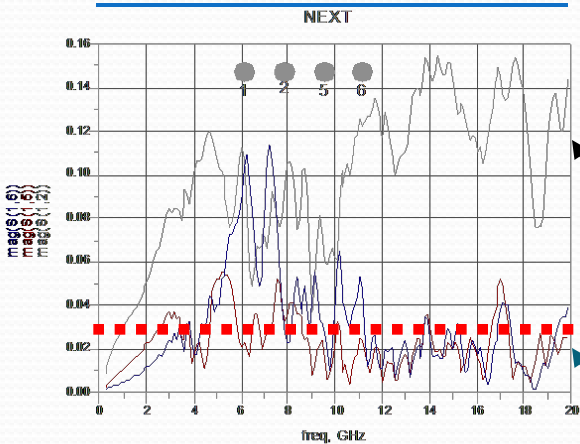
## Crosstalk Measurements

**Coupling within pairs:**  
Measured, as long as symmetry is assumed

**Coupling between pairs:**  
Nearest neighbor measured, as long as symmetry is assumed

Coupling within pairs

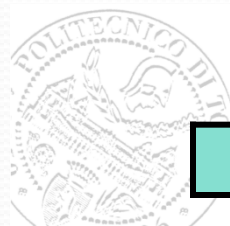
Coupling between pairs



## Measurement Matrix

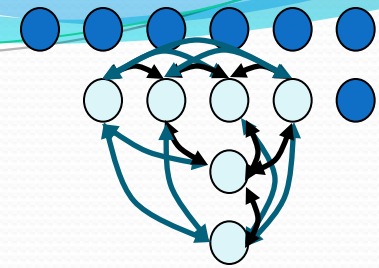
|    | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 |
|----|---|---|---|---|---|---|---|---|---|----|----|----|
| 1  |   |   |   |   |   |   |   |   | 0 | 0  | 0  | 0  |
| 2  |   |   |   |   |   |   |   |   | 0 | 0  | 0  | 0  |
| 3  |   |   |   |   |   |   |   |   | 0 | 0  | 0  | 0  |
| 4  |   |   |   |   |   |   |   |   | 0 | 0  | 0  | 0  |
| 5  |   |   |   |   |   |   |   |   |   |    |    |    |
| 6  |   |   |   |   |   |   |   |   |   |    |    |    |
| 7  |   |   |   |   |   |   |   |   |   |    |    |    |
| 8  |   |   |   |   |   |   |   |   |   |    |    |    |
| 9  | 0 | 0 | 0 | 0 |   |   |   |   |   |    |    |    |
| 10 | 0 | 0 | 0 | 0 |   |   |   |   |   |    |    |    |
| 11 | 0 | 0 | 0 | 0 |   |   |   |   |   |    |    |    |
| 12 | 0 | 0 | 0 | 0 |   |   |   |   |   |    |    |    |

 = data collected via measurement



# 12-port Measurements

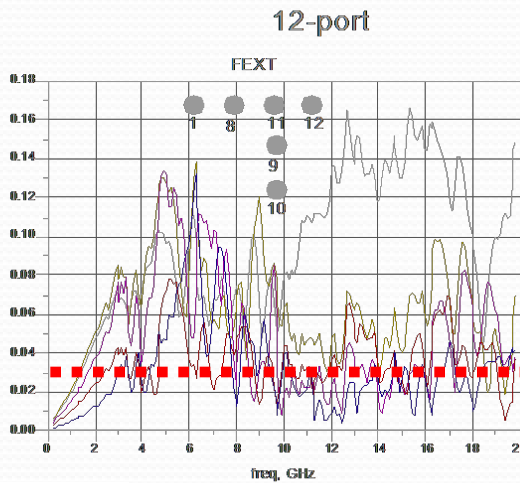
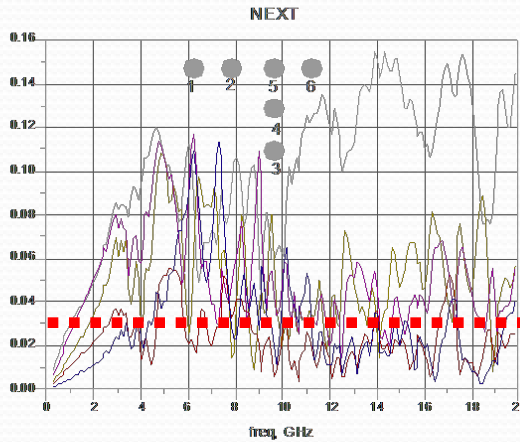
Package/Socket footprint



## Crosstalk Measurements

**Coupling within pairs:**  
Measured

**Coupling between pairs:**  
Measured



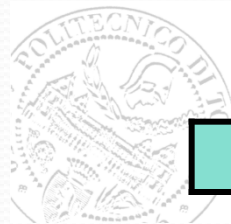
Coupling within pairs

Coupling between pairs

## Measurement Matrix

|    | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 |
|----|---|---|---|---|---|---|---|---|---|----|----|----|
| 1  |   |   |   |   |   |   |   |   |   |    |    |    |
| 2  |   |   |   |   |   |   |   |   |   |    |    |    |
| 3  |   |   |   |   |   |   |   |   |   |    |    |    |
| 4  |   |   |   |   |   |   |   |   |   |    |    |    |
| 5  |   |   |   |   |   |   |   |   |   |    |    |    |
| 6  |   |   |   |   |   |   |   |   |   |    |    |    |
| 7  |   |   |   |   |   |   |   |   |   |    |    |    |
| 8  |   |   |   |   |   |   |   |   |   |    |    |    |
| 9  |   |   |   |   |   |   |   |   |   |    |    |    |
| 10 |   |   |   |   |   |   |   |   |   |    |    |    |
| 11 |   |   |   |   |   |   |   |   |   |    |    |    |
| 12 |   |   |   |   |   |   |   |   |   |    |    |    |

= data collected via measurement



# 12 ports

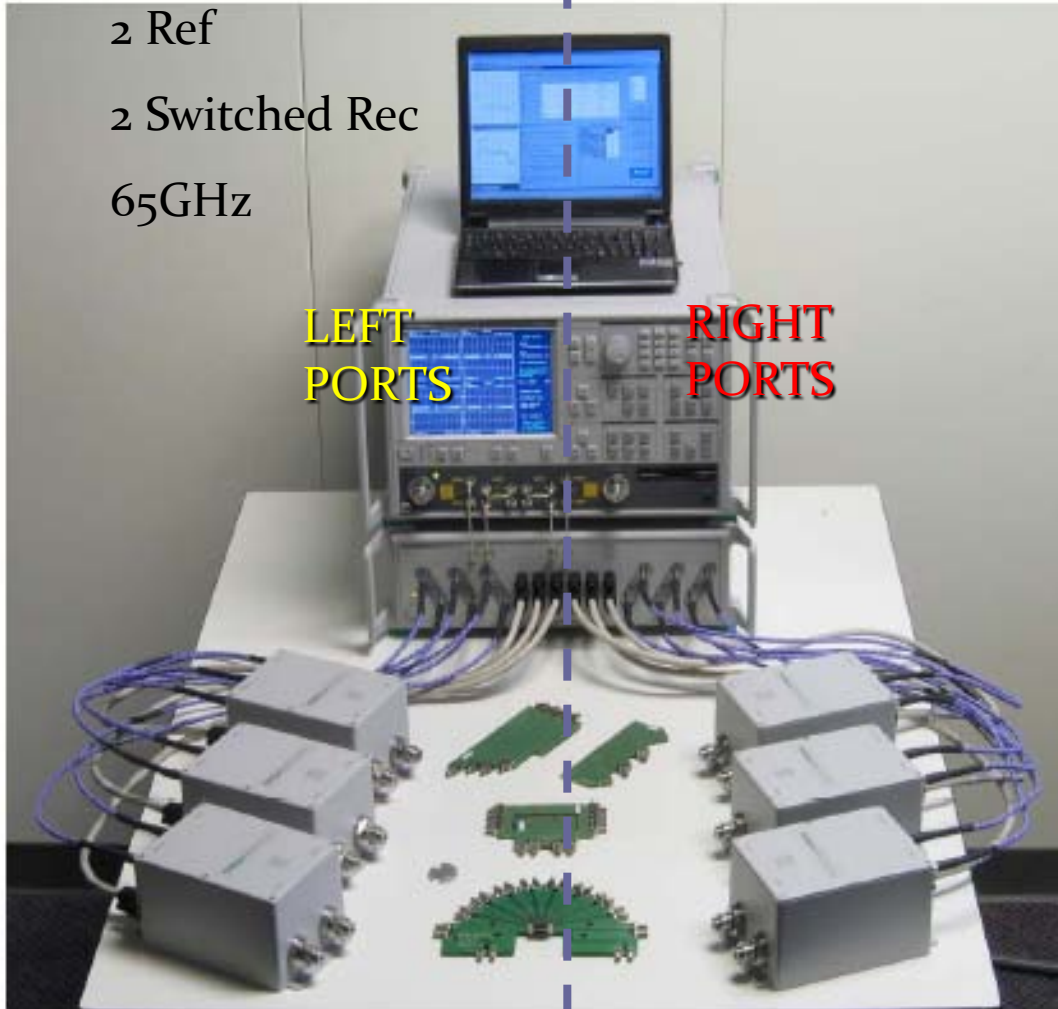
2 Ref

2 Switched Rec

65GHz

LEFT  
PORTS

RIGHT  
PORTS



# 12 ports

2 Ref  
2 Switched Rec  
50GHz

LEFT PORTS

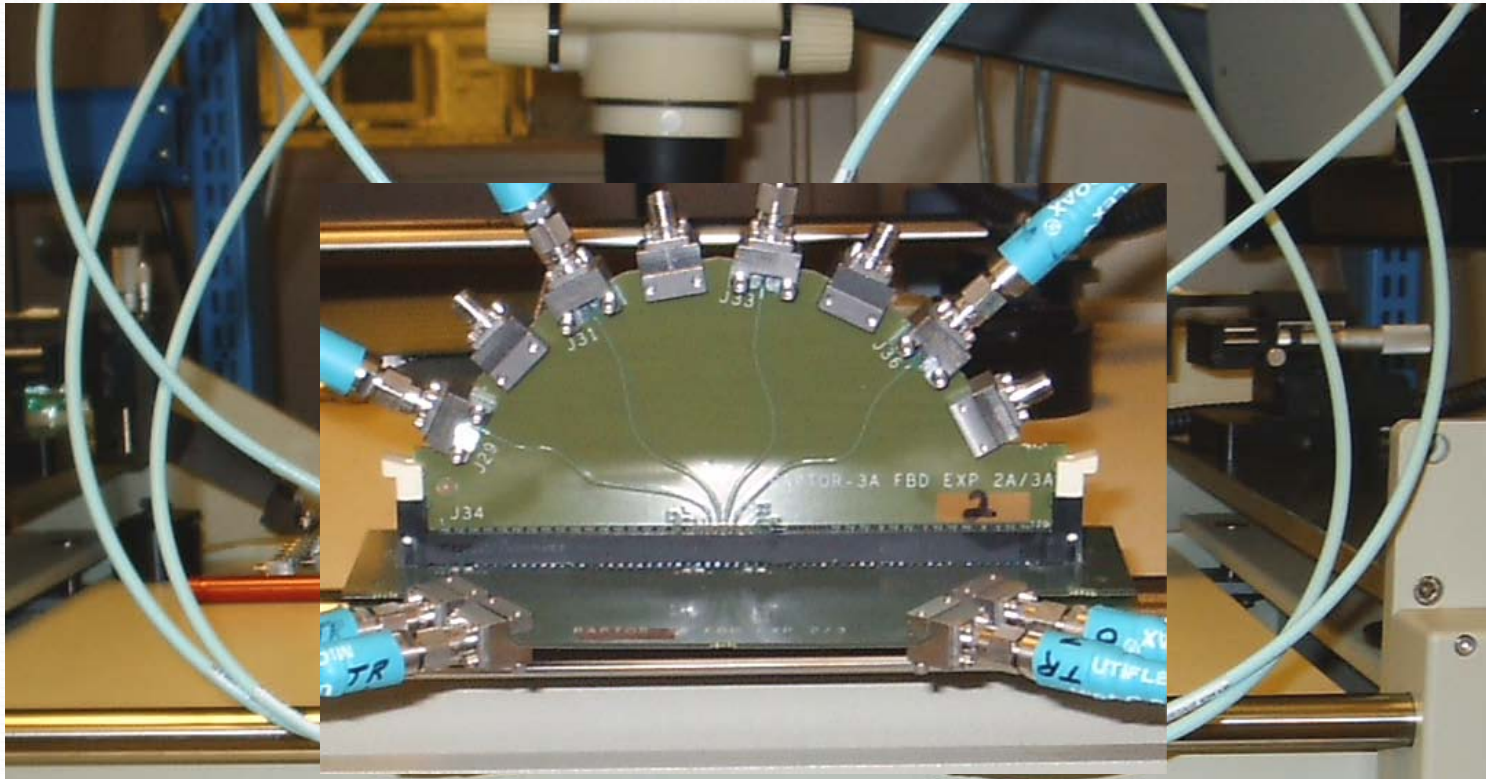
RIGHT PORTS

The image shows a laboratory setup for a 12-port system. A laptop on the left is connected to a central green PCB with 12 ports. This PCB is connected via purple cables to a stack of three white instruments on the right, which are also connected to a 12-port switch (SW4). A dashed blue vertical line separates the 'LEFT PORTS' from the 'RIGHT PORTS'. The instruments include a spectrum analyzer on top and two other units below. A mouse is visible on the desk.

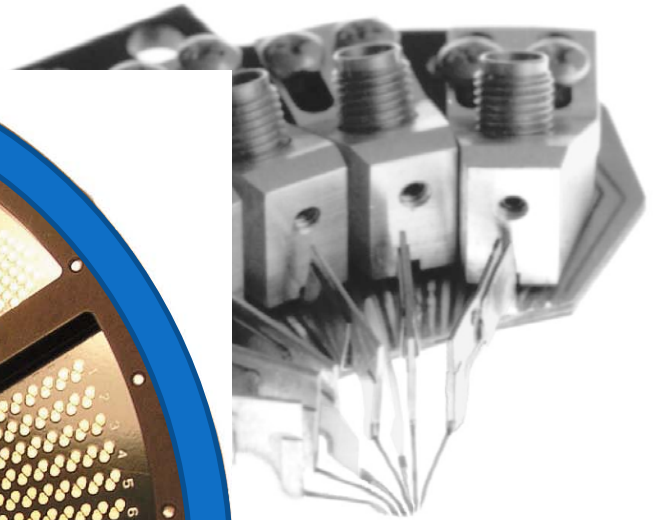
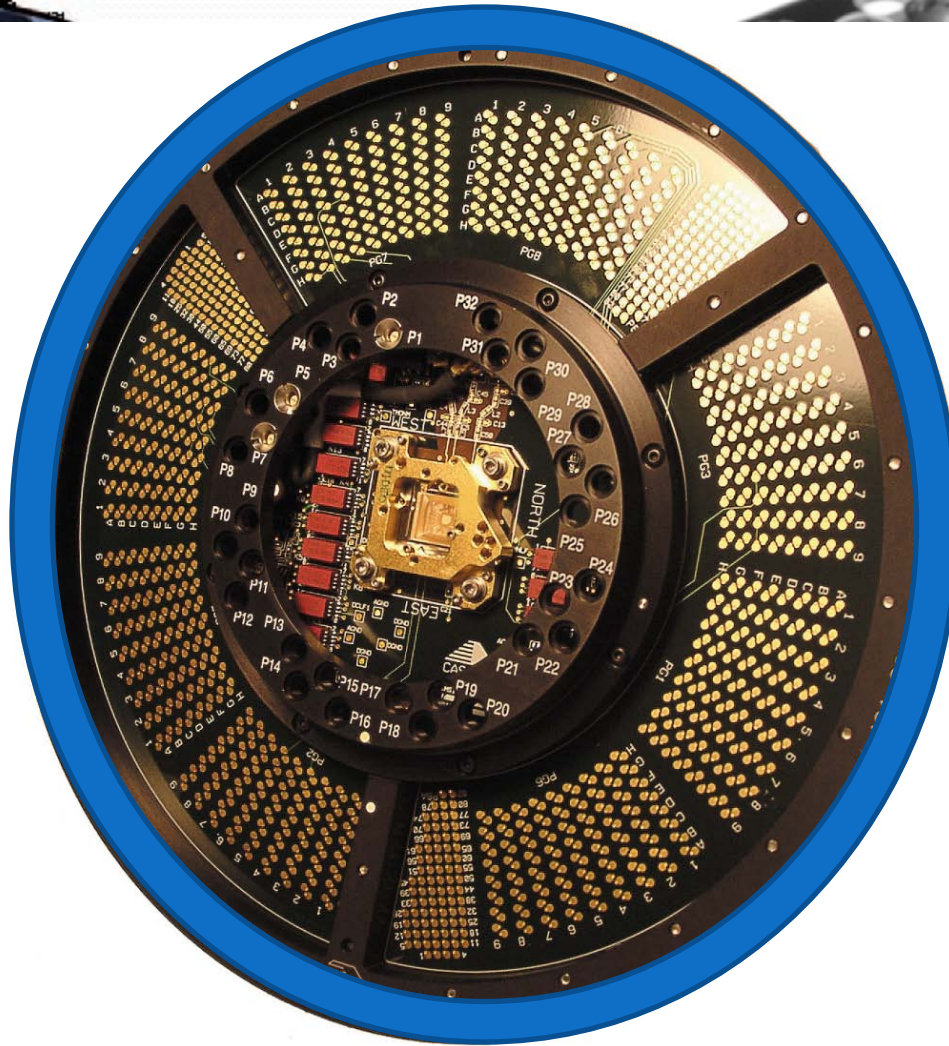


# Interfacing

- Custom Fixtures



# On Wafer



# Let's summarize up to now

1. Directional Couplers have finite directivity and frequency depend behaviour
2. Switches are not ideal and frequency dependent
3. Reference Plane position depends on cable, adapter interconnections and so on
4. DownConversion and Digitizing problems like:
  1. Source Phase Noise
  2. Frequency accuracy and repeatability
  3. Non linearity of mixer/sampler
  4. ADC Dynamic Range & Speed
5. Interfacing effect

ACCURACY???



# QUESTIONS UP TO NOW





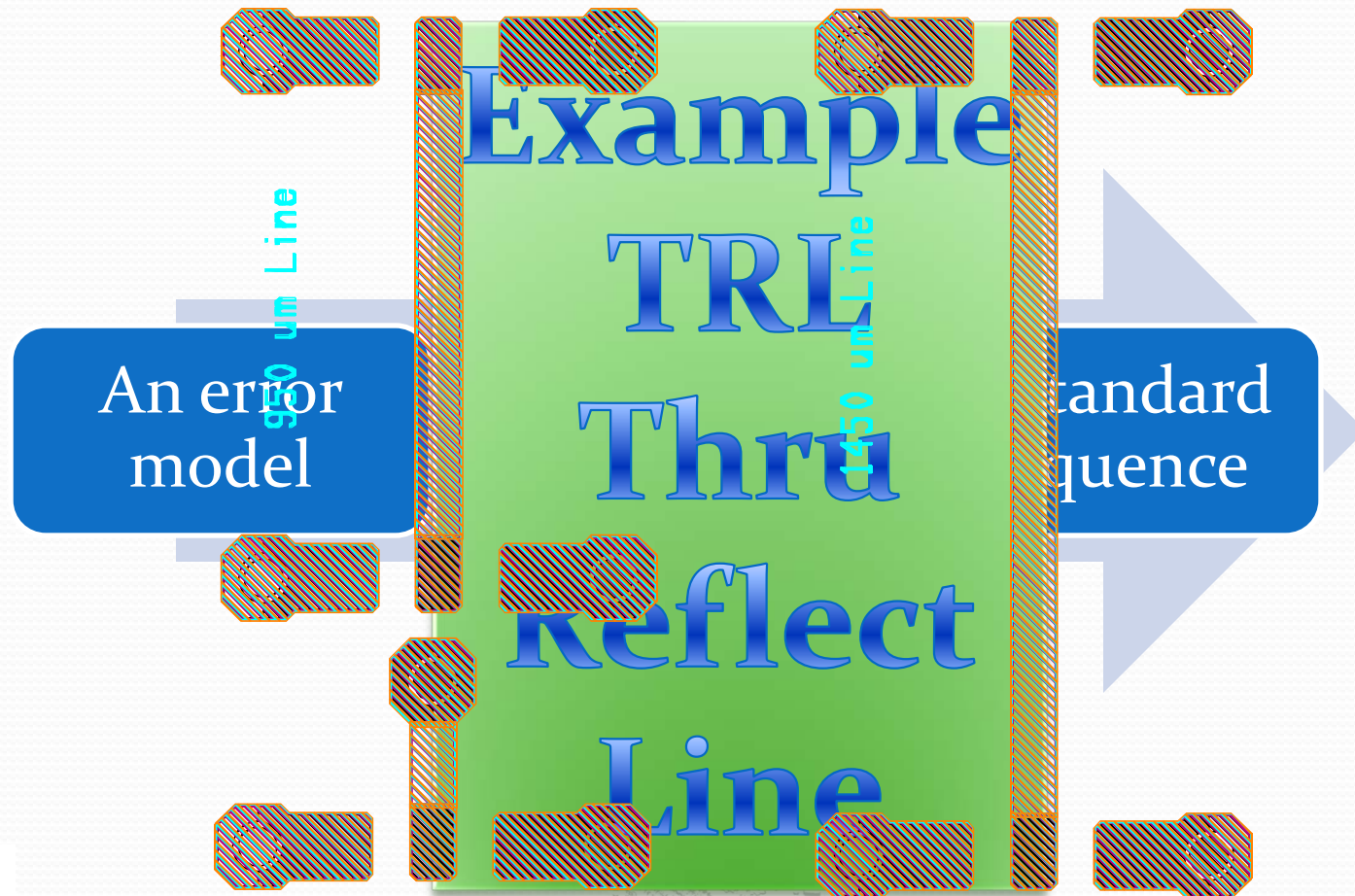
# Cause of Uncertainty

- Systematic Errors (85%)
  - Microwave Components
  - Interconnections
  - Incorrect Standard Modeling
  - Calibration Algorithm
- Random Error (10%)
  - Connection Repeatability
  - Frequency Stability
  - Noise
- Drift (5%)

**Calibration**

**Lab Care**

# Today 2-ports Calibrations

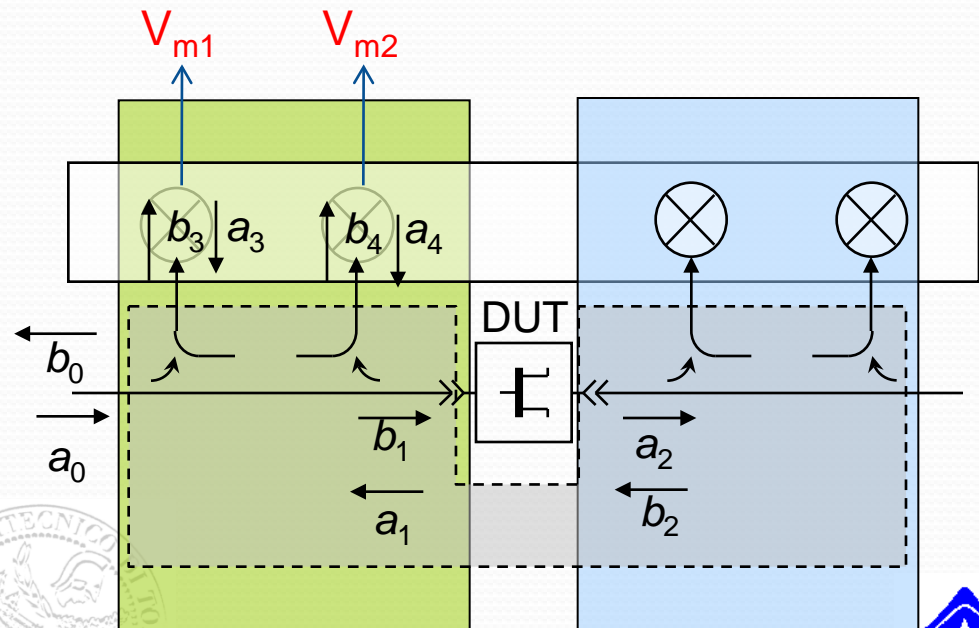


# Error Model Definition I

- **Ipothesis**

1. sampler (mixer), and all the other system components are **linear** and **invariant parts**
2. The two half   are independent 4-port network such that we can isolate each of them and the “talk” only through the DUT

- Let the  half
- 8 unknowns:  
 $a_0, b_0, a_1, b_1, a_3, b_3, a_4, b_4$
- The two acquire data are proportional to  $b_3, b_4$  :
- $V_{m1} = k_1 b_3, V_{m2} = k_2 b_4$



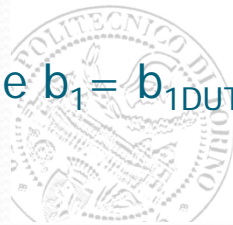
# Error Model Definition II

$$\begin{bmatrix} b_0 \\ b_1 \\ b_3 \\ b_4 \end{bmatrix} = \begin{pmatrix} S_{11} & S_{12} & S_{13} & S_{14} \\ S_{21} & S_{22} & S_{23} & S_{24} \\ S_{31} & S_{32} & S_{33} & S_{34} \\ S_{41} & S_{42} & S_{43} & S_{44} \end{pmatrix} \begin{bmatrix} a_0 \\ a_1 \\ a_3 \\ a_4 \end{bmatrix} \iff \text{4 port equation}$$

$$\begin{aligned} a_3 &= \Gamma_3 b_3 & V_{m1} &= k_3 b_3 \\ a_4 &= \Gamma_4 b_4 & V_{m2} &= k_4 b_4 \end{aligned} \iff \begin{array}{l} \text{Reflection Coefficients of the} \\ \text{downconversion part and} \\ \text{reading vs. wave} \end{array}$$

8 eq. with 10 unknowns. ( $a_0, b_0, a_1, b_1, a_3, b_3, a_4, b_4, V_{m1}, V_{m2}$ ):  
 Let use  $V_{m1}$  e  $V_{m2}$  as independent variables and called them:

$a_{m1} = V_{m1}, b_{m1} = V_{m2}, a_1 = a_{1DUT}$  e  $b_1 = b_{1DUT}$  we find the following model





# Error Model Definition III

$$\begin{bmatrix} b_0 \\ b_1 \\ b_3 \\ b_4 \end{bmatrix} = \begin{pmatrix} S_{11} & S_{12} & S_{13} & S_{14} \\ S_{21} & S_{22} & S_{23} & S_{24} \\ S_{31} & S_{32} & S_{33} & S_{34} \\ S_{41} & S_{42} & S_{43} & S_{44} \end{pmatrix} \begin{bmatrix} a_0 \\ a_1 \\ a_3 \\ a_4 \end{bmatrix}$$

$$a_3 = \Gamma_3 b_3$$

$$a_4 = \Gamma_4 b_4$$

$$b_0 = S_{11}a_0 + S_{12}a_1 + S_{13}a_3 + S_{14}a_4$$

$$b_1 = S_{21}a_0 + \dots$$

$$b_3 = S_{31}a_0 + \dots$$

$$b_4 = S_{41}a_0 + \dots + S_{44}a_4$$

$$b_0 = S_{11}a_0 + S_{12}a_1 + S_{13}\Gamma_3b_3 + S_{14}\Gamma_4b_4$$

$$b_1 = S_{21}a_0 + \dots + S_{23}\Gamma_3b_3 + S_{24}\Gamma_4b_4$$

$$b_3 = S_{31}a_0 + \dots + S_{33}\Gamma_3b_3 + S_{34}\Gamma_4b_4$$

$$b_4 = S_{41}a_0 + \dots + S_{43}\Gamma_3b_3 + S_{44}\Gamma_4b_4$$



# Error Model Definition IV

$$\begin{aligned}
 -S_{11}a_0 + b_0 - S_{12}a_1 &= S_{13}\Gamma_3 b_3 + S_{14}\Gamma_4 b_4 \\
 -S_{21}a_0 - S_{12}a_1 + b_1 &= S_{23}\Gamma_3 b_3 + S_{24}\Gamma_4 b_4 \\
 -S_{31}a_0 - S_{32}a_1 &= (S_{23}\Gamma_3 - 1)b_3 + S_{34}\Gamma_4 b_4 \\
 -S_{41}a_0 - S_{42}a_1 &= S_{43}\Gamma_3 b_3 + (S_{44}\Gamma_4 - 1)b_4
 \end{aligned}$$



$$\begin{bmatrix} -S_{11} & 1 & -S_{12} & 0 \\ -S_{21} & 0 & -S_{22} & 1 \\ -S_{31} & 0 & -S_{32} & 0 \\ -S_{41} & 0 & -S_{42} & 0 \end{bmatrix} \begin{bmatrix} a_0 \\ b_0 \\ a_1 \\ b_1 \end{bmatrix} = \begin{bmatrix} S_{13}\Gamma_3 & S_{14}\Gamma_4 \\ S_{23}\Gamma_3 & S_{24}\Gamma_4 \\ (S_{23}\Gamma_3 - 1) & S_{34}\Gamma_4 \\ S_{43}\Gamma_3 & (S_{44}\Gamma_4 - 1) \end{bmatrix} \begin{bmatrix} b_3 \\ b_4 \end{bmatrix}$$

If we call  $a_{m1}$  and  $b_{m1}$

$$V_{m1} = a_{m1} = k_3 b_3$$

$$V_{m2} = b_{m1} = k_4 b_4$$

$$\mathbf{W} \begin{bmatrix} a_0 \\ b_0 \\ a_1 \\ b_1 \end{bmatrix} = \mathbf{Q} \begin{bmatrix} b_3 \\ b_4 \end{bmatrix}$$

$$\begin{bmatrix} a_{m1} \\ b_{m1} \end{bmatrix} = \begin{bmatrix} k_1 & 0 \\ 0 & k_2 \end{bmatrix} \begin{bmatrix} b_3 \\ b_4 \end{bmatrix}$$

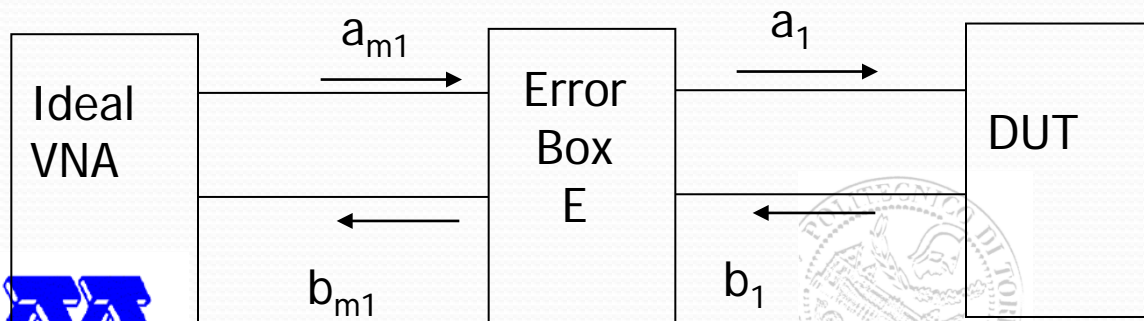


# The famous error box

$$\mathbf{W} \begin{bmatrix} a_0 \\ b_0 \\ a_1 \\ b_1 \end{bmatrix} = \mathbf{Q} \begin{bmatrix} b_3 \\ b_4 \end{bmatrix} \quad \begin{bmatrix} a_{m1} \\ b_{m1} \end{bmatrix} = \begin{bmatrix} k_1 & 0 \\ 0 & k_2 \end{bmatrix} \begin{bmatrix} b_3 \\ b_4 \end{bmatrix} = \mathbf{K} \begin{bmatrix} b_3 \\ b_4 \end{bmatrix}$$

$$\begin{bmatrix} a_0 \\ b_0 \\ a_1 \\ b_1 \end{bmatrix} = \mathbf{W}^{-1} \mathbf{Q} \mathbf{K}^{-1} \begin{bmatrix} a_{m1} \\ b_{m1} \end{bmatrix} = \mathbf{D} \begin{bmatrix} a_{m1} \\ b_{m1} \end{bmatrix}$$

$$\begin{aligned} a_0 &= D_{11} a_{m1} + D_{12} b_{m1} \\ b_0 &= D_{21} a_{m1} + D_{22} b_{m1} \\ a_1 &= D_{31} a_{m1} + D_{32} b_{m1} \\ b_1 &= D_{41} a_{m1} + D_{42} b_{m1} \end{aligned}$$



Shuffle the last 2 Equations and rename as

$$\begin{aligned} b_{m1} &= e_{11} a_{m1} + e_{12} b_1 \\ a_1 &= e_{21} a_{m1} + e_{22} b_1 \end{aligned}$$



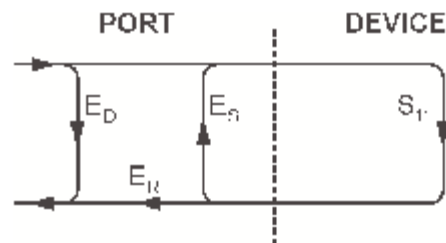
# Error Box Property

- It's not an actual network but only a linear system model
- Every parameter is frequency dependent but time invariant
- Since the  $E$  parameters are more or less link with some specifications of the coupler they are also called:

$$e_{11} = E_D \cong \textit{Directivity}$$

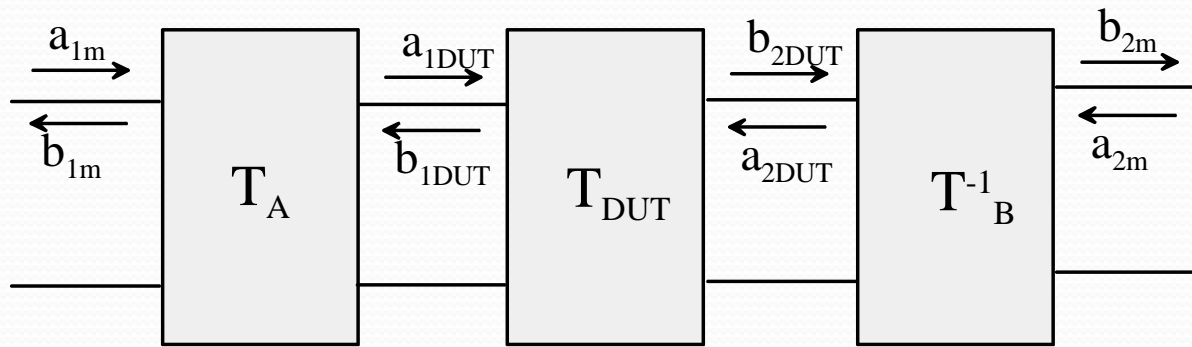
$$e_{22} = E_S \cong \textit{SourceMatch}$$

$$e_{21}e_{12} = E_R \cong \textit{Tracking}$$



# Two Port Error Model

Two error boxes on the right and left

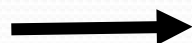


To apply this model, 4 independent readings on each source position are required

2-ports Measured S-matrix

$$\begin{bmatrix} b_{m1} \\ b_{m2} \end{bmatrix} = \mathbf{S} \mathbf{m} \begin{bmatrix} a_{m1} \\ a_{m2} \end{bmatrix}$$

~~$$S_{m_{ij}} = \frac{b_{mi}}{a_{mj}} \Big|_{a_{mi \neq j} = 0}$$~~



$$\begin{bmatrix} b'_{1m} \\ b'_{2m} \end{bmatrix} = \begin{pmatrix} S_{11m} & S_{12m} \\ S_{21m} & S_{22m} \end{pmatrix} \begin{bmatrix} a'_{1m} \\ a'_{2m} \end{bmatrix}, \quad \begin{bmatrix} b''_{1m} \\ b''_{2m} \end{bmatrix} = \begin{pmatrix} S_{11m} & S_{12m} \\ S_{21m} & S_{22m} \end{pmatrix} \begin{bmatrix} a''_{1m} \\ a''_{2m} \end{bmatrix}$$

$$\begin{pmatrix} S_{11m} & S_{12m} \\ S_{21m} & S_{22m} \end{pmatrix} = \begin{pmatrix} b'_{1m} & b''_{1m} \\ b'_{2m} & b''_{2m} \end{pmatrix} \begin{pmatrix} a'_{1m} & a''_{1m} \\ a'_{2m} & a''_{2m} \end{pmatrix}^{-1}$$

# FULL 2-Ports Error Model

$$\begin{bmatrix} b_{1DUT} \\ a_{1DUT} \end{bmatrix} = \begin{pmatrix} T_{A11} & T_{A12} \\ T_{A21} & T_{A22} \end{pmatrix}^{-1} \begin{bmatrix} b_{1m} \\ a_{1m} \end{bmatrix} = T_A^{-1} \begin{bmatrix} b_{1m} \\ a_{1m} \end{bmatrix}$$

8 error terms, but

7 UNKNOWN TO GET  
T<sub>dut</sub>

$$\begin{bmatrix} a_{2DUT} \\ b_{2DUT} \end{bmatrix} = \begin{pmatrix} T_{B11} & T_{B12} \\ T_{B21} & T_{B22} \end{pmatrix}^{-1} \begin{bmatrix} a_{2m} \\ b_{2m} \end{bmatrix} = T_B^{-1} \begin{bmatrix} a_{2m} \\ b_{2m} \end{bmatrix}$$

$T_A$ ,  $T_B$  are the transmission matrix equivalent of the two E matrices of left and right side while  $T_m$  is the transmission matrix equivalent of  $S_m$

$$\begin{bmatrix} b_{m1} \\ a_{m1} \end{bmatrix} = \mathbf{T}_m \begin{bmatrix} a_{m2} \\ b_{m2} \end{bmatrix} \longrightarrow \begin{bmatrix} b_{1m} \\ a_{1m} \end{bmatrix} = T_A T_{DUT} T_B^{-1} \begin{bmatrix} a_{2m} \\ b_{2m} \end{bmatrix}$$

# Most USED 2-port Calibrations

- TSD-TRL (Thru, Short, Delay or Thru, Reflect, Line)
- LRM (Line, Reflect, Match)
- SOLR (Short, Open, Load, Reciprocal)
- SOLT (Short, Open, Load, Thru)  
MANDATORY FOR 3 samplers VNAs

# SOLT

- The old good cal: **S**hort, **O**pen, **L**oad and **T**hru
- It measures 3 standards at port 1, 3 at port 2 and the THRU.
- It obviously overdetermined with the 8 port model (10 equations for 8 unknowns) but it's the proper choice for the 3-sampler architecture

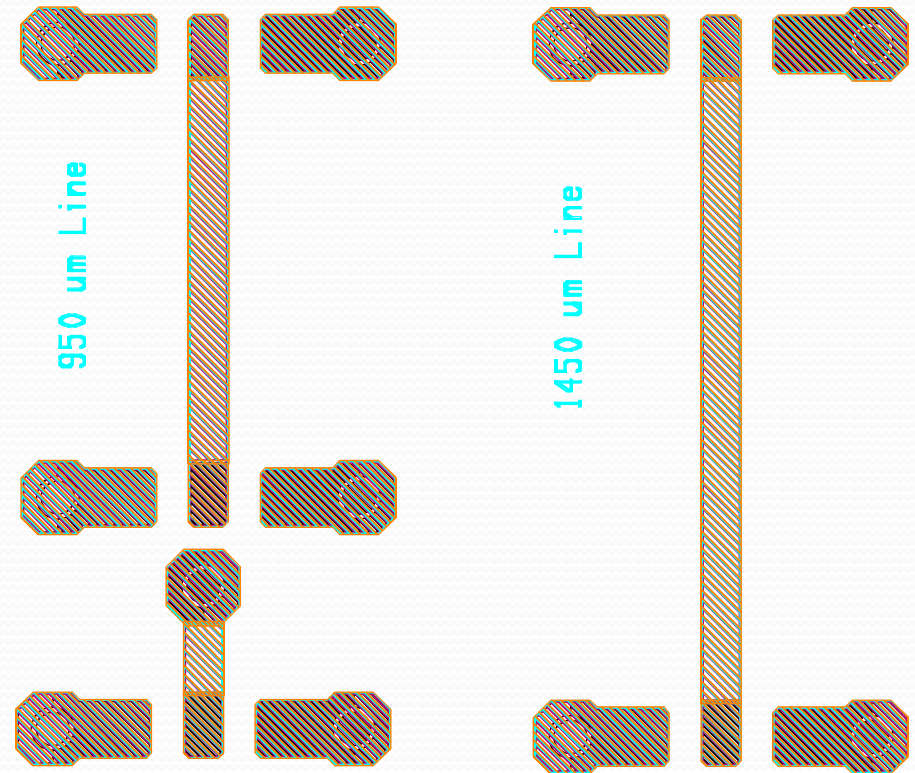


# Thru Reflect Line

- The Thru and Line must have the same geometry  
I.e. REFERENCE IMPEDANCE
- Normally the Reference plane it's placed in the middle of the THRU
- The system Reference impedance IS THE Characteristic impedance of the LINE
- Known 1 port Standard TSD
- Unknown 1 port standard -> TRL

# TSD-TRL II

- The length diff from the THRU and the LINE should avoid  $\lambda/2$  and its multiple
- To have broadband TRL more line are usefull (different line length)
- Side Result: The propagation constant of the line comes from free



# TSD-TRL III :MATH

$$T_L = \begin{pmatrix} e^{\gamma L_L} & 0 \\ 0 & e^{-\gamma L_L} \end{pmatrix}$$

Transmission matrix of the Line with  
Zref=Z<sub>¥</sub>

$$T_T = \begin{pmatrix} e^{\gamma L_T} & 0 \\ 0 & e^{-\gamma L_T} \end{pmatrix}$$

Transmission matrix of Thru with  
Zref=Z<sub>¥</sub> which imply that the LINE and  
THRU have the same geometry

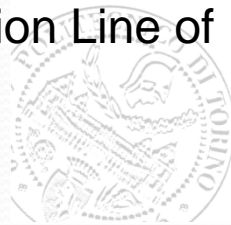
$$T_{Lm} = T_A T_L T_B^{-1}$$

$$T_L = T_A^{-1} T_{Lm} T_B$$

$$T_{Tm} = T_A T_T T_B^{-1}$$

$$T_T = T_A^{-1} T_{Tm} T_B$$

$T_{Lm}$  e  $T_{Tm}$  Measure Transmission Line of Line and Thru



# TSD-TRL IV : MATH

$$R_m = T_{Lm} T_{Tm}^{-1} = T_A T_L T_T^{-1} T_A^{-1} = T_A \Lambda T_A^{-1}$$

$R_m$ : from measurement

$$R_n = T_{Tm}^{-1} T_{Lm} = T_B T_T^{-1} T_L T_B^{-1} = T_B \Lambda T_B^{-1}$$

$R_n$ : from measurement

$$\Lambda = \begin{pmatrix} e^{\gamma(L_L - L_T)} & 0 \\ 0 & e^{-\gamma(L_L - L_T)} \end{pmatrix}$$



$\Lambda$  Diagonal Matrix

$T_A$  Eigenvector matrix of  $R_m$ ,  $T_B$  Eigenvector matrix of  $R_n$

# TSD-TRL V:MATH

$$T_A = p \begin{pmatrix} \frac{k}{p} a & b \\ \frac{k}{p} & 1 \end{pmatrix} = pX_A, \quad T_B = w \begin{pmatrix} 1 & \frac{u}{w} \\ f & \frac{u}{w} g \end{pmatrix} = wX_B$$

- $a, b + f, g$  from eigenvector

Deembedding:

$$T_{DUT} = \frac{p}{w} X_A T_m X_B^{-1} = \alpha X_A T_m X_B^{-1}$$

# TSD I

1. The one port standard  $G_S$  is known
2.  $G_S$  is measured at port 1 ( $G_{Sm1}$ ) and 2 ( $G_{Sm2}$ )

$$\Gamma_{Sm1} = \frac{b + \frac{k}{p} a \Gamma_S}{1 + \frac{k}{p}} \Rightarrow \frac{k}{p} = \frac{b - \Gamma_{Sm1}}{(\Gamma_S - a) \Gamma_{Sm1}}$$

$$\Gamma_{Sm2} = \frac{f + \frac{u}{w} g \Gamma_S}{1 + \frac{u}{w}} \Rightarrow \frac{u}{w} = \frac{f - \Gamma_{Sm2}}{(\Gamma_S - g) \Gamma_{Sm2}}$$



# TSD II

3. Once  $k/p$  e  $u/w$  are known, from the measurement of Thru  $S_{21m}$  we finally find  $\alpha$ :

$$\alpha = \frac{(g - f) \frac{u}{w}}{S_{21m} \left(1 - \frac{k}{p} \frac{u}{w}\right)}$$



# TRL

1. The one port standard is unknown  $\Gamma_s$
2. And measured at port 1 ( $\Gamma_{Sm1}$ ) and 2 ( $\Gamma_{Sm2}$ )
3. There are 3 unknowns:

$$\Gamma_s, \frac{k}{p}, \frac{u}{w}$$

And 3 equations:

$$\Gamma_{sm1} = \frac{b + \frac{k}{p} a \Gamma_s}{1 + \frac{k}{p}}, \quad \Gamma_{sm2} = \frac{f + \frac{u}{w} g \Gamma_s}{1 + \frac{u}{w}}, \quad \frac{T_{Tm12}}{T_{Tm22}} = S_{Tm11} = \frac{-\frac{k}{p} a \frac{u}{w} + b}{-\frac{k}{p} \frac{u}{w} + 1}$$

$$\Gamma_s^2 = \frac{\left(b - \Gamma_{Sm1}\right)\left(f - \Gamma_{Sm2}\right)\left(S_{11m} - a\right)}{\left(a - \Gamma_{Sm1}\right)\left(g - \Gamma_{Sm2}\right)\left(S_{11m} - a\right)}$$

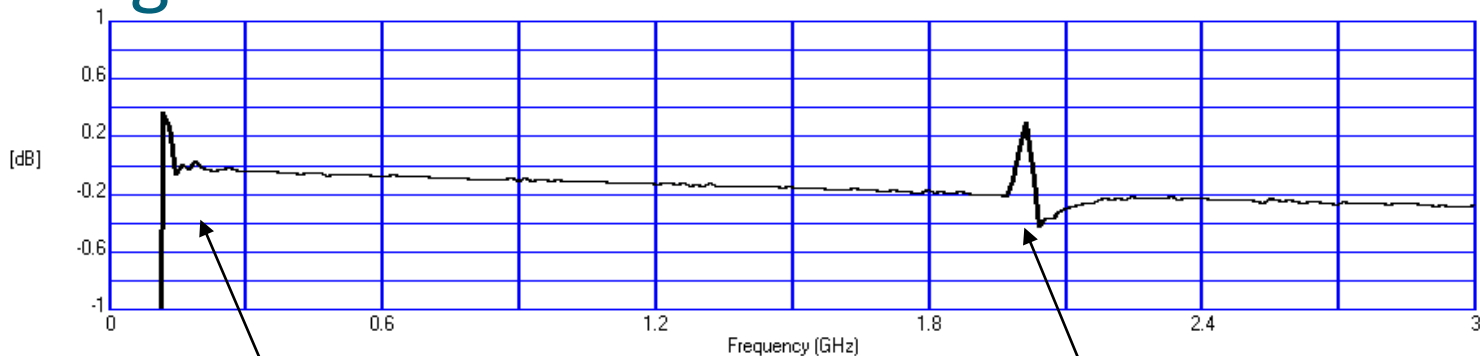


# Summary of TRL-TSD

- Thru and Line have the same  $Z_{ref}=Z_{\infty}$  and this becomes the reference impedance of the system and must be known in advance.
- AVOID FREQUENCY WHICH BRING THRU and the LINE length =  $\lambda/2$  and its multiple
- Multiple lines to cover broadband with at least  $10^{\circ}$  of phase difference
- IT REQUIRES TO MOVE THE PROBE LATERALLY

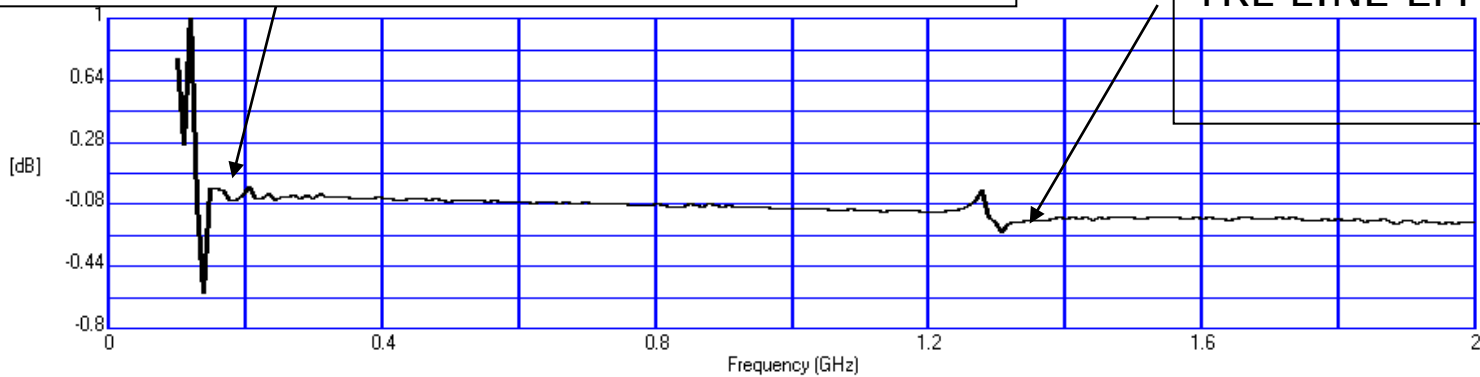
# Wrong TRL LINE

TITLE  
SPARAMETER

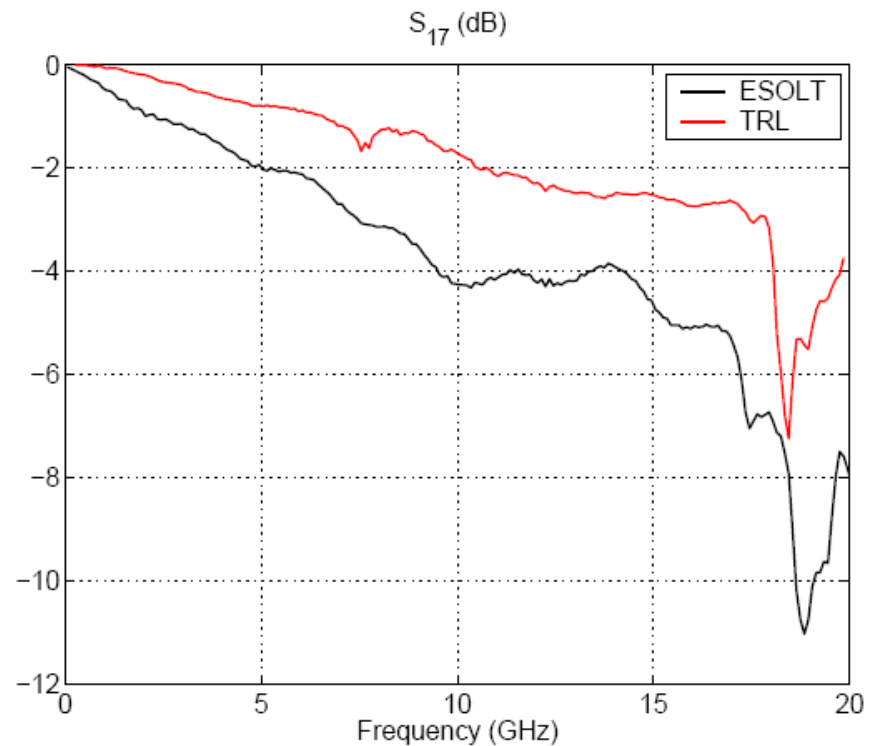
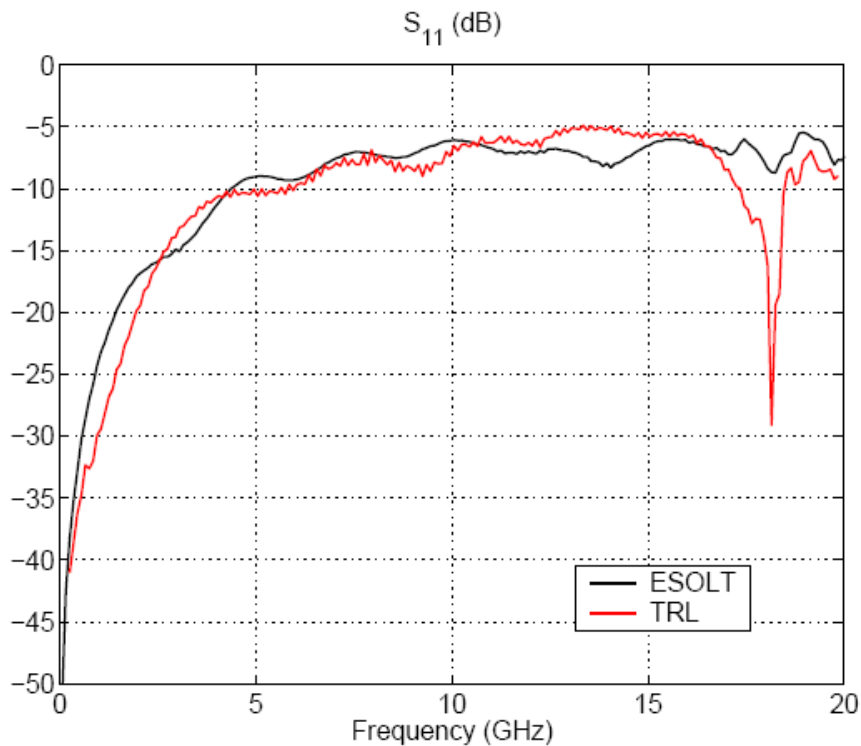


Here the test set were used below it's spec frequency limits(0.5GHz), the Dynamic Range decrease so much that the results become completely out

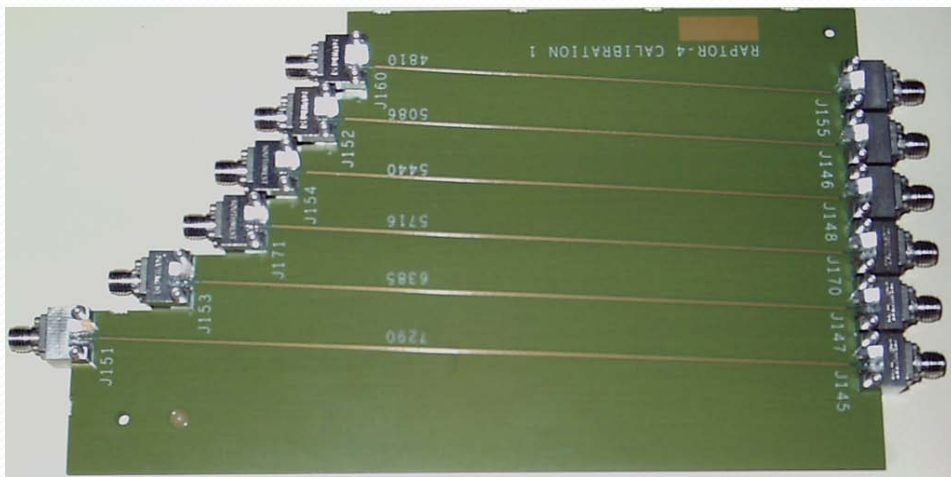
TRL LINE EFFECTS



# Different Algorithms

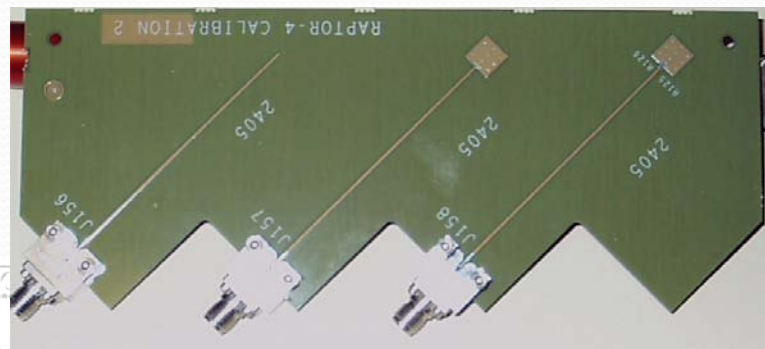


# Coax TRL On-Board Calibration/Verification Structures

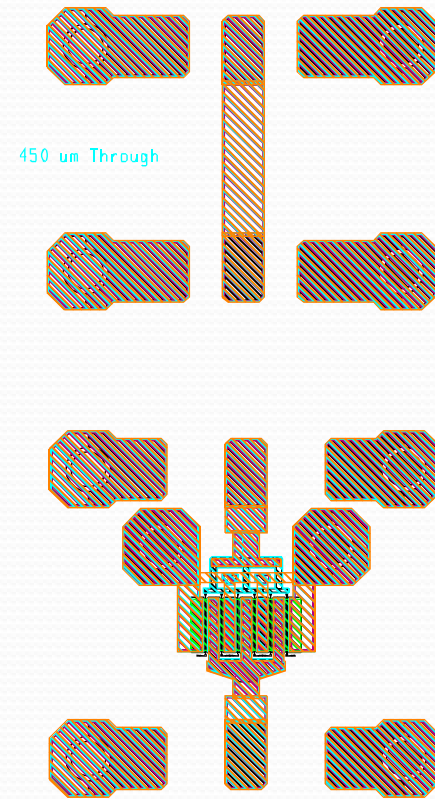
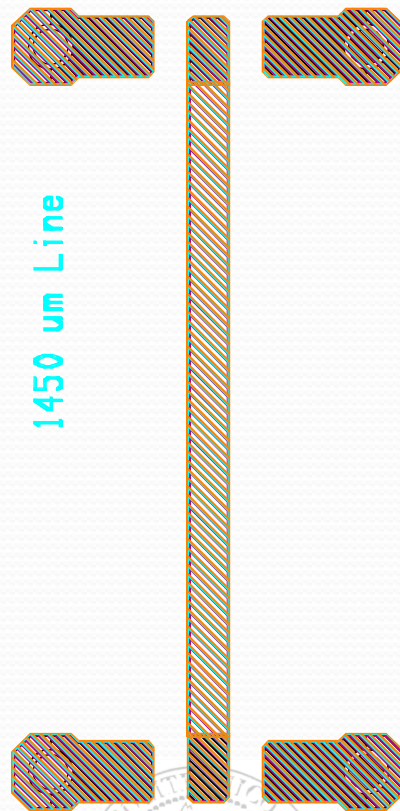
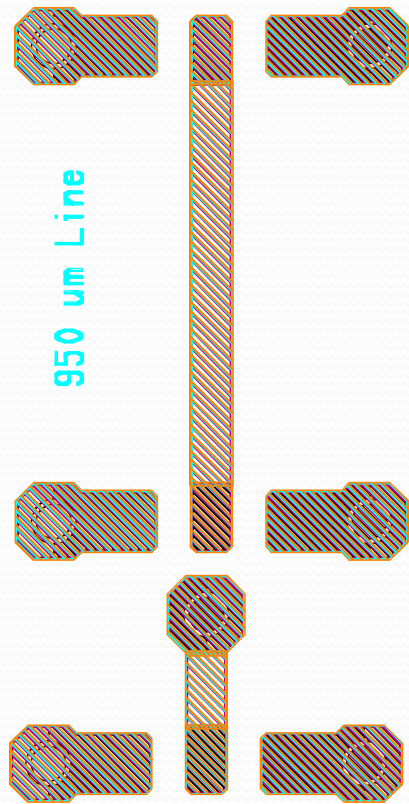


Thru and Line Structures

Reflect and Match Structures



# On-wafer Standard



# SOLR

- **Short, Open, Load and Reciprocal**
- **NO MORE THRU OR LINE REQUIRED**  
**BUT**
- 3 fully known standards and one fully unknown but reciprocal 2-port device (a cable for example)
- Free from port position problem

# SOLR MATH I

- Let's take again  $X_a$  e  $X_b$  and  $\Gamma_{sm1,2}$

$$T_A = p \begin{pmatrix} \frac{k}{p} a & b \\ 1 & 1 \end{pmatrix} = pX_{A'}, \quad T_B = W \begin{pmatrix} 1 & \frac{u}{W} \\ f & \frac{u}{W} g \end{pmatrix} = WX_B$$

$$\Gamma_{Sm1} = \frac{\frac{k}{p} a \Gamma_S + b}{1 + \frac{k}{p} \Gamma_S}, \quad \Gamma_{Sm2} = \frac{\frac{u}{W} g \Gamma_S + f}{1 + \frac{u}{W} \Gamma_S}$$





# SOLR II

□ With 3 fully known loads at port 1 we get:

$$a \frac{k}{p} , \frac{k}{p} , b$$

Thus  $X_a$  is now known

• Than with 3 fully known standard on port 2 we get :

$$f \frac{u}{w} , \frac{u}{w} , g$$

Thus even  $X_b$  is now fully know what is left is

$$\alpha = \frac{p}{w}$$

# SOLR III

$$\mathbf{T}_m = \frac{p}{w} \mathbf{X}_a \mathbf{T}_{dut} (\mathbf{X}_b)^{-1} = \alpha \mathbf{X}_a \mathbf{T}_{dut} (\mathbf{X}_b)^{-1}$$

$$\det(\mathbf{T}_m) = \alpha^2 \frac{\det(\mathbf{X}_a) \det(\mathbf{T}_{dut})}{\det(\mathbf{X}_b)}$$

←  $\det(\mathbf{T}_{dut}) = 1$   
for the reciprocity

$$\alpha = \pm \sqrt{\frac{\det(\mathbf{T}_m) \det(\mathbf{X}_b)}{\det(\mathbf{X}_a)}}$$

□ The sign of  $\alpha$  is given by a rough estimate of the delay introduced by the reciprocal

# SOLR Features

- A Thru is no more needed but just a way to connect the ports
- It's more to perform a calibration with the same port gender
- It's enough accurate when good one port standard and their models are available
- The Reference impedance is the one of the load standard

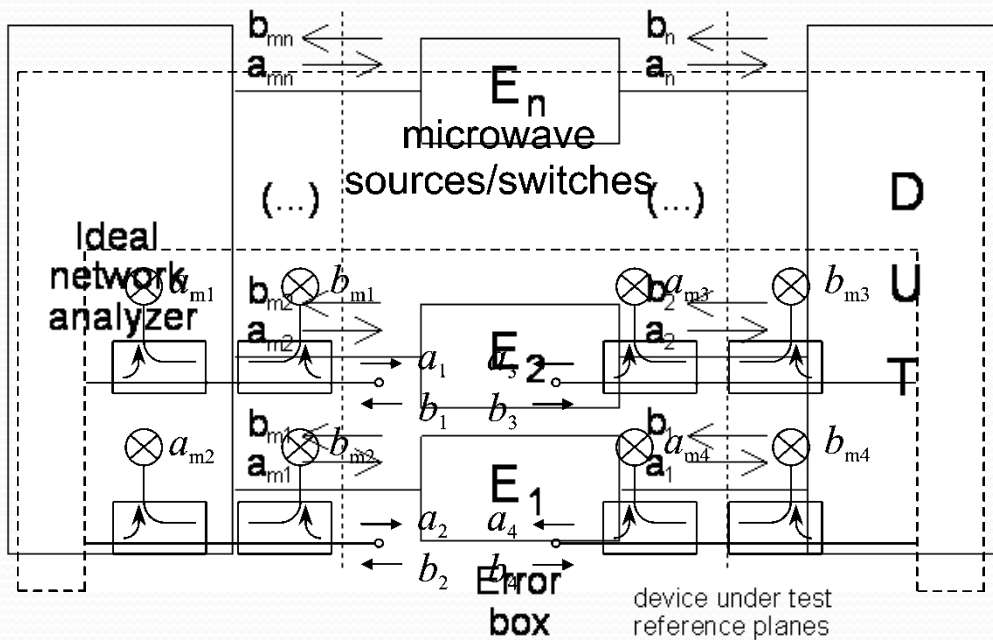
# Multipoint Calibration

**What if:**

**Calibration cannot be  
based on a fixed sequence**

**A general formulation must  
be found !**

# Classical multiport error model



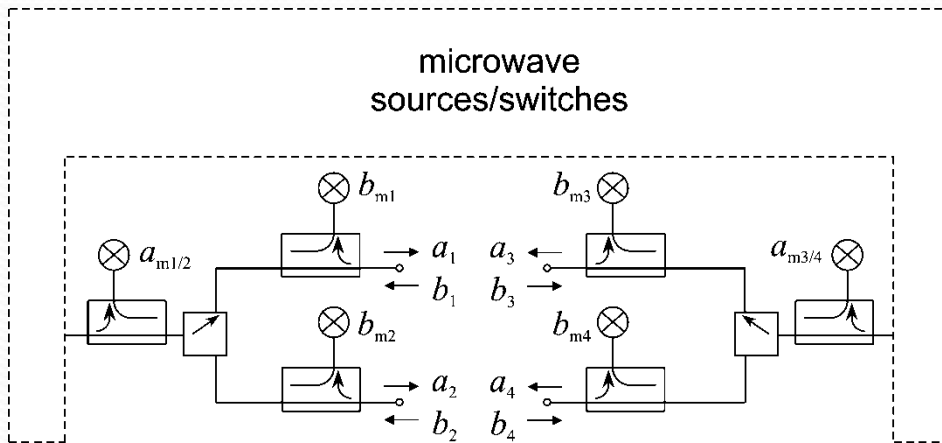
- Complete reflectometer multiport architecture: two directional couplers @ each port
- Error box extension as

$$\begin{aligned}
 a_i &= l_i b_{mi} - h_i c_{mi} \\
 b_i &= k_i b_{mi} - m_i a_{mi}
 \end{aligned}
 \quad
 \begin{matrix}
 \left[ \begin{array}{cccc} 1 & 0 & \dots & 0 \\ 0 & \dots & \dots & 0 \\ \vdots & \vdots & \vdots & \vdots \\ 0 & \dots & \dots & 0 \end{array} \right] &
 \left[ \begin{array}{cccc} 1 & 0 & \dots & 0 \\ 0 & \dots & \dots & 0 \\ \vdots & \vdots & \vdots & \vdots \\ 0 & \dots & \dots & 0 \end{array} \right] &
 \left[ \begin{array}{cccc} h_{m1} & 0 & \dots & 0 \\ 0 & \dots & \dots & 0 \\ \vdots & \vdots & \vdots & \vdots \\ 0 & \dots & \dots & 0 \end{array} \right] &
 \left[ \begin{array}{cccc} \dots & 0 & \dots & 0 \\ 0 & \dots & \dots & 0 \\ \vdots & \vdots & \vdots & \vdots \\ 0 & \dots & \dots & 0 \end{array} \right]
 \end{matrix}
 \quad
 \begin{aligned}
 \mathbf{v} &= \mathbf{L} \mathbf{b}_m - \mathbf{H} \mathbf{a}_m \\
 \mathbf{v} &= \mathbf{K} \mathbf{b}_m - \mathbf{M} \mathbf{a}_m
 \end{aligned}$$

4n - 1 unknowns



# Partial Reflectometer error model



- Partial reflectometer multiport architecture: two directional couplers @ each port are not always available
- This architecture has the advantages of costs ( $n-2$  couplers are saved) and speed

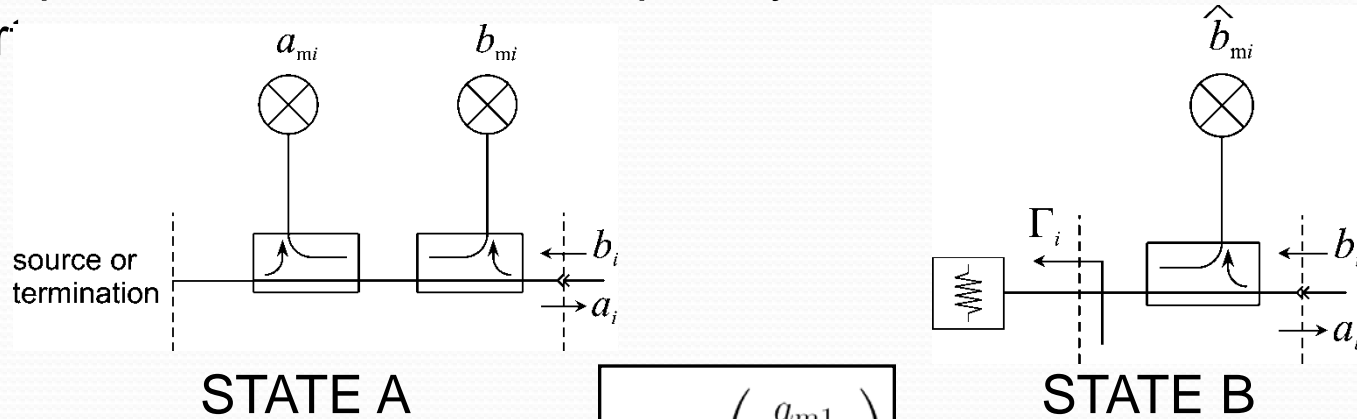
□ The model for these case must be:

- of general validity (i.e. not valid for only one calibration algorithm and scalable)
- compatible with the complete reflectometer one
- easy to be calibrated



# The new formulation

- The partial reflectometer multiport system has two states, for each  $i$  port



$$\mathbf{a} = \begin{pmatrix} a_1 \\ a_2 \\ \vdots \\ a_n \end{pmatrix}$$

$$a_i = l_i$$

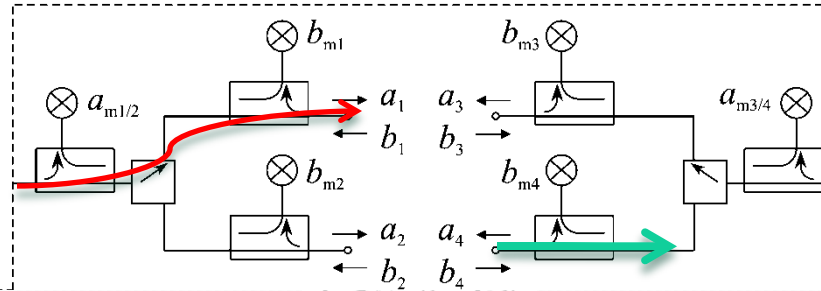
$$b_i = k_i$$

$$\mathbf{a} = \mathbf{L}$$

$$\mathbf{b} = \mathbf{K}$$

$$\mathbf{a}_m = \begin{pmatrix} a_{m1} \\ a_{m2} \\ \vdots \end{pmatrix}$$

microwave sources/switches



$$\hat{b}_{mi}$$

$$\hat{b}_{mi}$$

$$\hat{\mathbf{b}}_m$$

$$\hat{\mathbf{b}}_m$$





- In any measurement condition,  $a_i$  and  $b_i$  are defined quantities, with a certain value, VALUE THAT DOES NOT DEPEND on which error model we adopt, i.e.:

$$\begin{aligned} a_i &= l_i b_{mi} - h_i a_{mi} & a_i &= g_i \hat{b}_{mi} \\ b_i &= k_i b_{mi} - m_i a_{mi} & b_i &= f_i \hat{b}_{mi} \end{aligned} =$$

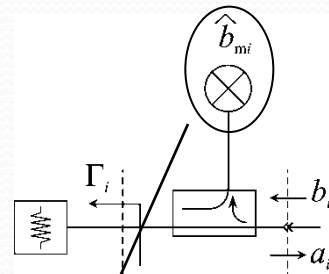
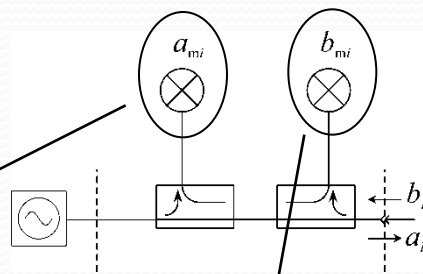
- All these equations can be written for each source position, and stacked together in matrix form:

different source positions,  $n$  = number of ports

$$\mathbf{a}_1 = \begin{pmatrix} a'_1 \\ a'_2 \\ \vdots \\ a'_n \end{pmatrix} \downarrow \downarrow \mathbf{a}_2 \dots \mathbf{a}_n, \mathbf{B} = [\mathbf{b}_1 \mathbf{b}_2 \dots \mathbf{b}_n]$$

$$\mathbf{A}_m = [\mathbf{a}_{m1} \mathbf{a}_{m2} \dots \mathbf{a}_{mn}], \mathbf{B}_m = [\mathbf{b}_{m1} \mathbf{b}_{m2} \dots \mathbf{b}_{mn}]$$

• Let:



$$\tilde{\mathbf{A}}_m \equiv \begin{bmatrix} a_{m11} & 0 & \cdots & 0 \\ 0 & a_{m22} & \cdots & 0 \\ \vdots & \vdots & \ddots & \vdots \\ 0 & 0 & \cdots & a_{mnn} \end{bmatrix} \quad \tilde{\mathbf{B}}_m \equiv \begin{bmatrix} b_{m11} & 0 & \cdots & 0 \\ 0 & b_{m22} & \cdots & 0 \\ \vdots & \vdots & \ddots & \vdots \\ 0 & 0 & \cdots & b_{mnn} \end{bmatrix} \quad \hat{\mathbf{B}}_m \equiv \begin{bmatrix} 0 & \hat{b}_{m12} & \hat{b}_{m13} & \cdots & \hat{b}_{m1n} \\ \hat{b}_{m21} & 0 & \hat{b}_{m23} & \cdots & \hat{b}_{m2n} \\ \hat{b}_{m31} & \hat{b}_{m32} & 0 & \cdots & \hat{b}_{m3n} \\ \vdots & \vdots & \ddots & \ddots & \vdots \\ \hat{b}_{mnn-1} & \hat{b}_{mnn-2} & \cdots & \hat{b}_{mnn-1} & 0 \end{bmatrix}$$

□ As well as:

$$\mathbf{A} = \tilde{\mathbf{A}} + \hat{\mathbf{A}}$$

$$\mathbf{B} = \tilde{\mathbf{B}} + \hat{\mathbf{B}}$$


$$\tilde{\mathbf{A}} \equiv \begin{bmatrix} a_{11} & 0 & \cdots & 0 \\ 0 & a_{22} & \cdots & 0 \\ \vdots & \vdots & \ddots & \vdots \\ 0 & 0 & \cdots & a_{nn} \end{bmatrix} \quad \hat{\mathbf{A}} \equiv \begin{bmatrix} 0 & a_{12} & a_{13} & \cdots & a_{1n} \\ a_{21} & 0 & a_{23} & \cdots & a_{2n} \\ a_{31} & a_{32} & 0 & \cdots & a_{3n} \\ \vdots & \vdots & \ddots & \ddots & \vdots \\ a_{n1} & a_{n2} & \cdots & a_{nn-1} & 0 \end{bmatrix}$$

- **Since** for each source position at each port we may have:

$$\begin{aligned} a_i &= l_i b_{mi} - h_i a_{mi} \\ b_i &= k_i b_{mi} - m_i a_{mi} \end{aligned}$$

or

$$\begin{aligned} a_i &= g_i \hat{b}_{mi} \\ b_i &= f_i \hat{b}_{mi} \end{aligned}$$




$$\begin{aligned} \tilde{A} &= L \tilde{B}_m - H \tilde{A}_m \\ \tilde{B} &= K \tilde{B}_m - M \tilde{A}_m \end{aligned}$$



$$\begin{aligned} \hat{A} &= G \hat{B}_m \\ \hat{B} &= F \hat{B}_m \end{aligned}$$

and

$$A = \tilde{A} + \hat{A} \quad B = \tilde{B} + \hat{B}$$



$$\begin{aligned} A &= \tilde{A} + \hat{A} = L \tilde{B}_m - H \tilde{A}_m + G \hat{B}_m \\ B &= \tilde{B} + \hat{B} = K \tilde{B}_m - M \tilde{A}_m + F \hat{B}_m \end{aligned}$$

$$\mathbf{B} = \mathbf{K}\tilde{\mathbf{B}}_m - \mathbf{M}\tilde{\mathbf{A}}_m + \mathbf{F}\hat{\mathbf{B}}_m \quad \mathbf{A} = \mathbf{L}\tilde{\mathbf{B}}_m - \mathbf{H}\tilde{\mathbf{A}}_m + \mathbf{G}\hat{\mathbf{B}}_m$$

$$\mathbf{B} = \mathbf{S}\mathbf{A}$$

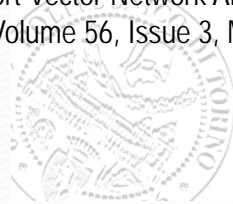
$$-\mathbf{S}\mathbf{G}\hat{\mathbf{B}}_m + \mathbf{F}\hat{\mathbf{B}}_m - \mathbf{S}\mathbf{L}\tilde{\mathbf{B}}_m + \mathbf{K}\tilde{\mathbf{B}}_m + \mathbf{S}\mathbf{H}\tilde{\mathbf{A}}_m - \mathbf{M}\tilde{\mathbf{A}}_m = \mathbf{0}$$

$6n - 1$  unknowns

- And the de-embedding is:

$$\mathbf{S} = \left[ \mathbf{K}\tilde{\mathbf{B}}_m - \mathbf{M}\tilde{\mathbf{A}}_m + \mathbf{F}\hat{\mathbf{B}}_m \right] \left[ \mathbf{L}\tilde{\mathbf{B}}_m - \mathbf{H}\tilde{\mathbf{A}}_m + \mathbf{G}\hat{\mathbf{B}}_m \right]^{-1}$$

"A Novel Calibration Algorithm for a Special Class of Multiport Vector Network Analyzers", Ferrero, A.; Teppati, V.; Garelli, M.; Neri, A.  
IEEE Transactions on Microwave Theory and Techniques, Volume 56, Issue 3, March 2008



# Let's look at the cal equation

$$-SG\hat{B}_m + F\hat{B}_m - SL\tilde{B}_m + K\tilde{B}_m + SH\tilde{A}_m - M\tilde{A}_m = 0$$

- Based on S parameters
- Always defined for any standards
- Can be used to find H,L,M,K,F,G during the cal
- As well as to find S during the measurement



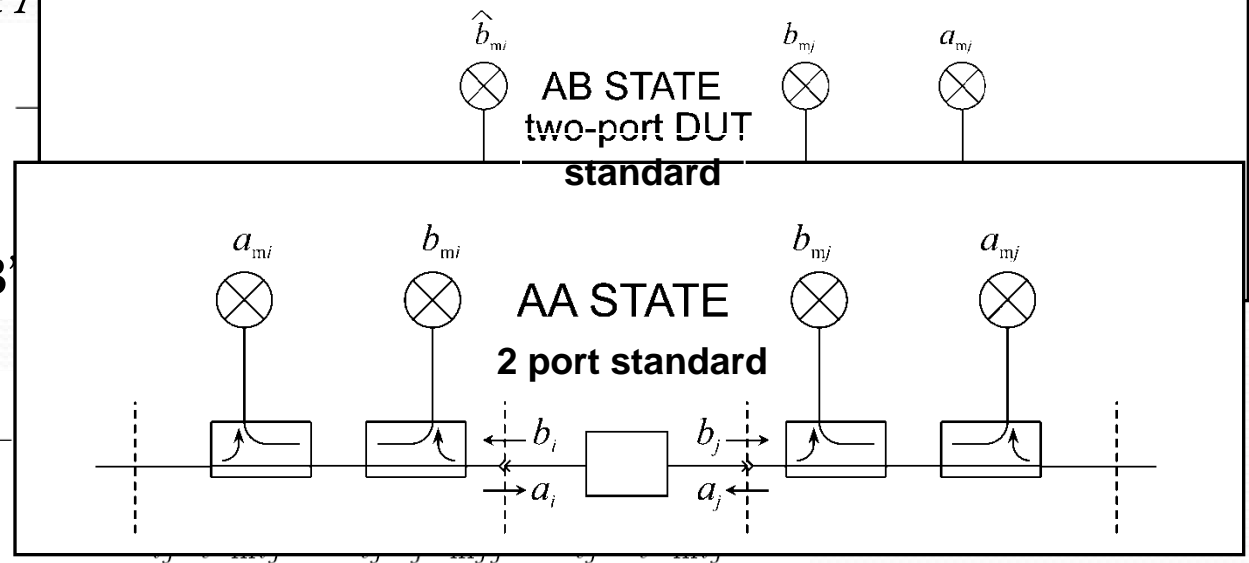
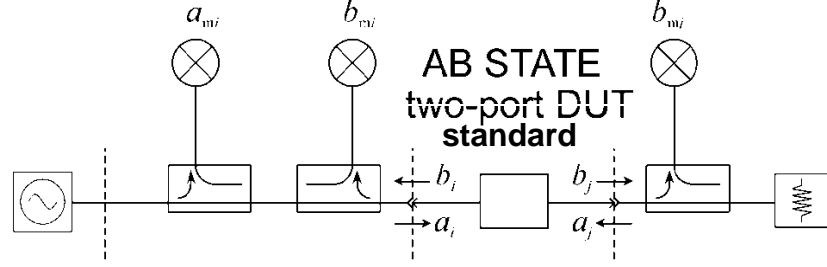
# Even a more

- For the calibration that i.e. for an “all state A

$$\sum_{p=1}^n S_{ip} l_p b_{mpj}$$

- and for a “state A-B”

$$-\sum_{p=1}^n (1 -$$



(i = 1, ..., n)  
(j = 1, ..., n)

- during calibration, each standard measurement will give type A equations, or type B equations, accordingly to the measurement configuration used (AA or AB)



# Dynamic Calibration

Since no constraints are given on the standard type and the math can combine whatever sequence, the calibration becomes dynamic i.e. the software can generate the standard sequence which gives a set of enough linear independent equations as well as it accomplished for:

- Connectors at each ports
- Available standards USE ONLY 1 or 2 ports ONES !!
- User interconnection description
- Use of particular two port pairs self calibration





# Partially Known Standards

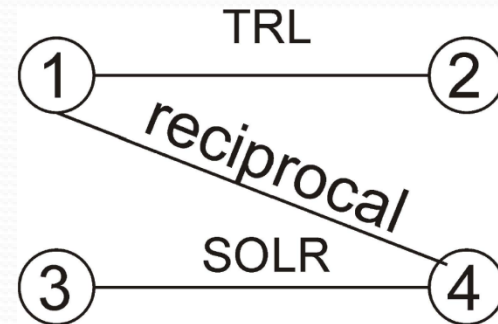
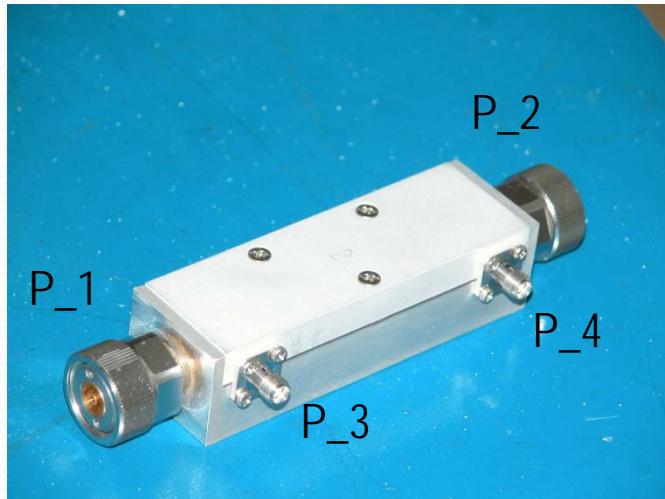
- If two ports can go in state A contemporarily, classical SOLT, LRM, TRL, SOLR etc. algorithms can be applied to these ports because the new error model is compatible with the classical one!

Let's combine everything

and design  
a cal that fits the DUT



# Example: Design CAL for the DUT



|     | P_1   | P_2 | P_3   | P_4   |
|-----|-------|-----|-------|-------|
| P_1 | X     | TRL | X     | Recip |
| P_2 | TRL   | X   | X     | X     |
| P_3 | X     | X   | SOL   | Recip |
| P_4 | Recip | X   | Recip | SOL   |

| Standard                 | Port | Port |
|--------------------------|------|------|
| APC7THRU                 | 1    | 2    |
| APC7-AirLine             | 1    | 2    |
| APC7REFLECT              | 1    |      |
| APC7REFLECT              | 2    |      |
| 3.5mm BroadBand Load-F   | 3    |      |
| 3.5mm Female Open        | 3    |      |
| 5mm Coaxial Female Short | 3    |      |
| 3.5mm BroadBand Load-F   | 4    |      |
| 3.5mm Female Open        | 4    |      |
| 5mm Coaxial Female Short | 4    |      |
| APC7-3.5mmF              | 1    | 4    |
| 3.5mm F-F Adapter        | 3    | 4    |



# Cause of Uncertainty

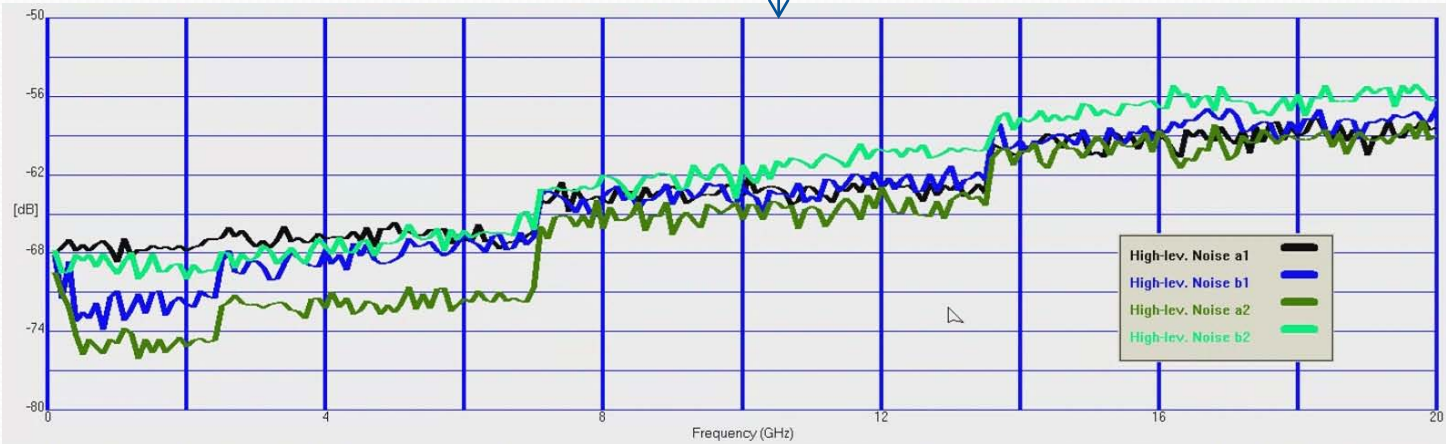
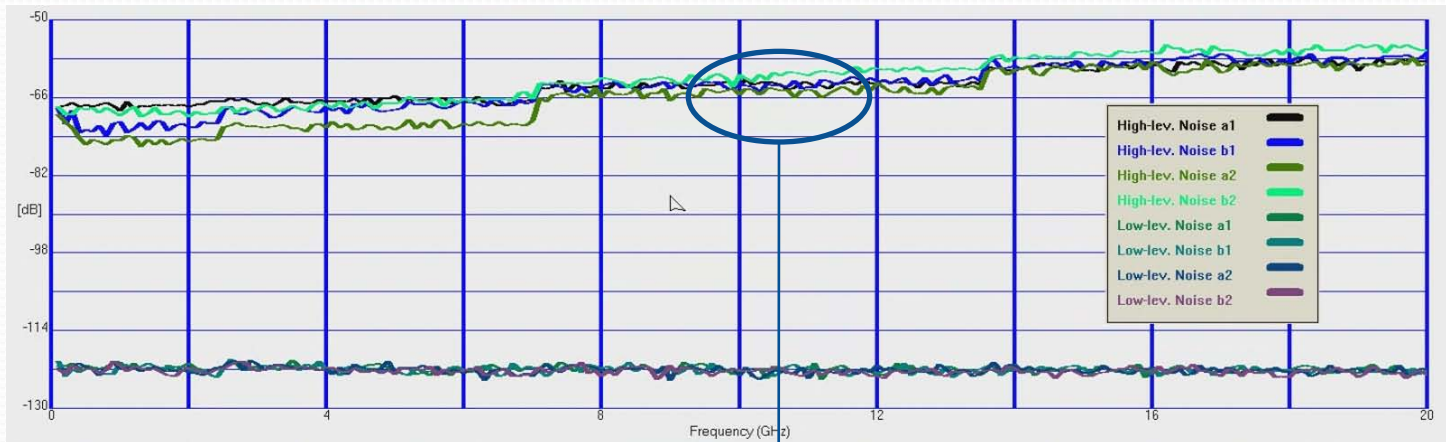
- Systematic Errors (85%)
  - Microwave Components
  - Interconnections
  - Incorrect Standard Modeling
  - Calibration Algorithm
- Random Error (10%)
  - Connection Repeatability
  - Frequency Stability
  - Noise
- Drift (5%)

**Calibration**

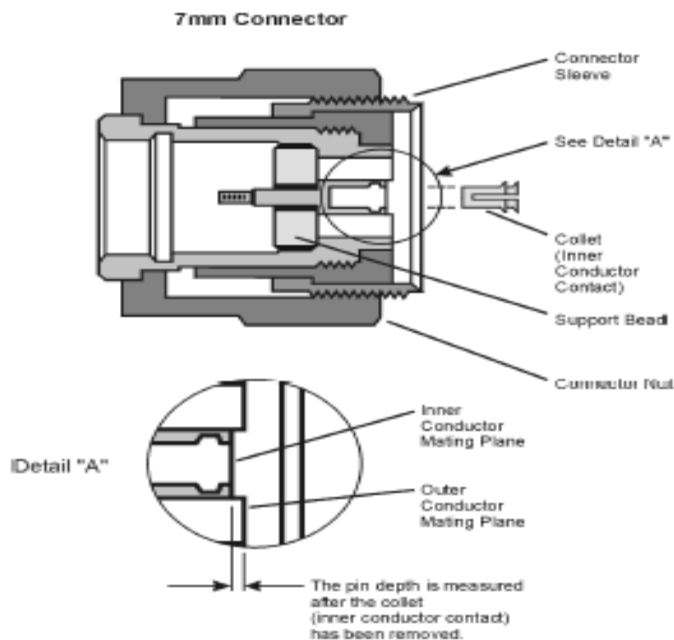
**Lab Care**

# VNA Noise

THE GOOD OLD 8510:RAW DATA NOISE



# Repeatability an example: APC7mm



A close look to the connector

| Device          | Typical Pin Depth micrometers (10 <sup>-4</sup> inches) | Measurement Uncertainty <sup>a</sup> micrometers (10 <sup>-4</sup> inches) | Observed Pin Depth Limit <sup>b</sup> micrometers (10 <sup>-4</sup> inches) |
|-----------------|---|--|---|
| Opens           | 0 to -12.7<br>(0 to -5.0)                               | +10.02 to -10.2<br>(+ 4.0 to -4.0)   | +10.2 to -22.91<br>(+ 4.0 to -9.0)  |
| Shorts          | 0 to -5.1<br>(0 to -2.0)                                | +6.4 to -6.4<br>(+ 2.5 to -2.5)  | +6.4 to -11.4<br>(+ 2.5 to -4.5)  |
| Broadband loads | 0 to -7.62<br>(0 to -3.0)                               | +4.1 to -4.1<br>(+ 1.6 to -1.6)  | +4.1 to -11.7<br>(+ 1.6 to -4.6)  |

Table 2-3 Electrical Specifications for 85050D 7 mm Devices

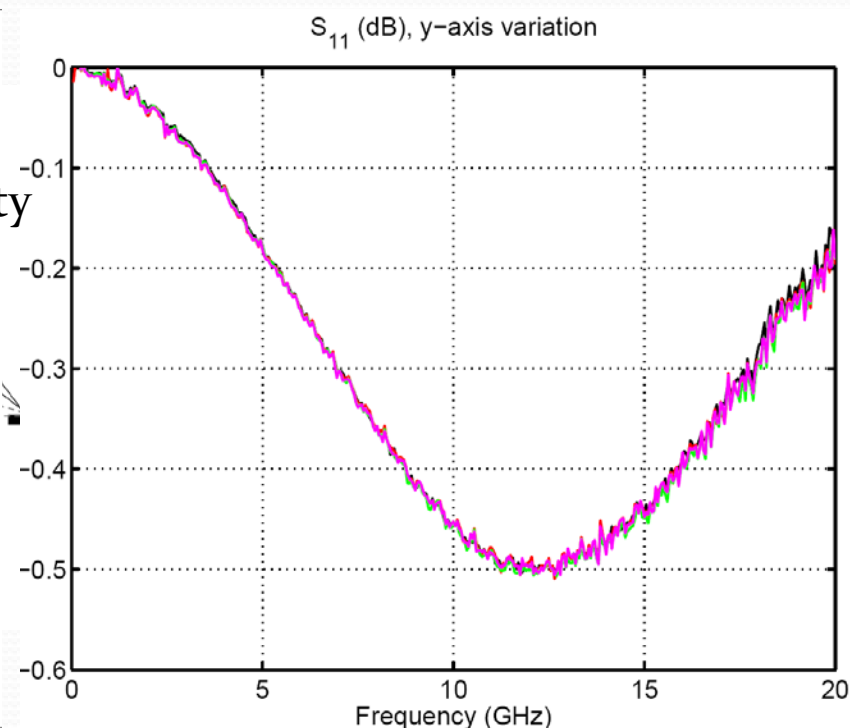
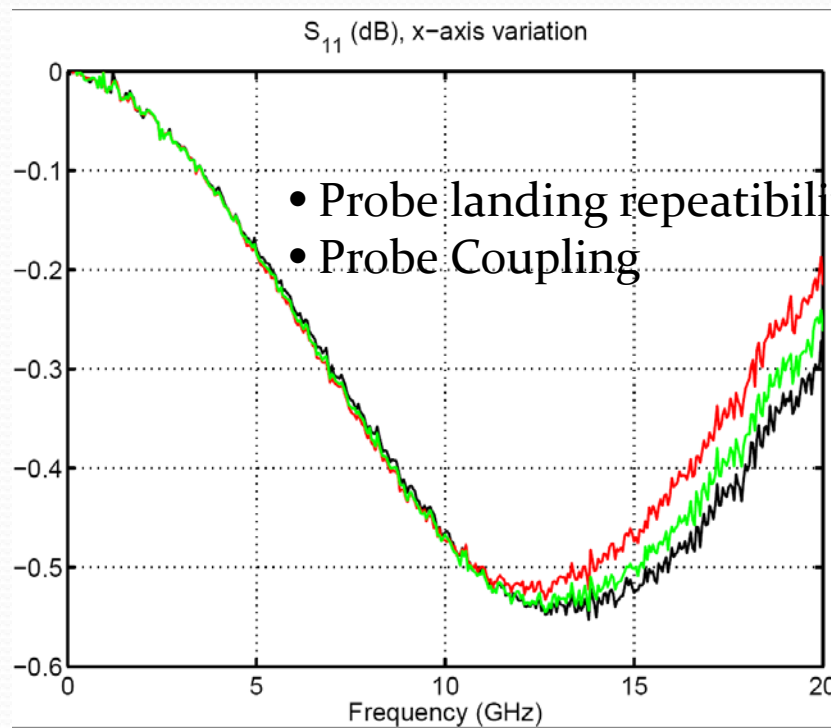
| Device                               | Specification       | Frequency (GHz)          |
|--------------------------------------|---------------------|--------------------------|
| Broadband loads                      | ≥ 38 dB Return loss | dc to 18 GHz             |
| Short <sup>a</sup> collet style      | ± 0.2° from nominal | dc to 2 GHz <sup>b</sup> |
|                                      | ± 0.3° from nominal | 2 to 8 GHz <sup>b</sup>  |
|                                      | ± 0.5° from nominal | 8 to 18 GHz <sup>b</sup> |
| Open <sup>a</sup> with collet pusher | ± 0.3° from nominal | dc to 2 GHz <sup>b</sup> |
|                                      | ± 0.4° from nominal | 2 to 18 GHz <sup>b</sup> |
|                                      | ± 0.6° from nominal | 8 to 18 GHz <sup>b</sup> |

a. The specifications for the opens and shorts are given as allowed deviation from the nominal model as defined in the standard definitions (see "Nominal Standard Definitions" on page A-9).

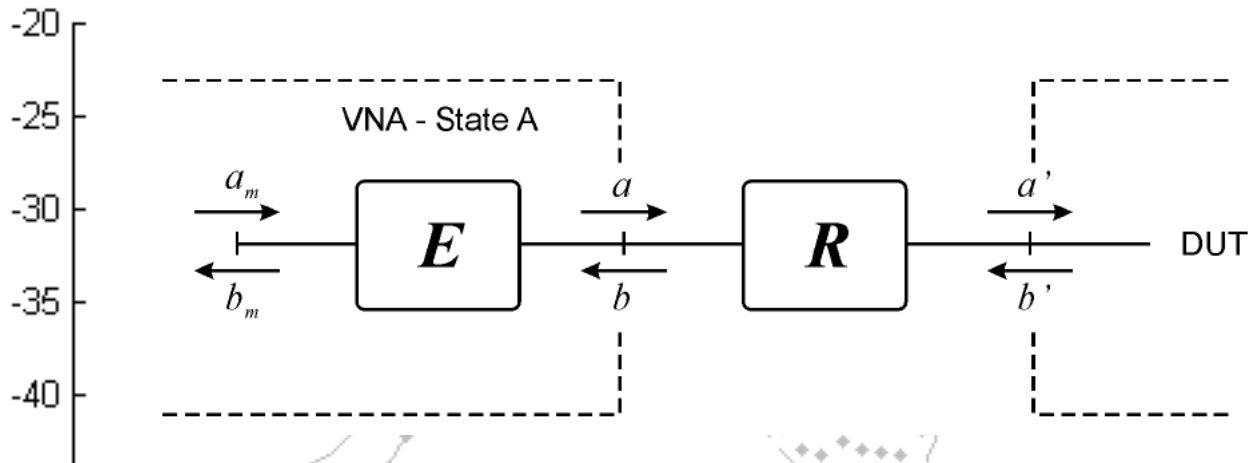
b. Nominal, in this case, means the electrical characteristics as defined by the calibration constants supplied on the calibration constants disk.



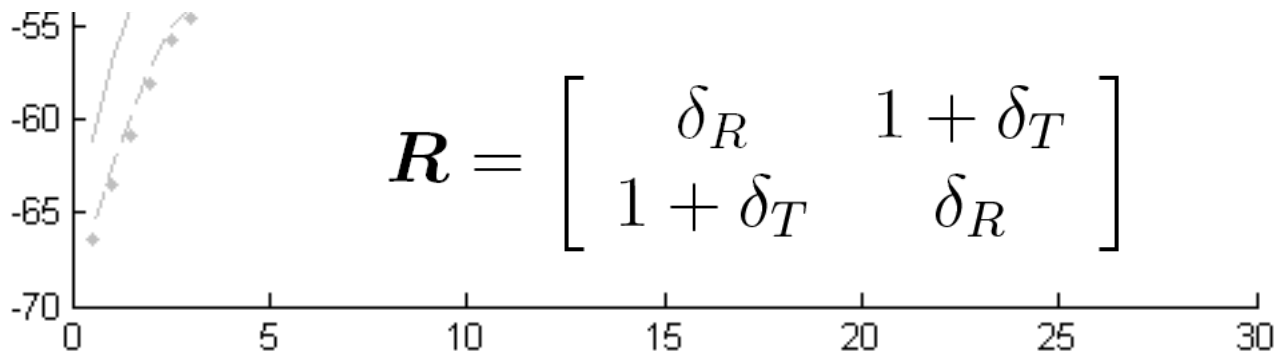
# Multifinger On wafer probes



# Repeatability Model



1. The scattering matrix is reciprocal ( $R_{12} = R_{21}$ , this implies  $\delta_{12} = \delta_{21} = \delta_T$ )
2. The scattering matrix is physically symmetrical ( $R_{11} = R_{22}$ , this implies  $\delta_{11} = \delta_{22} = \delta_R$ )



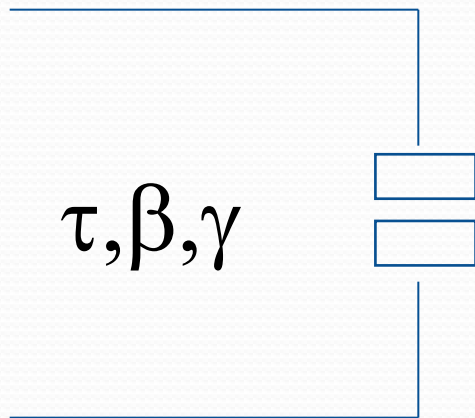
$$\mathbf{R} = \begin{bmatrix} \delta_R & 1 + \delta_T \\ 1 + \delta_T & \delta_R \end{bmatrix}$$



# Standard Accuracy

- Standard Model
- Model Identification
- Parameter Accuracy

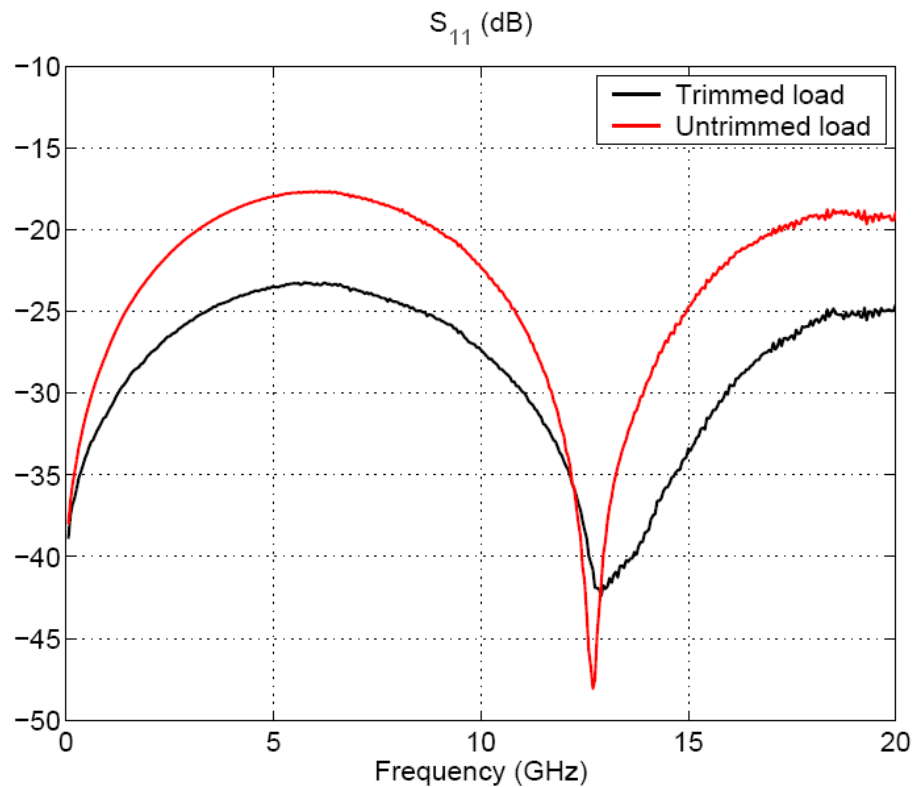
# Standard Model



$$C = C_0 + C_1 f + C_2 f^2 + C_3 f^3$$

- How do we get  $C_j$
- FEM Methods

# Standard Model: 40ps line

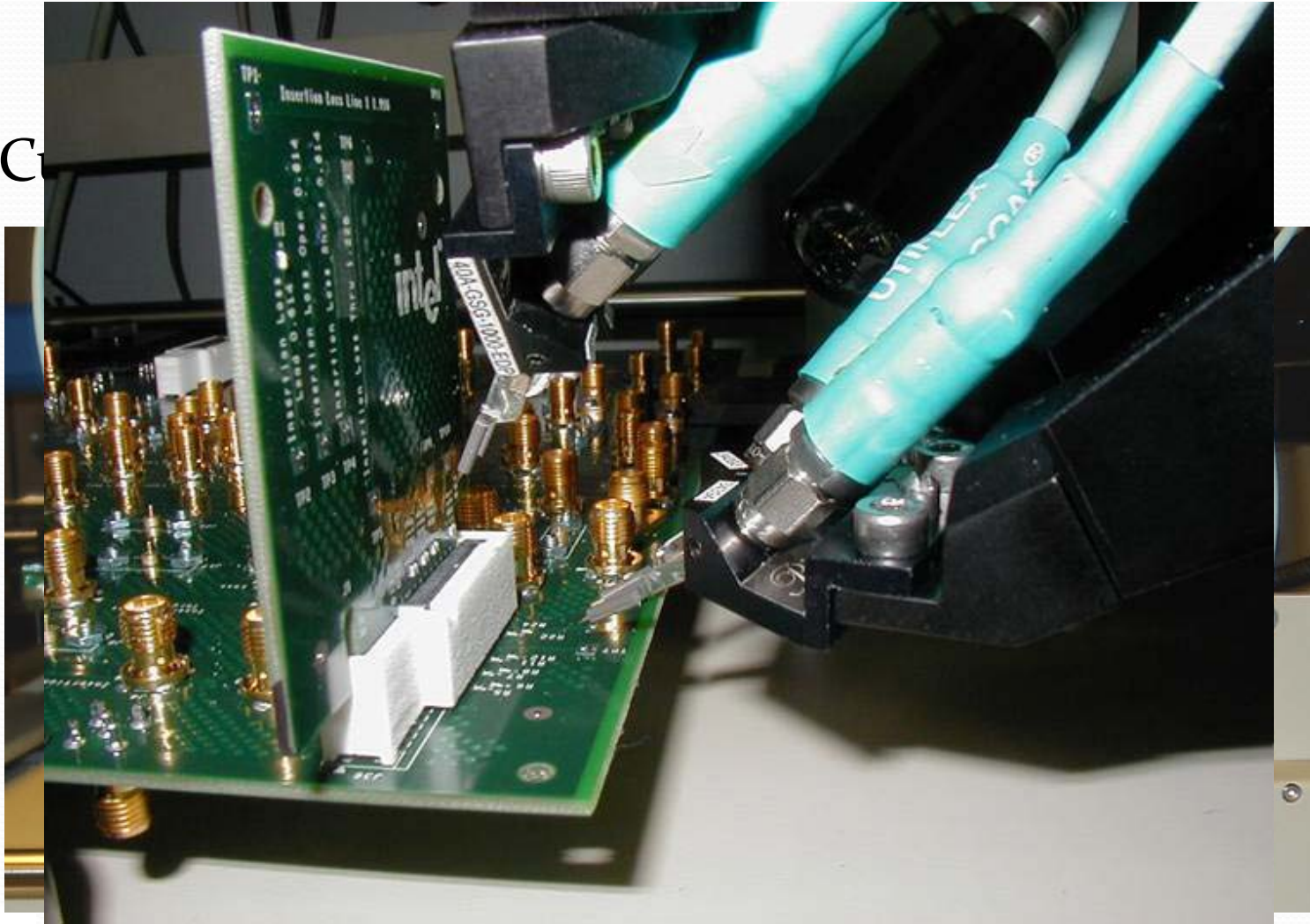


# Let's put everything together

- Interfacing :
  - On Board
  - On Wafer
- Standard design
- A complete example of socket board

# Interfacing

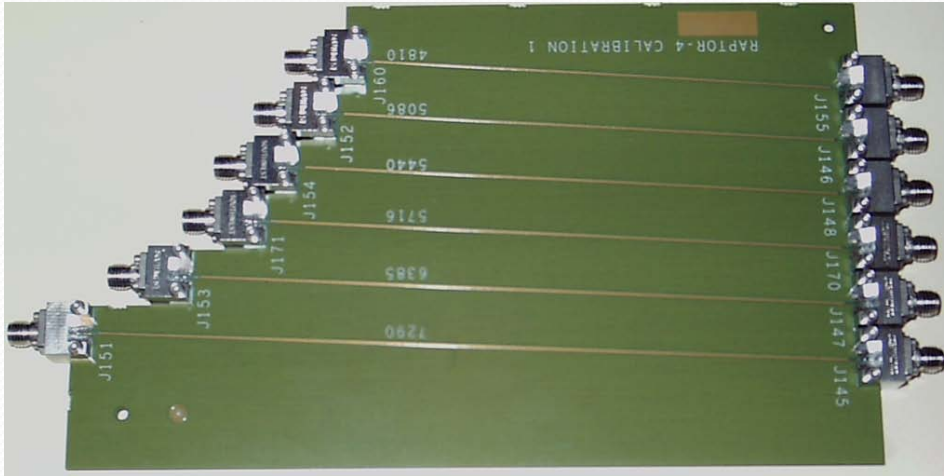
- C



# Standard Design for Multiport Measurements

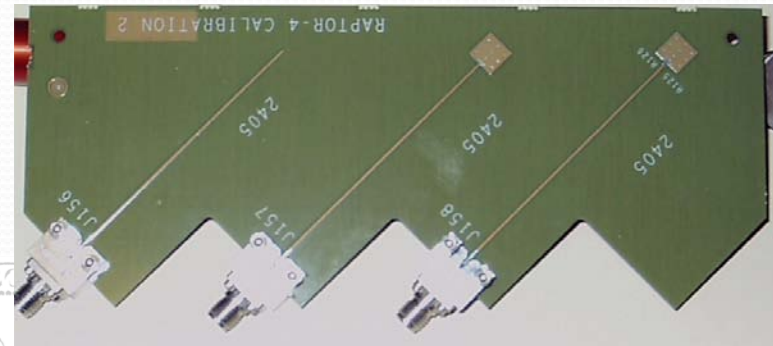
- Requirements:
  - Minimum Number of Connections
  - Easy to fabbricate
  - Calibration and Verification Elements

# Coax On-Board Simple Calibration Structures



Thru and Line Structures

Reflect and Match Structures



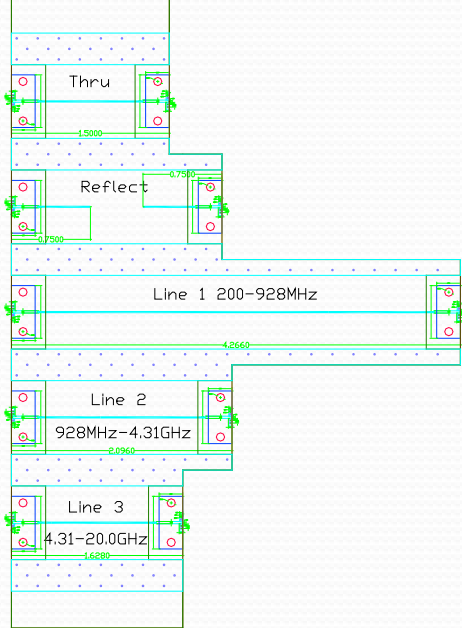


# More complex On fixture Standard

3-TRL/TRM kits

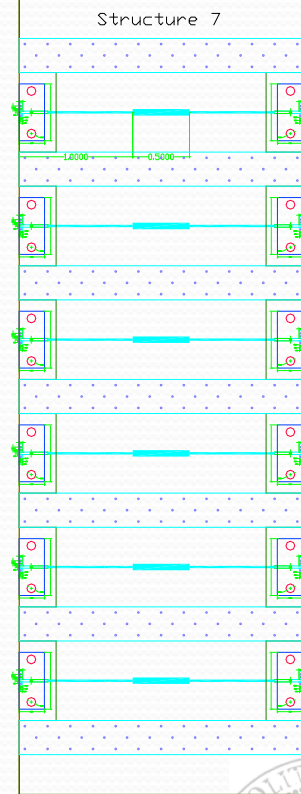
0.2-20GHz  
0.05-50GHz  
0.05-65GHz

part #: AN\_12port\_TV1\_20G\_TRL



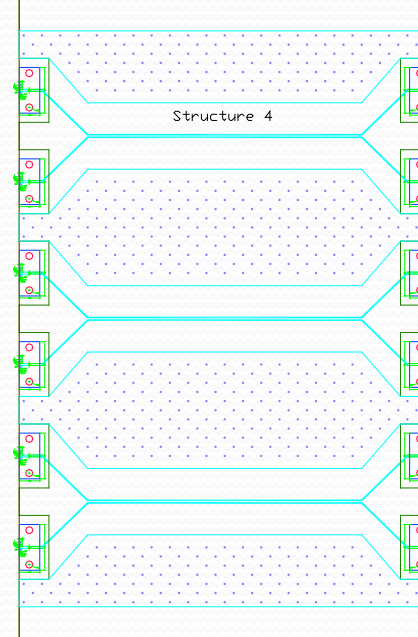
12-port  
Beatty standard

part #: AN\_12port\_TV1\_Beatty



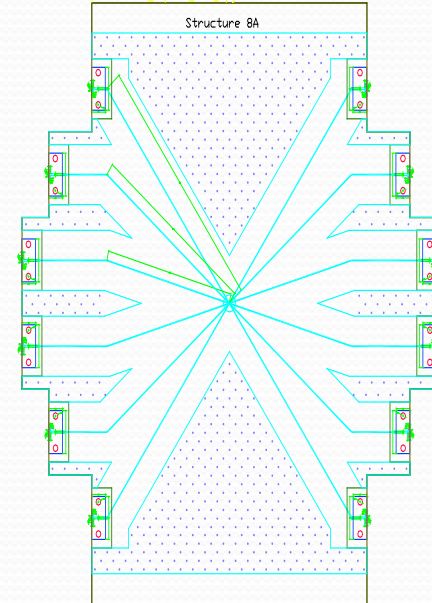
12-port  
simple & coupled ustrip

part #: AN\_12port\_TV1\_coupled\_line



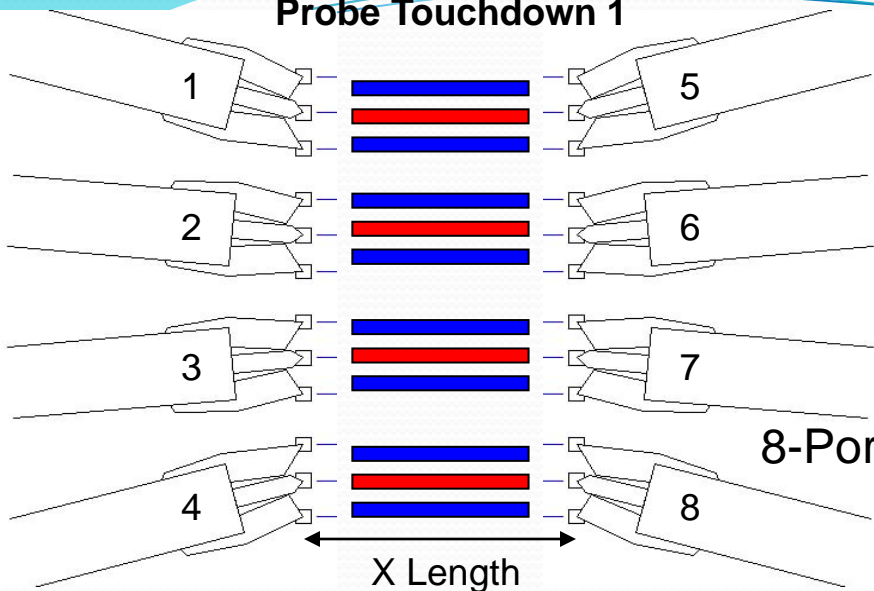
12-port  
unknown thru

part #: AN\_12port\_TV1\_spyder

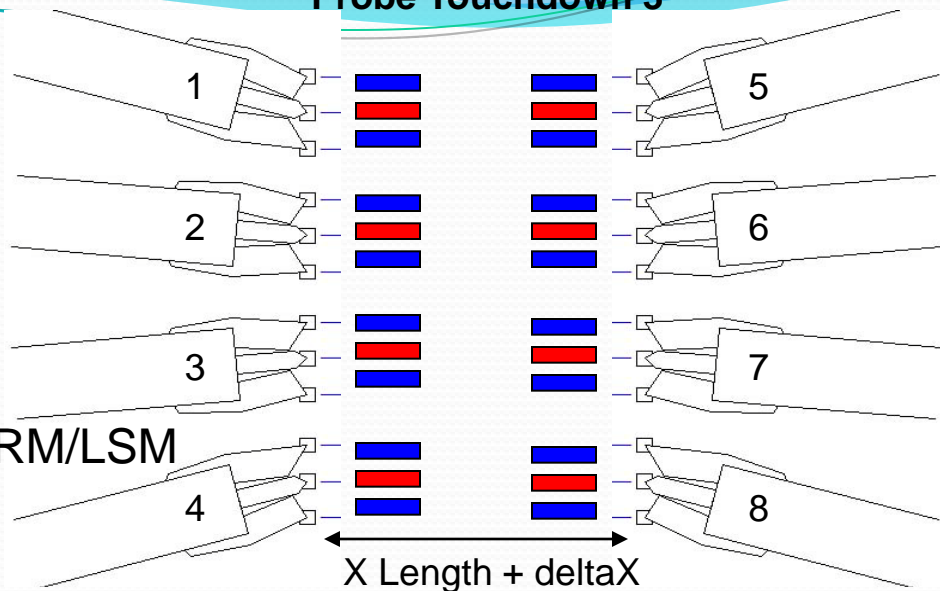


# ON WAFER STANDARD KIT

## Probe Touchdown 1



## Probe Touchdown 3

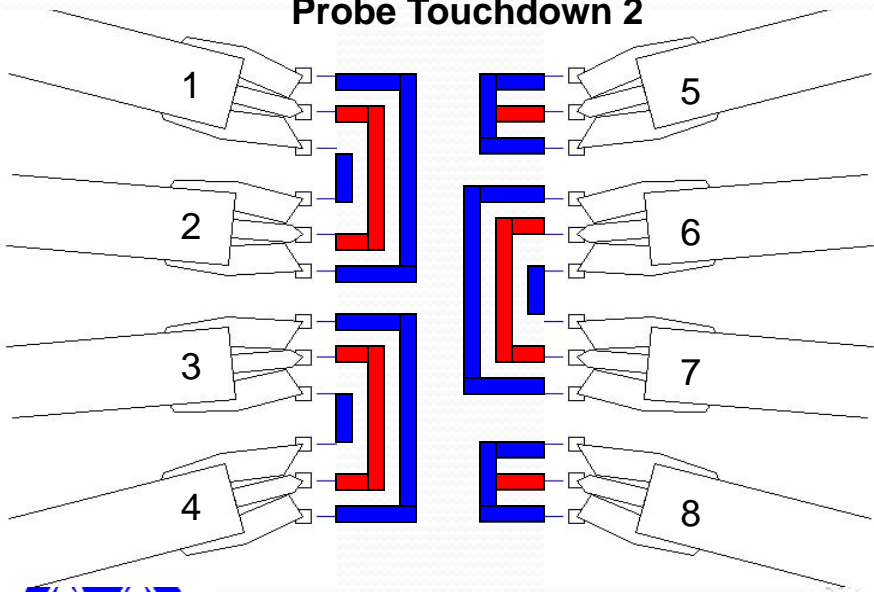


## 8-Port LRM/LSM

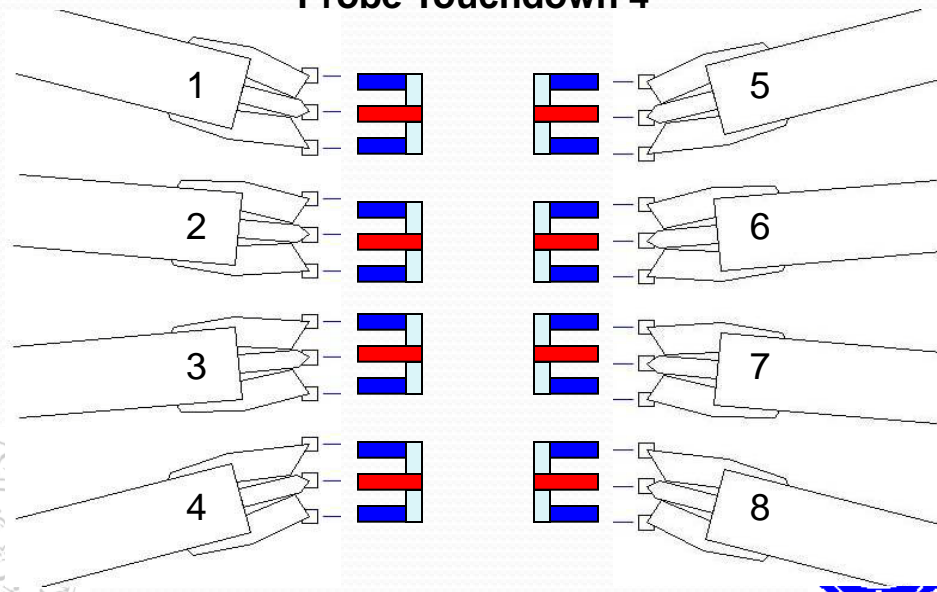
X Length

X Length + deltaX

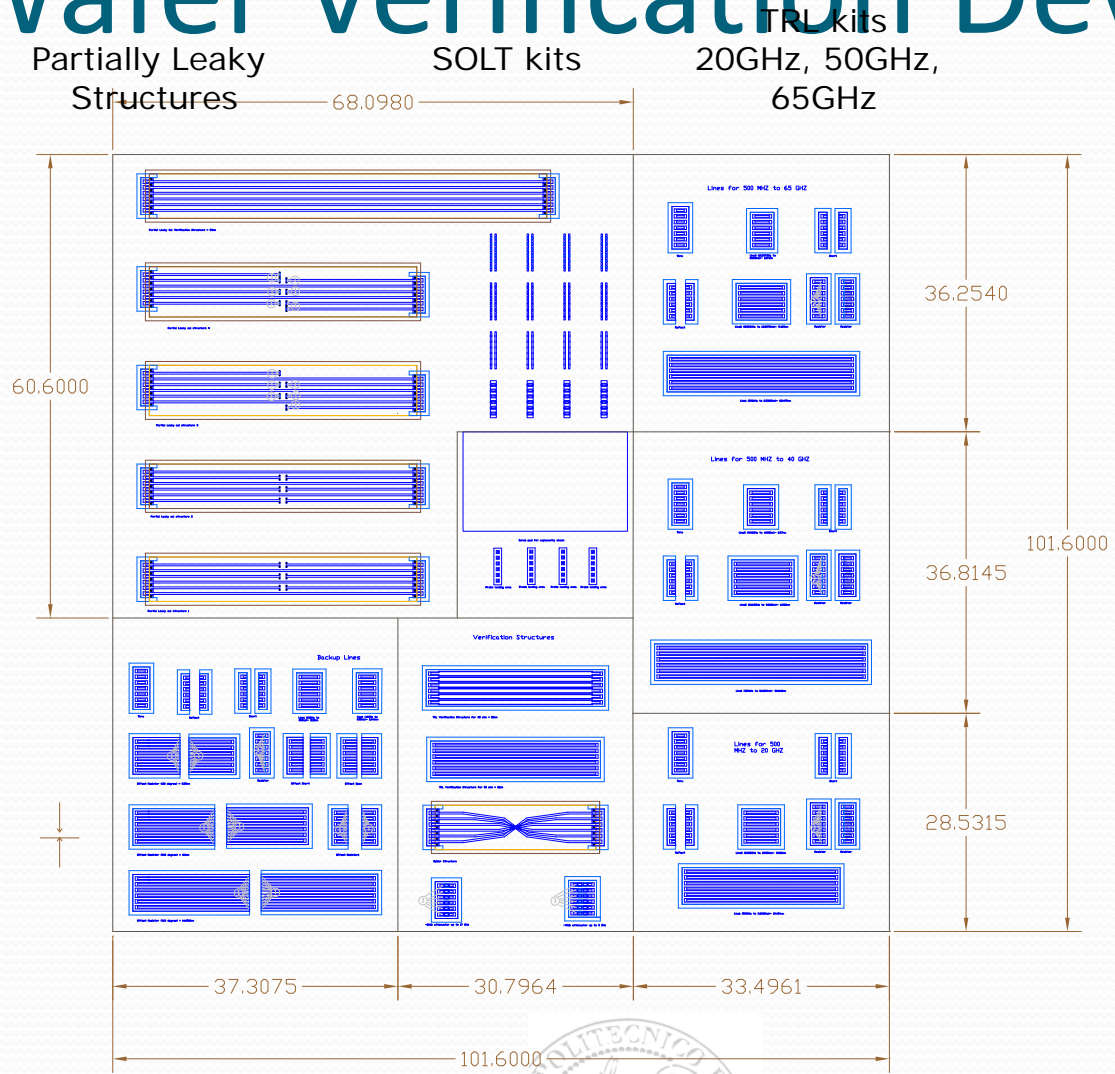
## Probe Touchdown 2



## Probe Touchdown 4

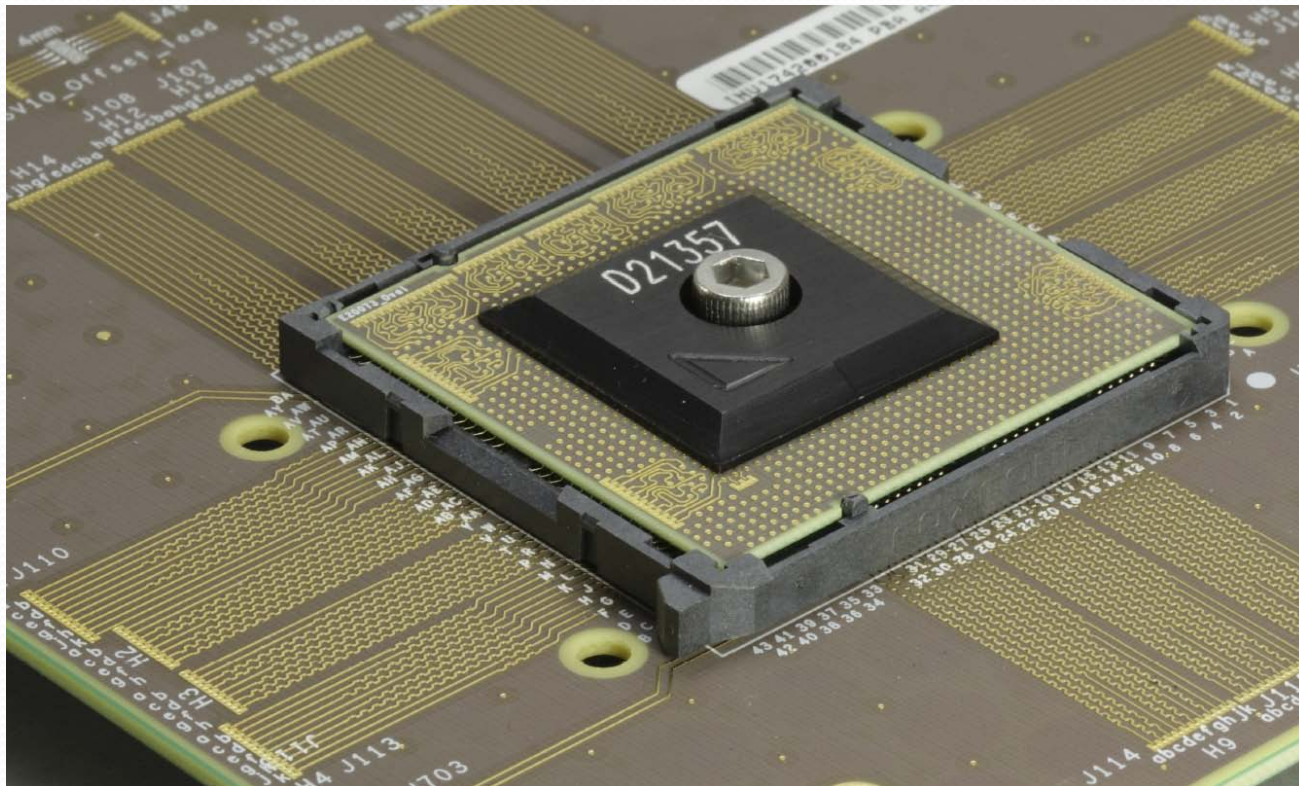


# On Wafer Verification Devices



# Socket Board Characterization

- The target is to obtain accurate measurements of a socket/board interface

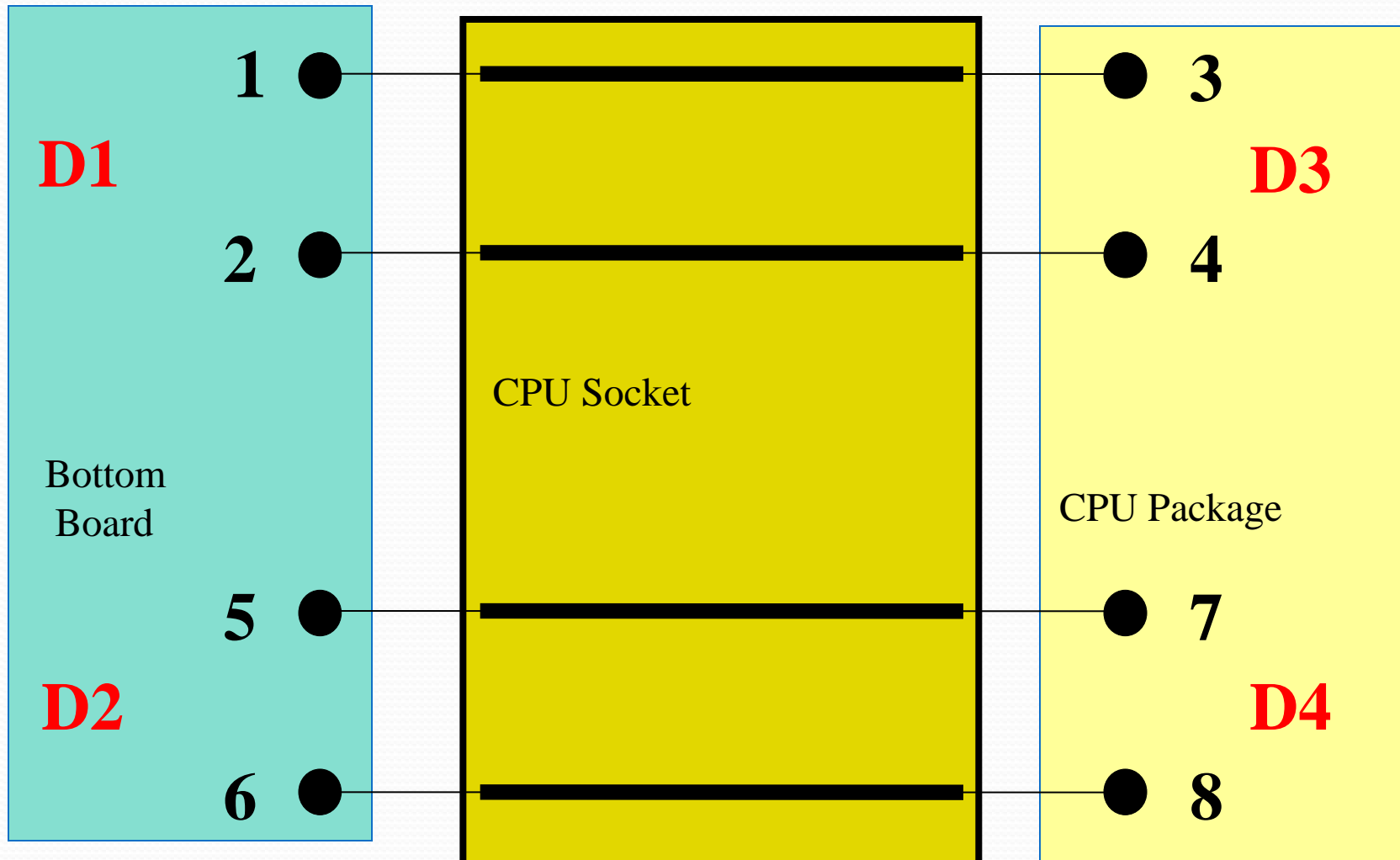


# Socket Board Characterization

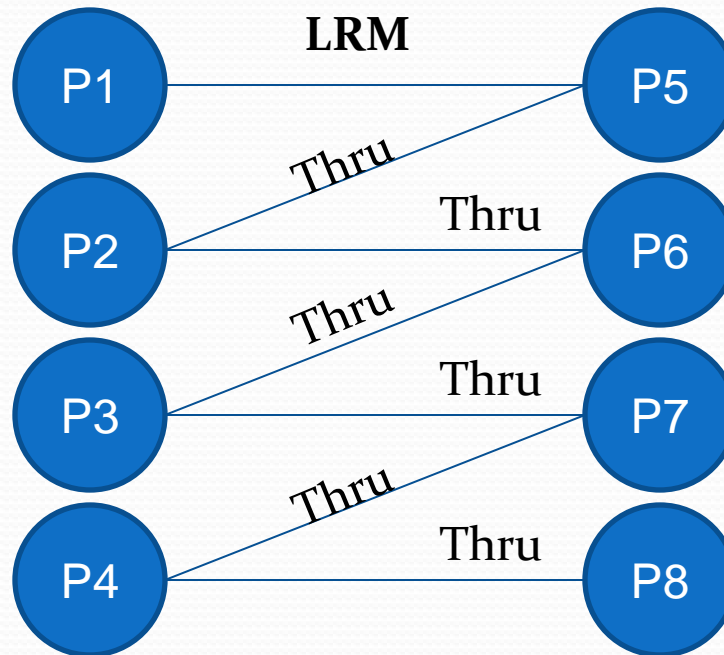
- Define the effective structure to measure:
  - Number of ports
  - Port Location (on board on Socket)
  - Access Lines
- Define a Calibration Procedure
- Built the Required Standards
- Verify the calibration with verification devices
- PERFORM THE DUT MEASUREMENTS



# 8 Port Differential Socket Setup



# Let's Design the Cal





# 8-Port LRM Calibration Matrix

|        | Port 1 | Port 2 | Port 3 | Port 4 | Port 5 | Port 6 | Port 7 | Port 8 |
|--------|--------|--------|--------|--------|--------|--------|--------|--------|
| Port 1 | X      | X      | X      | X      | 2P_LRM | X      | X      | X      |
| Port 2 | X      | X      | X      | X      | Thru   | Thru   | X      | X      |
| Port 3 | X      | X      | X      | X      | X      | Thru   | Thru   | X      |
| Port 4 | X      | X      | X      | X      | X      | X      | Thru   | Thru   |
| Port 5 | 2P_LRM | Thru   | X      | X      | X      | X      | X      | X      |
| Port 6 | X      | Thru   | Thru   | X      | X      | X      | X      | X      |
| Port 7 | X      | X      | Thru   | Thru   | X      | X      | X      | X      |
| Port 8 | X      | X      | X      | Thru   | X      | X      | X      | X      |

## Calibration Procedure:

- Thru Port 1, 5
- Thru Port 2, 6
- Thru Port 3, 7
- Thru Port 4, 8
- Thru Port 2, 5
- Thru Port 3, 6
- Thru Port 4, 7
- Reflect Port 1
- Reflect Port 5
- Load Port 1
- Load Port 5

Structure 1 (All ports touchdown)

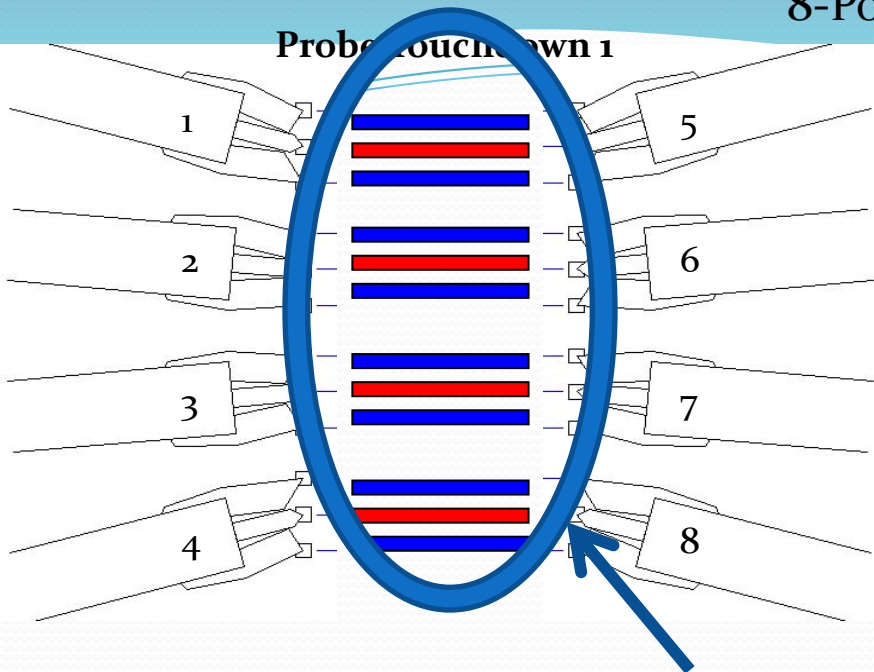
Structure 2 (All ports touchdown)

Structures 3 - 4

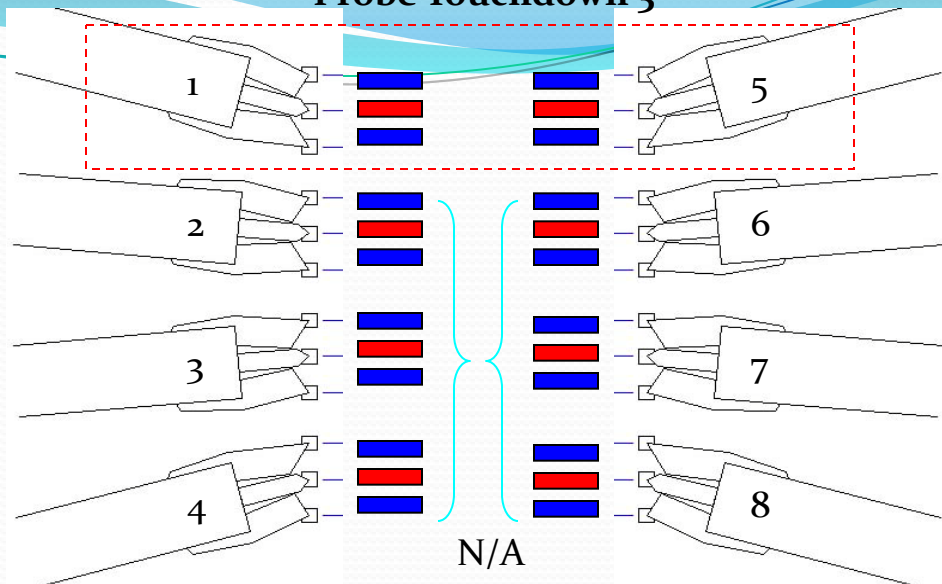


# 8-Port LRM

## Probe Touchdown 1



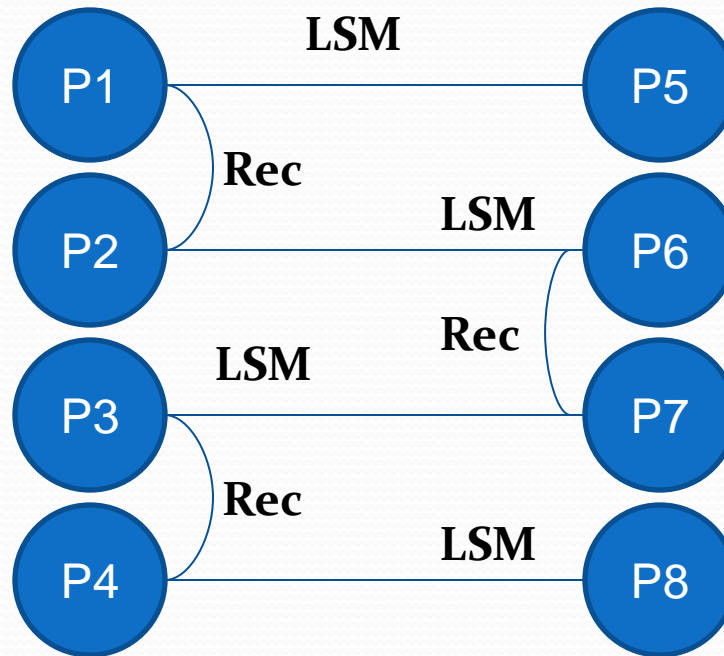
## Probe Touchdown 3



# What if the standard has xtalk?



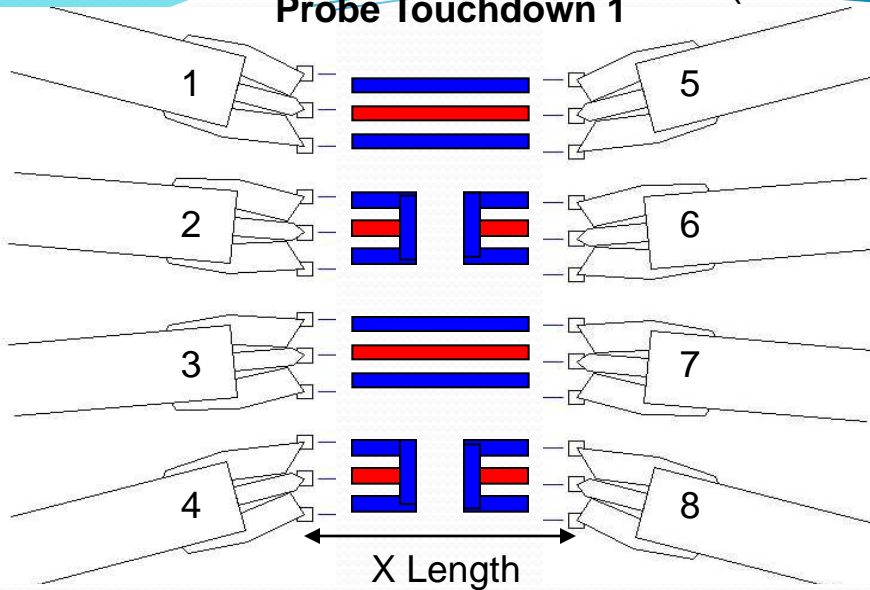
# Another Cal to avoid Xtalk



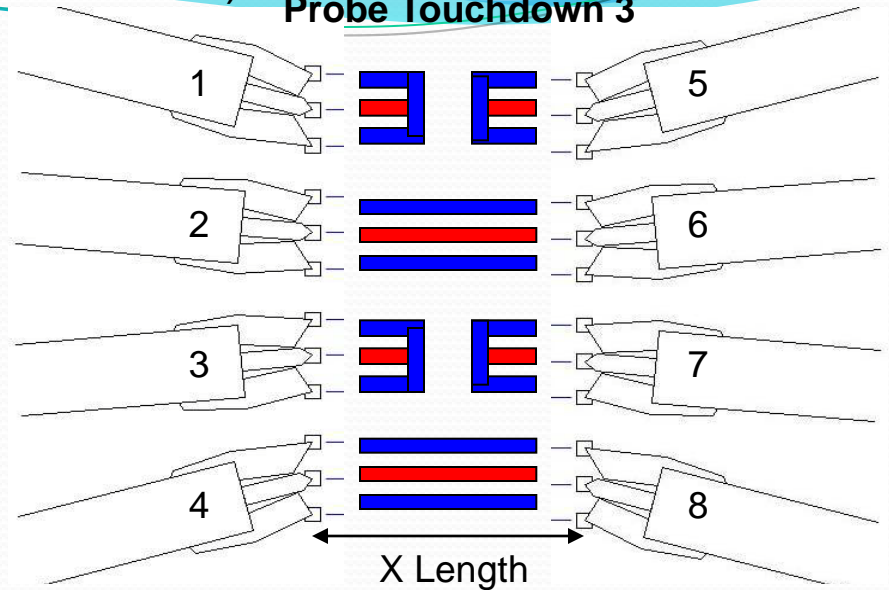
# 8-Port LRM/LSM Standards

(Probe Tip Calibration)

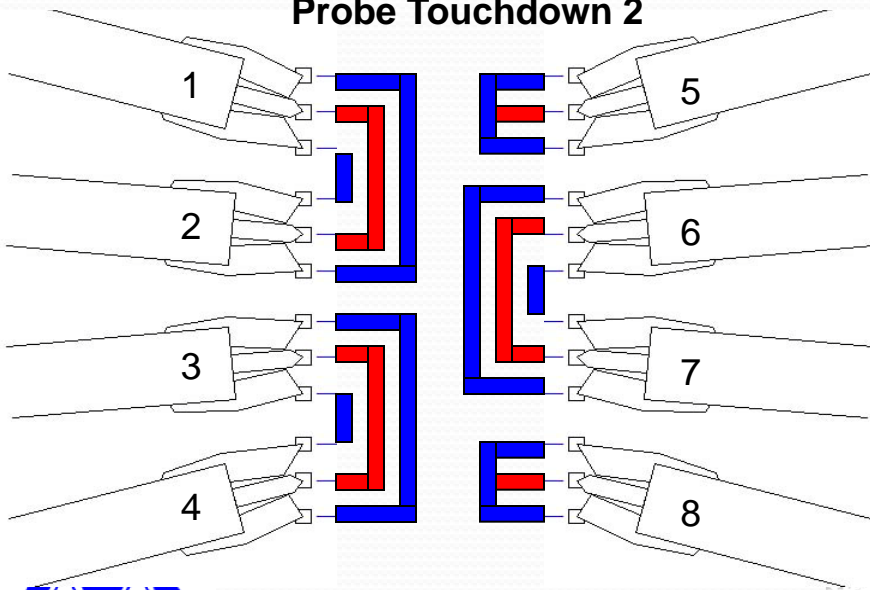
### Probe Touchdown 1



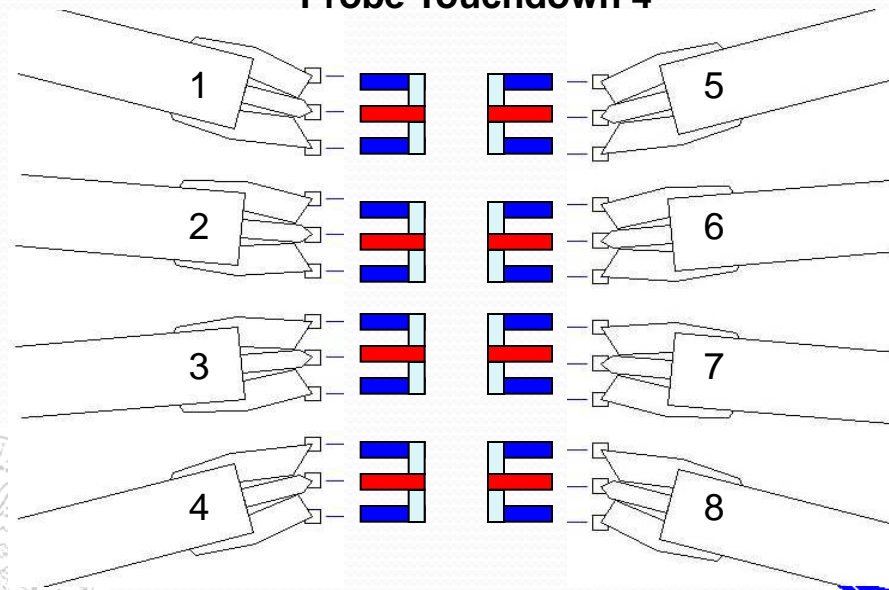
### Probe Touchdown 3



### Probe Touchdown 2



### Probe Touchdown 4



Minimize probe tip Xtalk

GND

SIG

TERM

# 8-Port LRM/LSM Multi-Calibration Matrix with Reciprocal Thrus

|        | Port 1 | Port 2 | Port 3 | Port 4 | Port 5 | Port 6 | Port 7 | Port 8 |
|--------|--------|--------|--------|--------|--------|--------|--------|--------|
| Port 1 | X      | Recip  | X      | X      | 2P_LSM | X      | X      | X      |
| Port 2 | Recip  | X      | X      | X      | X      | 2P_LSM | X      | X      |
| Port 3 | X      | X      | X      | Recip  | X      | X      | 2P_LSM | X      |
| Port 4 | X      | X      | Recip  | X      | X      | X      | X      | 2P_LSM |
| Port 5 | 2P_LSM | X      | X      | X      | X      | X      | X      | X      |
| Port 6 | X      | 2P_LSM | X      | X      | X      | X      | Recip  | X      |
| Port 7 | X      | X      | 2P_LSM | X      | X      | Recip  | X      | X      |
| Port 8 | X      | X      | X      | 2P_LSM | X      | X      | X      | X      |

• Calibration Procedure:

- Thru Port 1, 5
- Thru Port 2, 6
- Thru Port 3, 7
- Thru Port 4, 8
- Recip 1, 2
- Recip 3, 4
- Recip 6, 7
- Reflect Port 1, Reflect Port 5
- Reflect Port 2, Reflect Port 6
- Reflect Port 3, Reflect Port 7
- Reflect Port 4, Reflect Port 8
- Load Port 1, Load Port 5
- Load Port 2, Load Port 6
- Load Port 3, Load Port 7
- Load Port 4, Load Port 8

Structure 1

Structure 2

Structures 3

Structures 4

4 separate 2-port LSM/LRM calibrations linked with reciprocal thru standards

- No wasted probe touchdowns
- Never move probe tips in x or y direction
- Full characterization of every port
- Could provide more accurate calibrations

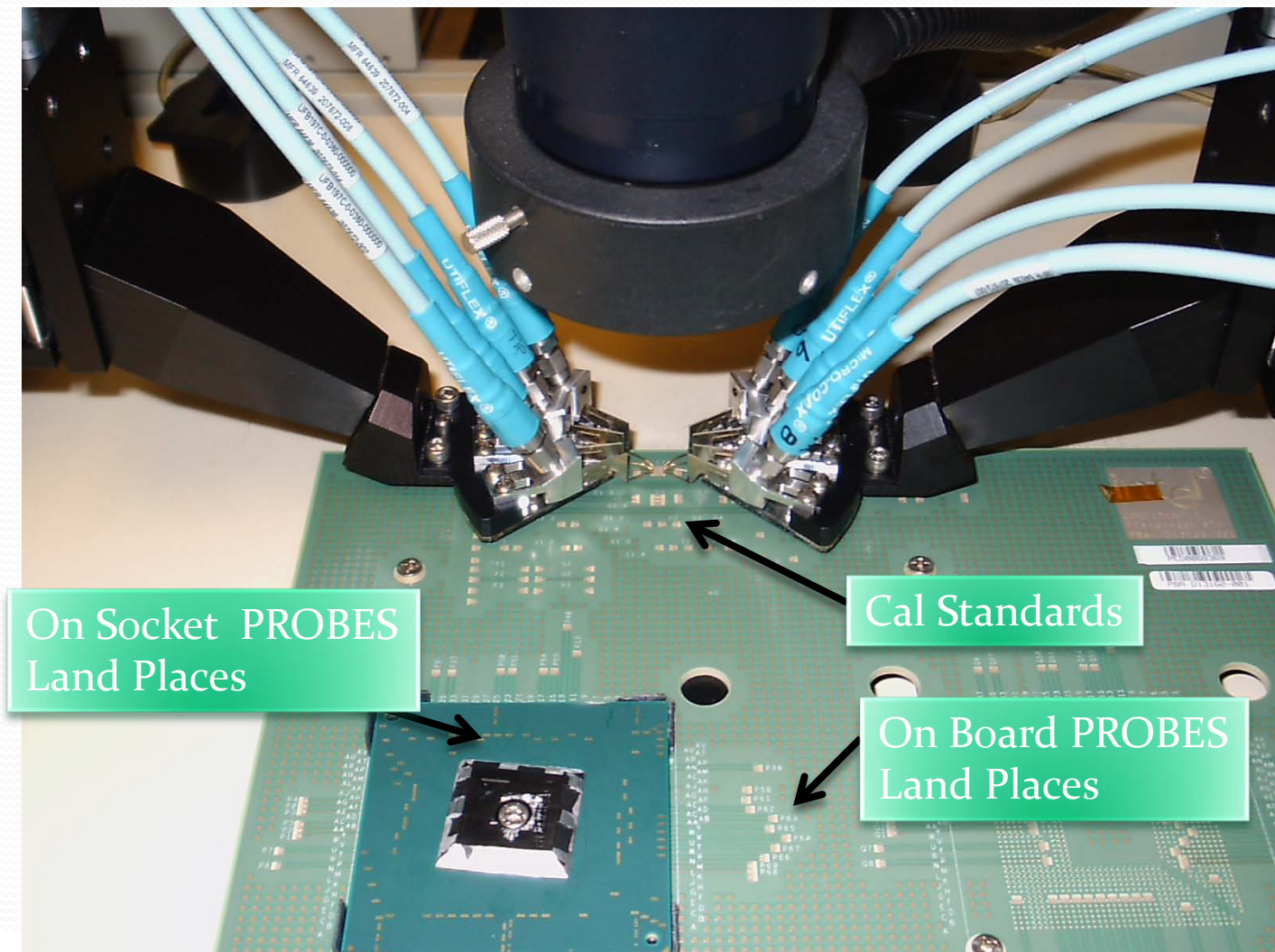
LRM requires reflect on all ports

LSM only requires 1 reflect per calibration

=> Only half of Structure 3 is needed for LSM

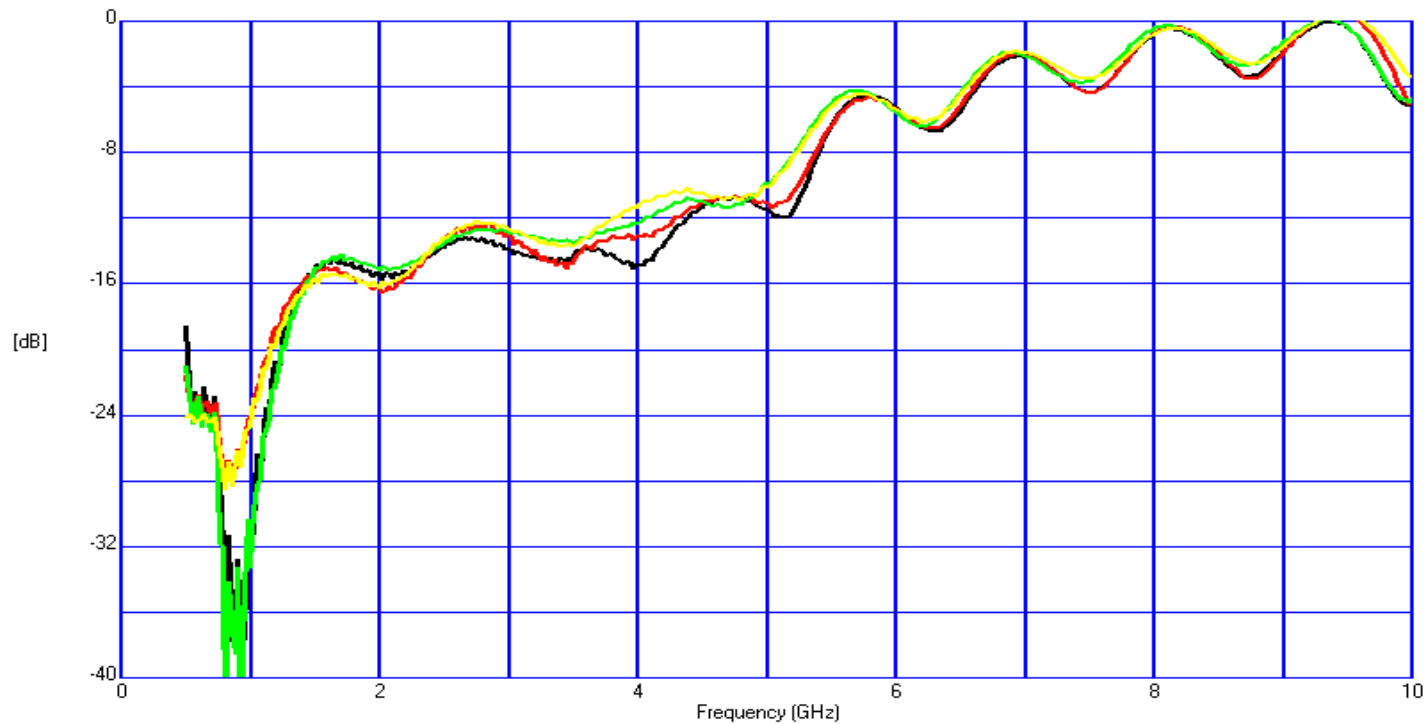


# Socket/Board Example



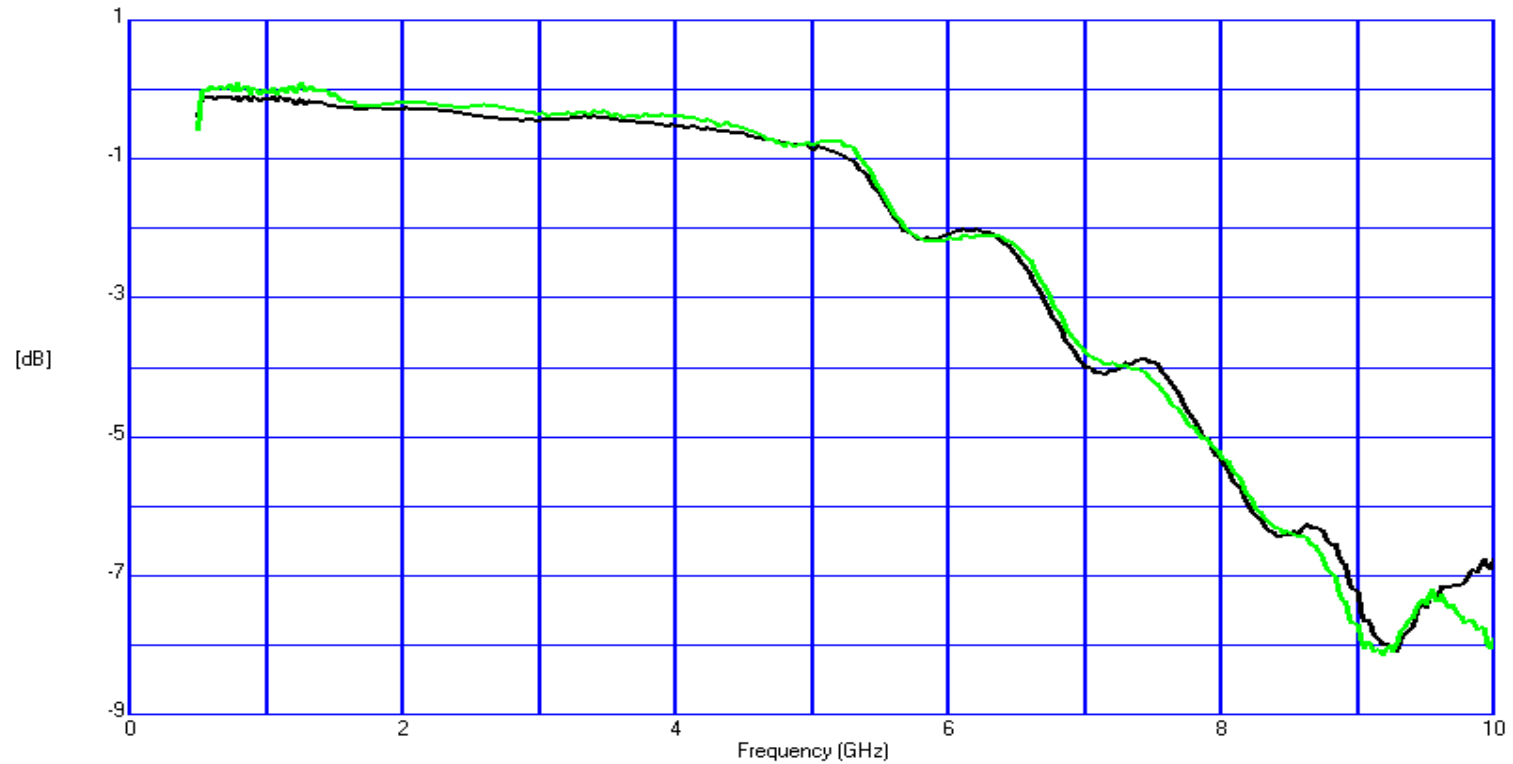
# Socket-Board Data

SDD11-SDD22-SDD33-SDD44



# Socket-Board Data

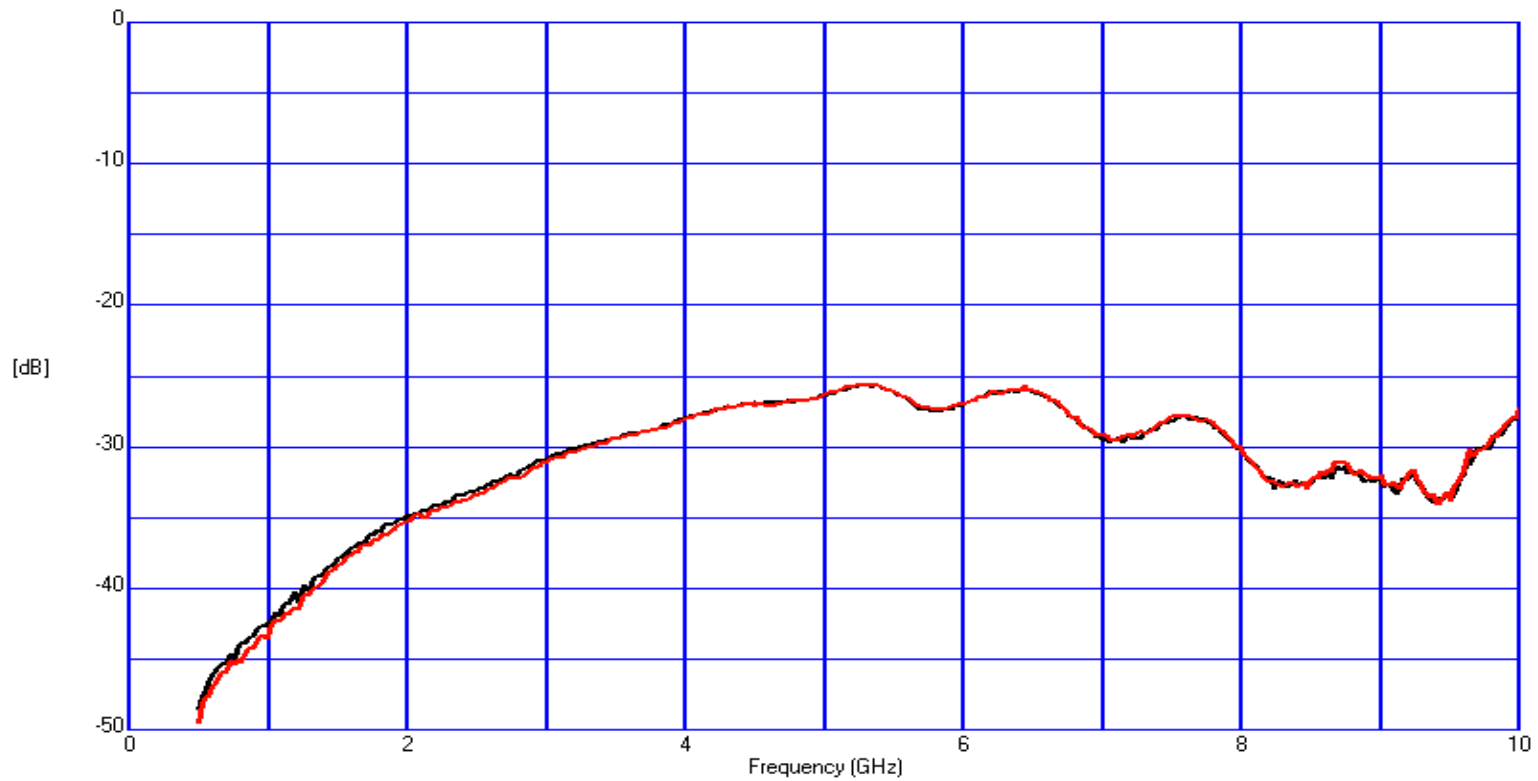
SDD12 - SDD34





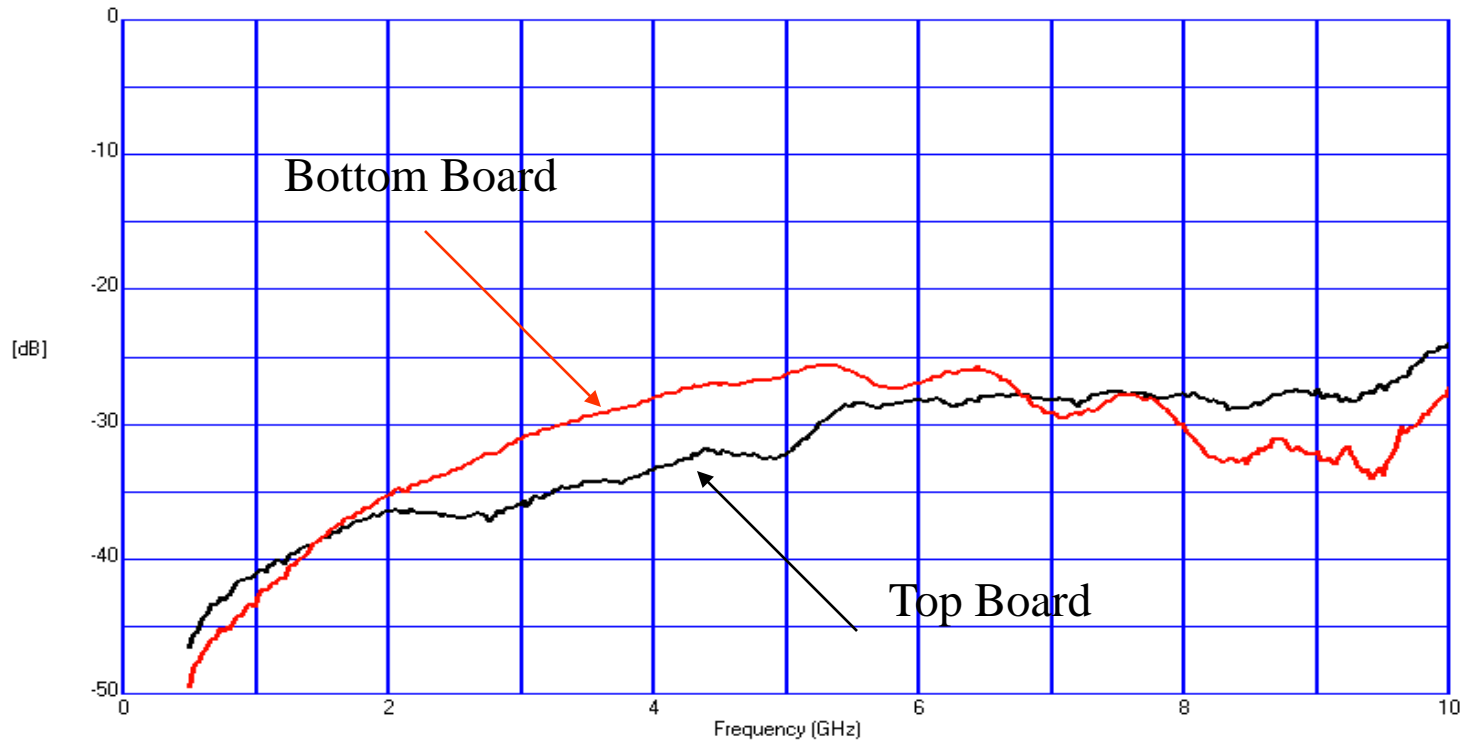
# Socket-Board Data

## SD14 – SD23 (Far End Xtalk)

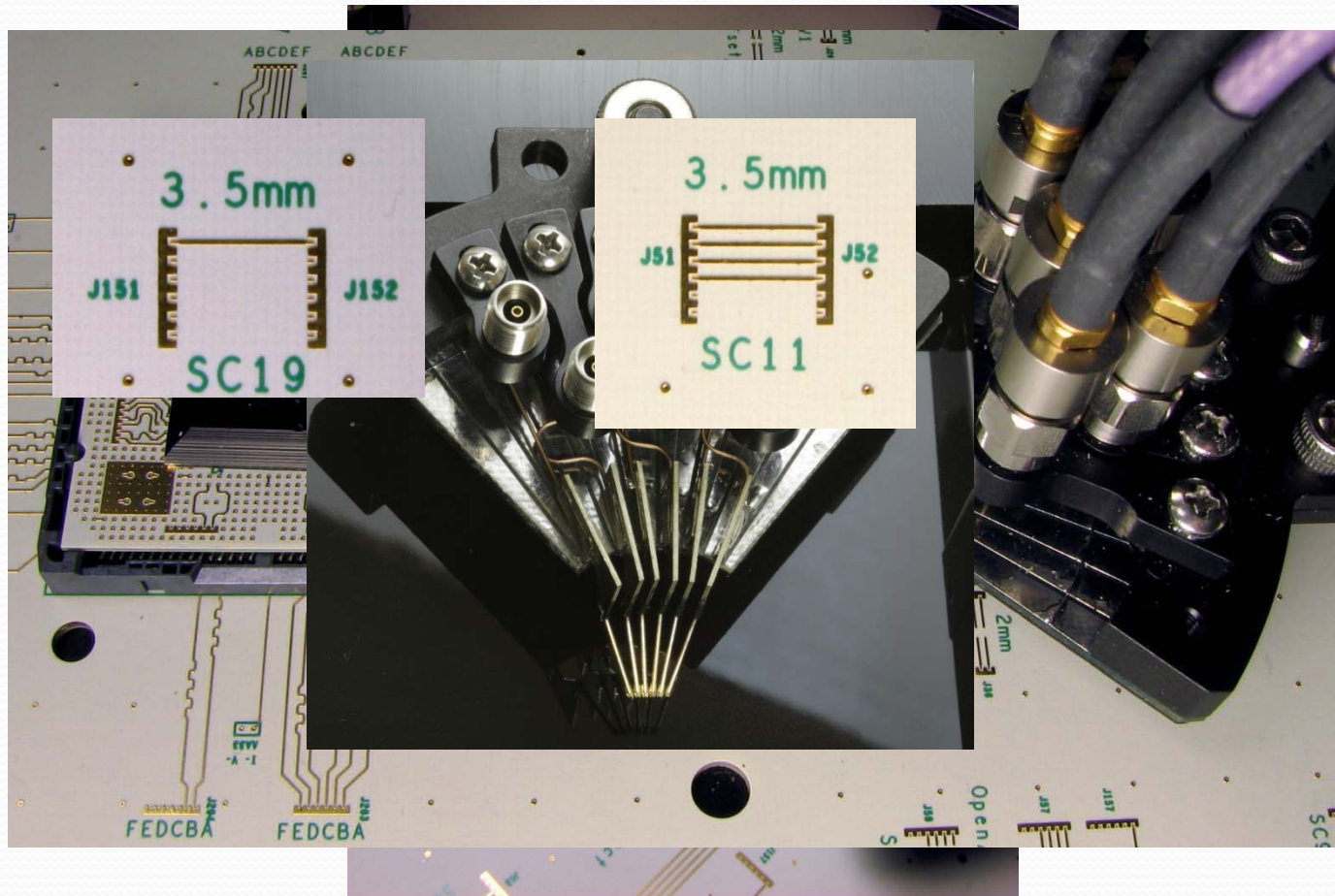


# Socket-Board Data

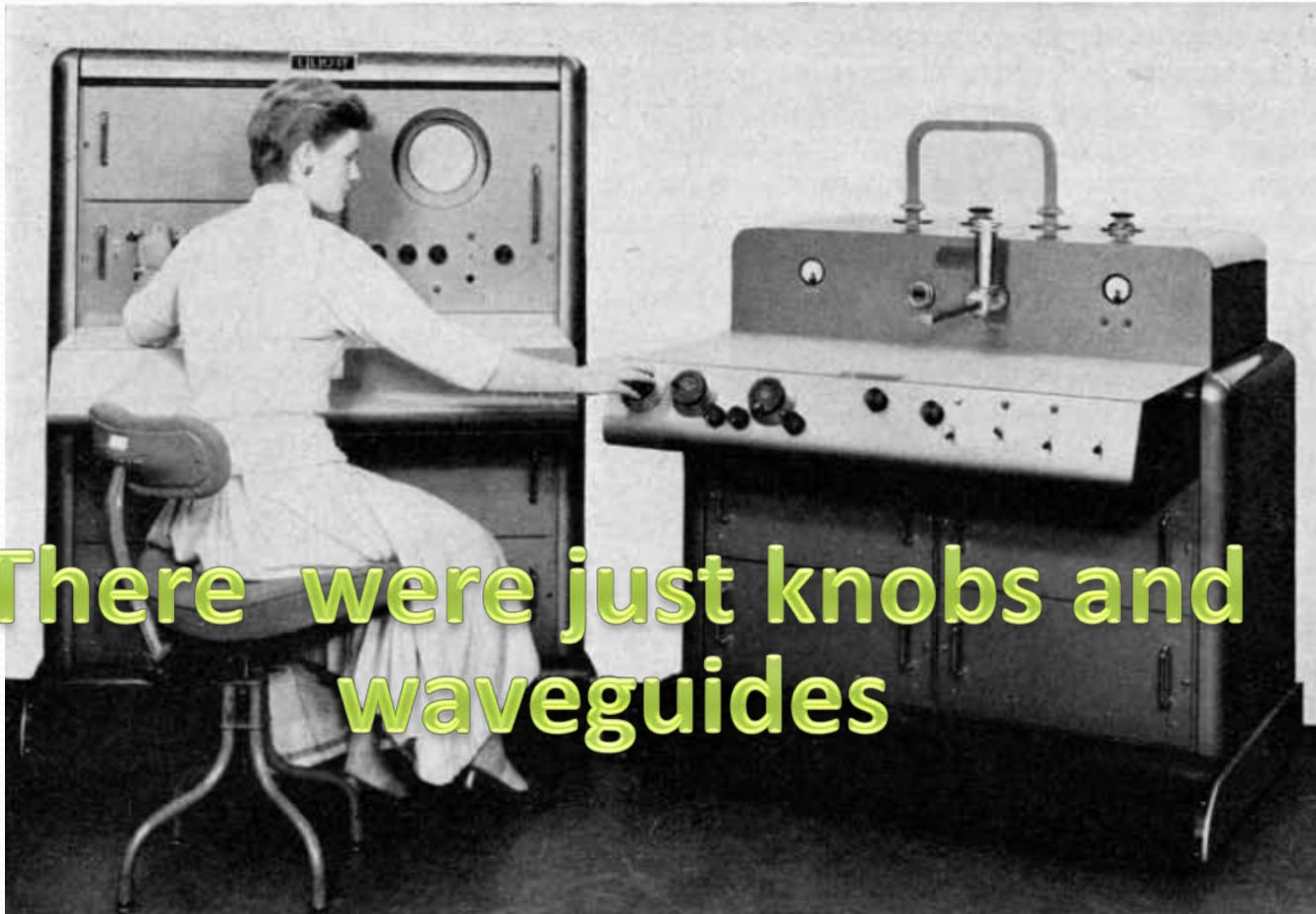
SD13 – SD24 (Near End Xtalk)



# A similar case but 12ports !



# So at the beginning....



There were just knobs and waveguides

Then computers came in....



and the situation gets.....



# MESSY BUT..

With a well design  
Measurement Strategy  
Even the Mess gets clean



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